ADC32RF42 デュアル・チャネル、14ビット、1.5GSPS、アナログ/デジタル・コンバータ

1 特長

- 14ビット、デュアル・チャネル、1.5GSPS ADC
- ノイズ・フロア: -151.8dBFS/Hz
- 最高4GHzをサポートするRF入力
- アパーチャ・ジッタ: 90f_S
- チャネル分離: f_{IN} = 1.8GHzにおいて95dB
- スペクトラム性能(f_{IN} = 950MHz、-2dBFS時)
  - SNR: 61.1dBFS
  - SFDR: 67dBc HD2、HD3
- スペクトラム性能(f_{IN} = 1.85GHz、-2dBFS時)
  - SNR: 58.9dBFS
  - SFDR: 64dBc HD2、HD3
- オンチップのデジタル・ダウン・コンバータ
  - 最大4つのDDC (デュアル・バンド・モード)
  - DDCごとに最大3つの独立NCO
- 過電圧保護用のオンチップの入力クランプ
- プログラム可能なオンチップの電力検出器、AGCサポート用アラーム・ピン付き
- オンチップ・ディザリング
- オンチップの入力終端
- 入力フル・スケール: 1.35V_{PP}
- マルチチップの同期をサポート
- JESD204Bインターフェイス
  - サブクラス1ベースの確定的レイテンシ
  - チャネルごとに4レーン、最高12.5Gbps
- 消費電力: 1.5GSPSのとき2W/Ch
- 72ピンのVQFNパッケージ(10mm×10mm)

2 アプリケーション

- マルチバンド、マルチモードの2G、3G、4G携帯電話レシーバ
- フェーズ・アレイ・レーダー
- 電子兵器
- ケーブル・インフラストラクチャ
- 広帯域ワイヤレス
- 高速デジタイザ
- ソフトウェア定義のラジオ
- 通信テスト機器
- マイクロ波およびミリ波受信機

3 概要

ADC32RF42デバイスは、14ビット、1.5GSPS、デュアル・チャネルのA/Dコンバータ(ADC)で、最高4GHz、さらにそれ以上の入力周波数でのRFサンプリングをサポートします。ADC32RF42は高い信号対雑音比(SNR)を実現するよう設計されており、-151.8dBFS/Hzのノイズ・スペクトル密度と、広い入力周波数範囲にわたるダイナミック・レンジとチャネル分離を実現します。バッファ付きアナログ入力とオンチップの終端により、広い周波数帯域にわたって入力インピーダンスが均一で、サンプルとホールドのグリッチ・エネルギーが最小化されます。

各ADCチャネルは、デュアル・バンドのデジタル・ダウン・コンバータ(DDC)に接続でき、DDCごとに3つまでの独立した16ビット数値制御発振器(NCO)により、位相コヒーレントな周波数ホッピングが可能です。さらに、ADCにはフロントエンドのピークおよびRMS電力検出器とアラーム機能が装備されており、外部の自動ゲイン制御(AGC)アルゴリズムをサポートします。

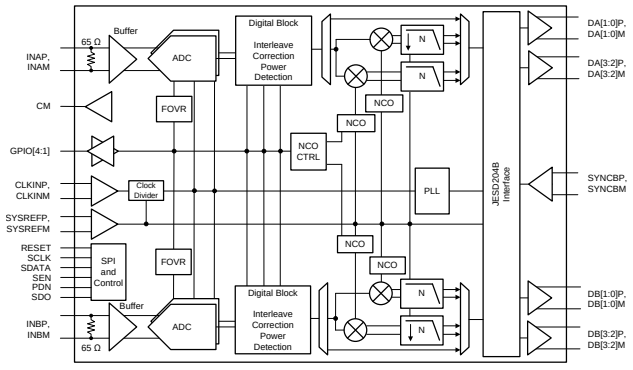
ADC32RF42は、サブクラス1ベースの確定的レイテンシを持つJESD204Bシリアル・インターフェイスをサポートし、12.5Gbpsまでのデータ速度で、ADCごとに最大4レーンを使用できます。このデバイスは72ピンのVQFNパッケージ(10mm×10mm)で供給され、工業用温度範囲(-40℃～+85℃)に対応します。

製品情報(1)

型番	パッケージ	本体サイズ(typ)
ADC32RF42	VQFN (72)	10.00mm×10.00mm

(1) 提供されているすべてのパッケージについては、このデータシートの末尾にある注文情報を参照してください。

ブロック概略図



Copyright © 2017, Texas Instruments Incorporated

英語版のTI製品についての情報を翻訳したこの資料は、製品の概要を確認する目的で便宜的に提供しているものです。該当する正式な英語版の最新情報は、www.ti.comで閲覧でき、その内容が常に優先されます。TIでは翻訳の正確性および妥当性につきましては一切保証いたしません。実際の設計などの前には、必ず最新版の英語版をご参照くださいますようお願いいたします。

目次

1 特長 ... 1
2 アプリケーション ... 1
3 概要 ... 1
4 改訂履歴 ... 2
5 **Device Family Comparison Table** ... 3
6 **Pin Configuration and Functions** ... 3
7 **Specifications** ... 5
7.1 Absolute Maximum Ratings ... 5
7.2 ESD Ratings ... 5
7.3 Recommended Operating Conditions ... 5
7.4 Thermal Information ... 5
7.5 Electrical Characteristics ... 6
7.6 AC Performance Characteristics ... 7
7.7 Digital Requirements ... 9
7.8 Timing Requirements ... 10
7.9 Typical Characteristics ... 12
8 **Parameter Measurement Information** ... 17
8.1 Input Clock Diagram ... 17
9 **Detailed Description** ... 18
9.1 Overview ... 18
9.2 Functional Block Diagram ... 18
9.3 Feature Description ... 19
9.4 Device Functional Modes ... 44
9.5 Register Maps ... 57
10 **Application and Implementation** ... 108
10.1 Application Information ... 108
10.2 Typical Application ... 115
11 **Power Supply Recommendations** ... 117
12 **Layout** ... 117
12.1 Layout Guidelines ... 117
12.2 Layout Example ... 118
13 デバイスおよびドキュメントのサポート ... 119
13.1 ドキュメントのサポート ... 119
13.2 ドキュメントの更新通知を受け取る方法 ... 119
13.3 コミュニティ・リソース ... 119
13.4 商標 ... 119
13.5 静電気放電に関する注意事項 ... 119
13.6 Glossary ... 119
14 メカニカル、パッケージ、および注文情報 ... 119

4 改訂履歴

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

日付	改訂内容	注
2017年5月	*	初版

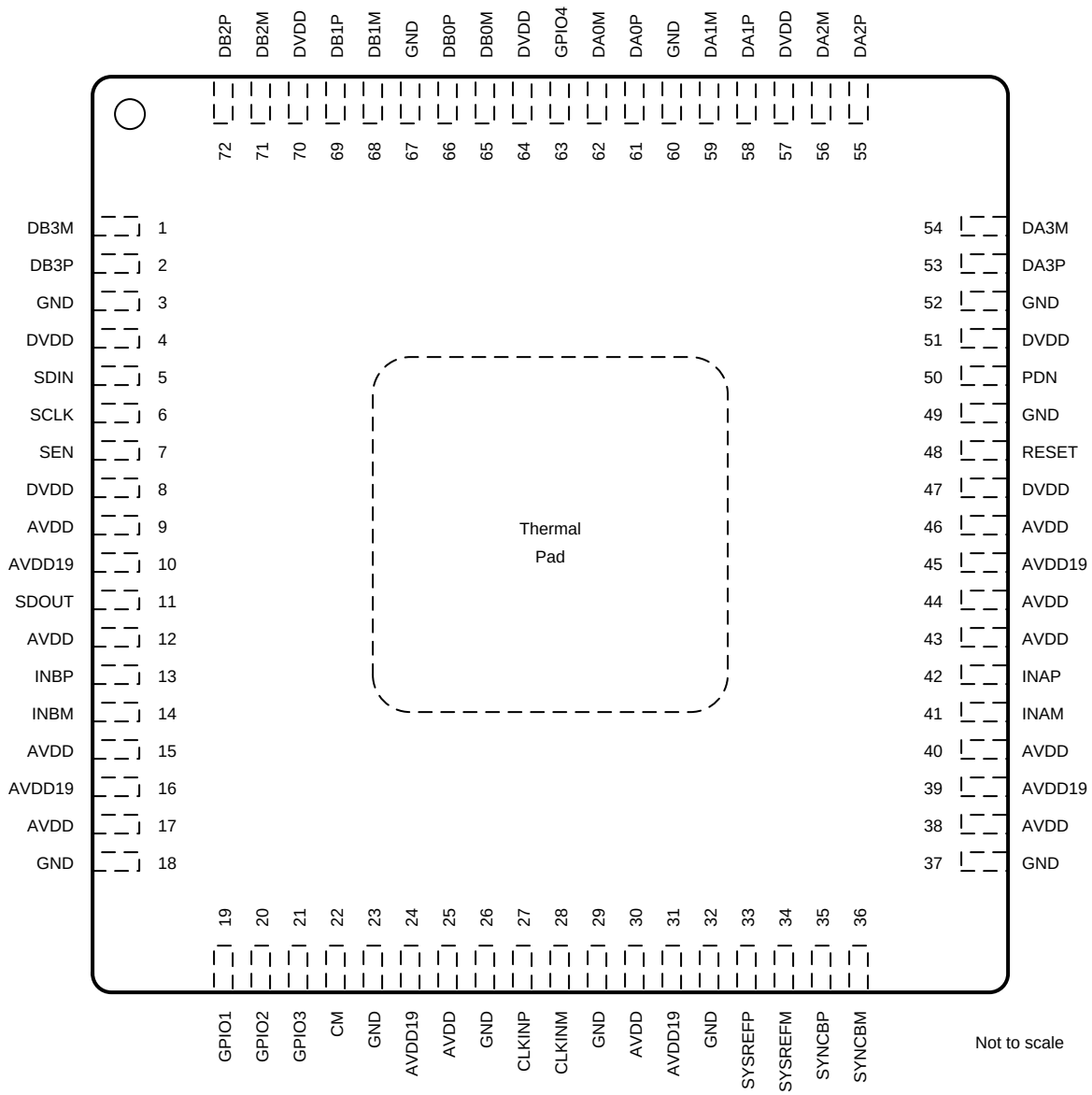
Copyright © 2017, Texas Instruments Incorporated

5 Device Family Comparison Table

PART NUMBER	SPEED GRADE (MSPS)	RESOLUTION (Bits)	CHANNELS
ADC32RF45	3000	14	2
ADC32RF44	2600	14	2
ADC32RF42	1500	14	2

6 Pin Configuration and Functions

RMP Package
72-Pin VQFN
Top View



Copyright © 2017, Texas Instruments Incorporated

Pin Functions

NAME	NO.	I/O	DESCRIPTION
INPUT, REFERENCE			
INAM	41	I	Differential analog input for channel A
INAP	42		
INBM	14	I	Differential analog input for channel B
INBP	13		
CM	22	O	Common-mode voltage for analog inputs, 1.2 V
CLOCK, SYNC			
CLKINM	28	I	Differential clock input for the analog-to-digital converter (ADC). This pin has an internal differential 100-Ω termination.
CLKINP	27		
SYSREFM	34	I	External sync input. This pin has an internal, differential 100-Ω termination and requires external biasing.
SYSREFP	33		
GPIO1	19	I/O	GPIO control pin; configured through the SPI. This pin can be configured to be either a fast overrange output for channel A and B, a fast detect alarm signal from the peak power detect, or a numerically-controlled oscillator (NCO) control. GPIO 4 (pin 63) can also be configured as a single-ended SYNCB input.
GPIO2	20		
GPIO3	21		
GPIO4	63		
CONTROL, SERIAL			
RESET	48	I	Hardware reset; active high. This pin has an internal 20-kΩ pulldown resistor.
SCLK	6	I	Serial interface clock input. This pin has an internal 20-kΩ pulldown resistor.
SDIN	5	I/O	Serial interface data input. This pin has an internal 20-kΩ pulldown resistor. SDIN can be data input in 4-wire mode, data input and output in 3-wire mode.
SEN	7	I	Serial interface enable. This pin has an internal 20-kΩ pullup resistor to DVDD.
SDOUT	11	O	Serial interface data output in 4-wire mode
PDN	50	I	Power down; active high. This pin can be configured through an SPI register setting and can be configured to a fast overrange output channel B through the SPI. This pin has an internal 20-kΩ pulldown resistor.
DATA INTERFACE			
DA0M	62	O	JESD204B serial data output for channel A
DA0P	61		
DA1M	59		
DA1P	58		
DA2M	56		
DA2P	55		
DA3M	54		
DA3P	53		
DB0M	65	O	JESD204B serial data output for channel B
DB0P	66		
DB1M	68		
DB1P	69		
DB2M	71		
DB2P	72		
DB3M	1		
DB3P	2		
SYNCBM	36	I	Synchronization input for the JESD204B port. This pin has an LVDS or 1.8-V logic input, an optional on-chip 100-Ω termination, and is selectable through the SPI. This pin requires external biasing.
SYNCBP	35		
POWER SUPPLY			
AVDD19	10, 16, 24, 31, 39, 45	I	Analog 1.9-V power supply
AVDD	9, 12, 15, 17, 25, 30, 38, 40, 43, 44, 46	I	Analog 1.15-V power supply
DVDD	4, 8, 47, 51, 57, 64, 70	I	Digital 1.15 V-power supply, including the JESD204B transmitter
GND	3, 18, 23, 26, 29, 32, 37, 49, 52, 60, 67	I	Ground; shorted to thermal pad inside device

Copyright © 2017, Texas Instruments Incorporated

7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
Supply voltage range	AVDD19	–0.3	2.1	V
	AVDD	–0.3	1.4	
	DVDD	–0.3	1.4	
Voltage applied to input pins	INAP, INAM and INBP, INBM	–0.3	AVDD19 + 0.3	V
	CLKINP, CLKINM	–0.3	AVDD + 0.6	
	SYSREFP, SYSREFM, SYNCBP, SYNCBM	–0.3	AVDD + 0.6	
	SCLK, SEN, SDIN, RESET, PDN, GPIO1, GPIO2, GPIO3, GPIO4	–0.2	AVDD19 + 0.2	
Voltage applied to output pins		–0.3	2.2	V
Temperature	Operating free-air, T_A	–40	85	°C
	Storage, T_{stg}	–65	150	

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

7.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001(1)	±1000	V
		Charged-device model (CDM), per JEDEC specification JESD22-C101(2)	±500	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
Supply voltage(1)	AVDD19	1.8	1.9	2.0	V
	AVDD	1.1	1.15	1.25	
	DVDD	1.1	1.15	1.2	
Temperature	Operating free-air, T_A	–40		85	°C
	Operating junction, T_J		105(2)	125	

(1) Always power up the DVDD supply (1.15 V) before the AVDD19 (1.9 V) supply. The AVDD (1.15 V) supply can come up in any order.
(2) Prolonged use above this junction temperature may increase the device failure-in-time (FIT) rate.

7.4 Thermal Information

THERMAL METRIC(1)		ADC32RF42 RMP (VQFN) 72 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	21.8	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	4.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	2.0	°C/W
ψ_{JT}	Junction-to-top characterization parameter	0.1	°C/W
ψ_{JB}	Junction-to-board characterization parameter	2.0	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	0.2	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

Copyright © 2017, Texas Instruments Incorporated

7.5 Electrical Characteristics

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
POWER CONSUMPTION(1) (Dual-Channel Operation, Both Channels A and B are Active; DDC Bypass Mode(2))						
I_{AVDD19}	1.9-V analog supply current	14-bit, bypass mode, f_S = 1.5 GSPS		1150	1969	mA
I_{AVDD}	1.15-V analog supply current	14-bit, bypass mode, f_S = 1.5 GSPS		604	1079	mA
I_{DVDD}	1.15-V digital supply current	14-bit, bypass mode, f_S = 1.5 GSPS		1000	1846	mA
P_D	Power dissipation	14-bit, bypass mode, f_S = 1.5 GSPS		4.03	6.95	W
	Global power-down power dissipation			360		mW
ANALOG INPUTS						
	Resolution			14		Bits
	Differential input full-scale			1.35		V_{PP}
V_{IC}	Input common-mode voltage			1.2(3)		V
R_{IN}	Input resistance	Differential resistance at dc		65		Ω
C_{IN}	Input capacitance	Differential capacitance at dc		2		pF
	V_{CM} common-mode voltage output			1.2		V
	Analog input bandwidth (–3-dB point)	ADC driven with 50-Ω source		3200		MHz
ISOLATION						
	Crosstalk isolation between channel A and channel B(4)	f_{IN} = 100 MHz		100		dBc
		f_{IN} = 900 MHz		99		
		f_{IN} = 1800 MHz		95		
		f_{IN} = 2700 MHz		86		
		f_{IN} = 3500 MHz		85		
CLOCK INPUT(5)						
	Input clock frequency		750	1500		MHz
	Differential (peak-to-peak) input clock amplitude		0.5	1.5	2.5	V_{PP}
	Input clock duty cycle		45%	50%	55%	
	Internal clock biasing			1.0		V
	Internal clock termination (differential)			100		Ω

(1) See the *Power Consumption in Different Modes* section for more details.
(2) Full-scale signal is applied to the analog inputs of all active channels.
(3) When used in dc-coupling mode, the common-mode voltage at the analog inputs should be kept within V_{CM} ±25 mV for best performance.
(4) Crosstalk is measured with a –2-dBFS input signal on aggressor channel and no input on the victim channel.
(5) See Figure 32.

Copyright © 2017, Texas Instruments Incorporated

7.6 AC Performance Characteristics

typical values specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN(1)	NOM	MAX	UNIT
SNR	Signal-to-noise ratio	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		62.8		dBFS
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		62.6		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		61.1		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		60.4		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		60.0		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		58.9		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		57.9		
NSD	Noise spectral density averaged across the Nyquist zone	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		151.6		dBFS/Hz
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		151.4		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		149.8		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		149.1		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		148.8		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		147.6		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		146.7		
	Small-signal SNR	f_{IN} = 950 MHz, A_{OUT} = –40 dBFS		63.0		dBFS
NF(2)	Input noise figure	f_{IN} = 950 MHz, A_{OUT} = –40 dBFS		27.7		dB
SINAD	Signal-to-noise and distortion ratio	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		61.4		dBFS
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		61.0		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		60.9		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		59.9		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		59.2		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		58.2		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		55.8		
ENOB	Effective number of bits	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		9.9		Bits
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		9.8		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		9.8		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		9.6		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		9.5		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		9.4		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		9.0		
SFDR	Spurious-free dynamic range	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		67		dBc
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		64		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		70		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		67		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		66		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		64		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		58		

(1) Minimum values are specified at A_{OUT} = –3 dBFS.
(2) The ADC internal resistance = 65 Ω, the driving source resistance = 50 Ω.

Copyright © 2017, Texas Instruments Incorporated

AC Performance Characteristics (continued)

typical values specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN(1)	NOM	MAX	UNIT
HD2	Second-order harmonic distortion	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		68		dBc
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		64		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		72		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		70		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		67		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		64		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		58		
HD3	Third-order harmonic distortion	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		67		dBc
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		71		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		70		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		67		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		70		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		73		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		66		
HD4, HD5	Fourth- and fifth-order harmonic distortion	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		89		dBc
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		84		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		85		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		83		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		85		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		83		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		82		
IL spur	Interleaving spur: $f_S / 2 – f_{IN}$,	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		91		dBc
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		87		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		83		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		82		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		82		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		82		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		80		
HD2 IL	Interleaving spur for HD2: $f_S / 2$ – HD2	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		86		dBc
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		87		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		83		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		80		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		79		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		79		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		80		
Worst spur	Spurious-free dynamic range (excluding HD2, HD3, HD4, HD5, and interleaving spurs IL and HD2 IL)	f_{IN} = 100 MHz, A_{OUT} = –2 dBFS		80		dBc
		f_{IN} = 300 MHz, A_{OUT} = –2 dBFS		82		
		f_{IN} = 950 MHz, A_{OUT} = –2 dBFS		80		
		f_{IN} = 1200 MHz, A_{OUT} = –2 dBFS		82		
		f_{IN} = 1350 MHz, A_{OUT} = –2 dBFS		79		
		f_{IN} = 1850 MHz, A_{OUT} = –2 dBFS		80		
		f_{IN} = 2100 MHz, A_{OUT} = –2 dBFS		81		
IMD3	Third-order intermodulation distortion	f_{IN1} = 940 MHz, f_{IN2} = 960 MHz, A_{OUT} = –8 dBFS (each tone)		75		dBFS

Copyright © 2017, Texas Instruments Incorporated

7.7 Digital Requirements

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	NOM	MAX	UNIT
DIGITAL INPUTS (RESET, SCLK, SEN, SDIN, PDN, GPIO1, GPIO2, GPIO3, GPIO4)						
V_{IH}	High-level input voltage		0.8			V
V_{IL}	Low-level input voltage				0.4	V
I_{IH}	High-level input current			50		µA
I_{IL}	Low-level input current			–50		µA
C_i	Input capacitance			4		pF
DIGITAL OUTPUTS (SDOUT, GPIO1, GPIO2, GPIO3, GPIO4)						
V_{OH}	High-level output voltage		AVDD19 –0.1	AVDD19		V
V_{OL}	Low-level output voltage				0.1	V
DIGITAL INPUTS (SYSREFP and SYSREFM; SYNCBP and SYNCBM; Requires External Biasing)						
V_{ID}	Differential input voltage		350	450	800	mV_{PP}
V_{CM}	Input common-mode voltage		1.05	1.2	1.325	V
DIGITAL OUTPUTS (JESD204B Interface: DA[3:0], DB[3:0], Meets JESD204B LV-0IF-11G-SR Standard)						
$\lvert V_{OD} \rvert$	Output differential voltage			700		mV_{PP}
$\lvert V_{OCM} \rvert$	Output common-mode voltage			450		mV
	Transmitter short-circuit current	Transmitter pins shorted to any voltage between –0.25 V and 1.45 V	–100		100	mA
z_{os}	Single-ended output impedance			50		Ω
C_o	Output capacitance	Output capacitance inside the device, from either output to ground		2		pF

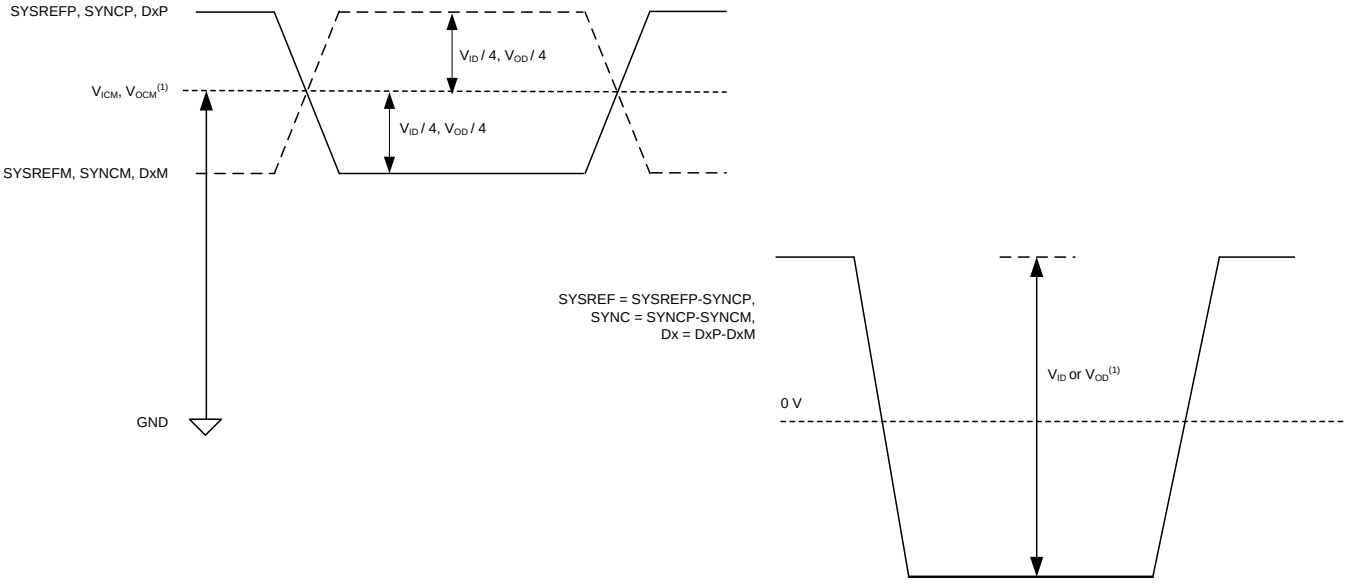
Copyright © 2017, Texas Instruments Incorporated

7.8 Timing Requirements

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 2.6 GHz, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)

		MIN	NOM	MAX	UNIT
SAMPLE TIMING					
	Aperture delay	250		750	ps
	Aperture delay matching between two channels on the same device		±15		ps
	Aperture delay matching between two devices at the same temperature and supply voltage		±150		ps
	Aperture jitter, clock amplitude = 2 V_{PP}		90		f_S
	Fast overrange latency, ADC sample to FOVR indication on GPIO pins		70		Input clock cycles
t_{PD}	Propagation delay time: logic gates and output buffer delay (does not change with f_S)		6		ns
SYSREF TIMING (1)					
t_{SU_SYSREF}	SYSREF setup time: referenced to clock rising edge, 1.5 GSPS	140	70		ps
t_{H_SYSREF}	SYSREF hold time: referenced to clock rising edge, 1.5 GSPS	50	20		ps
	Valid transition window sampling period: $t_{SU_SYSREF} - t_{H_SYSREF}$, 1.5 GSPS	476			ps
JESD OUTPUT INTERFACE TIMING					
UI	Unit interval: 12.5 Gbps	80	100	400	ps
	Serial output data rate	2.5	10.0	12.5	Gbps
	Rise, fall times: 1-pF, single-ended load capacitance to ground		60		ps
	Total jitter: BER of 1E-15 and lane rate = 12.5 Gbps		25		%UI
	Random jitter: BER of 1E-15 and lane rate = 12.5 Gbps		0.99		%UI, rms
	Deterministic jitter: BER of 1E-15 and lane rate = 12.5 Gbps		9.1		%UI, pk-pk

(1) Common-mode voltage for the SYSREF input is kept at 1.2 V.



V_{OCM} is not the same as V_{ICM}. Similarly, V_{OD} is not the same as V_{ID}.

Figure 1. Logic Levels for Digital Inputs and Outputs

Copyright © 2017, Texas Instruments Incorporated

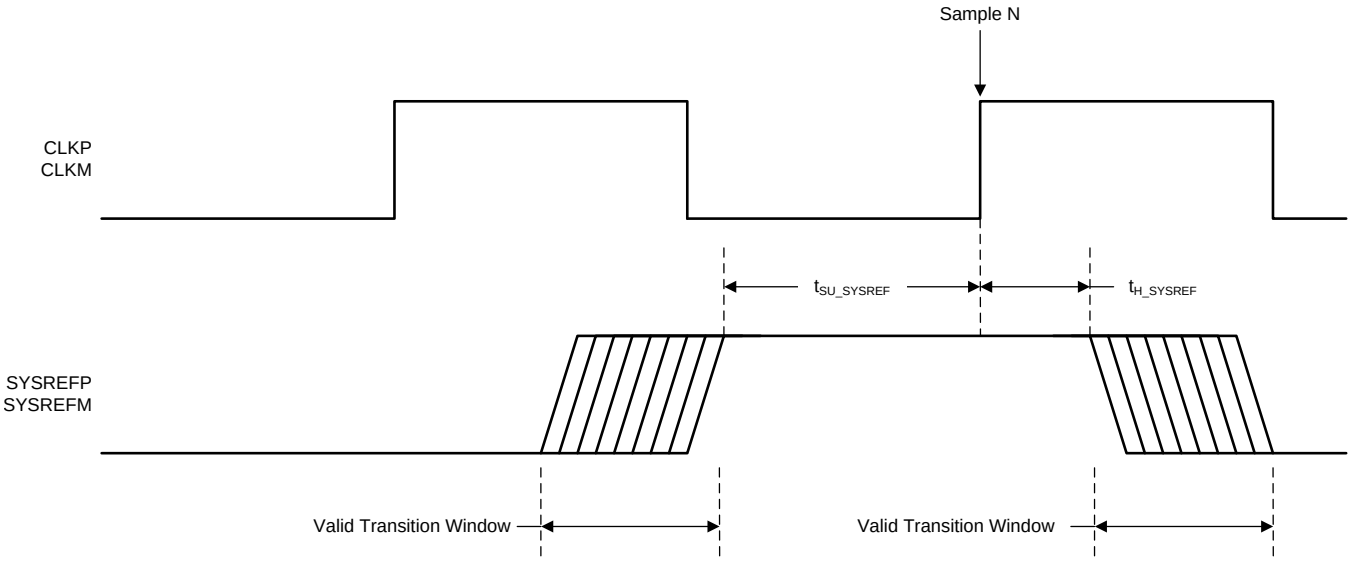
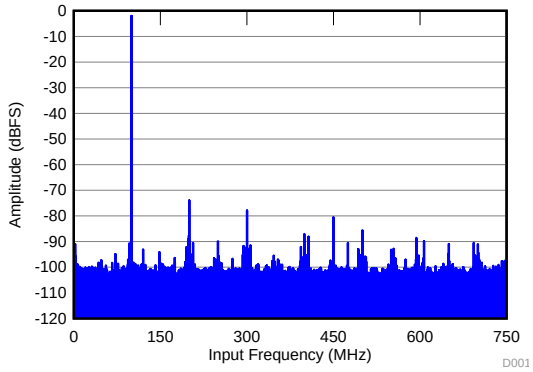


Figure 2. SYSREF Timing Diagram

Copyright © 2017, Texas Instruments Incorporated

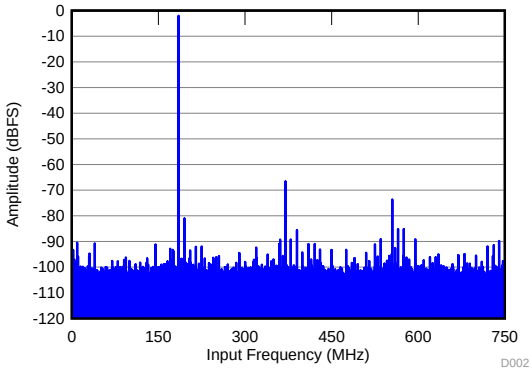
7.9 Typical Characteristics

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 65536 points FFT, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)



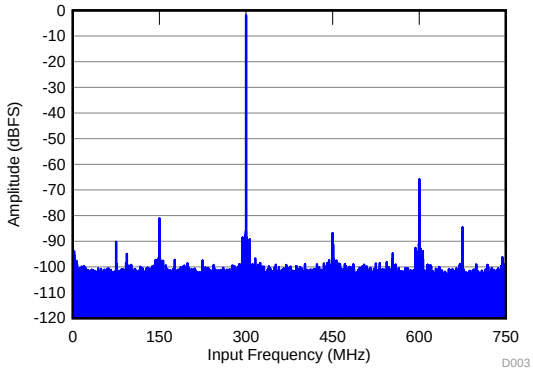
SFDR = 73 dBc, SNR = 62.4 dBFS, SINAD = 62 dBFS,
THD = 71 dBc, HD2 = –75 dBFS, HD3 = –78 dBFS,
SFDR (non HD2, HD3) = 85 dBc, IL spur = 81 dBFS

Figure 3. FFT for 100-MHz Input Signal



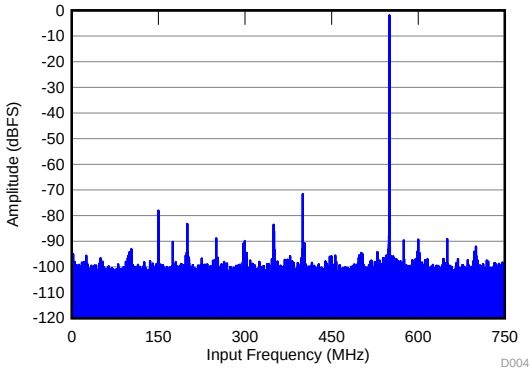
SFDR = 65 dBc, SNR = 62.3 dBFS, SINAD = 61 dBFS,
THD = 64 dBc, HD2 = –67 dBFS, HD3 = –73 dBFS,
SFDR (non HD2, HD3) = 89 dBc, IL spur = 81 dBFS

Figure 4. FFT for 185-MHz Input Signal



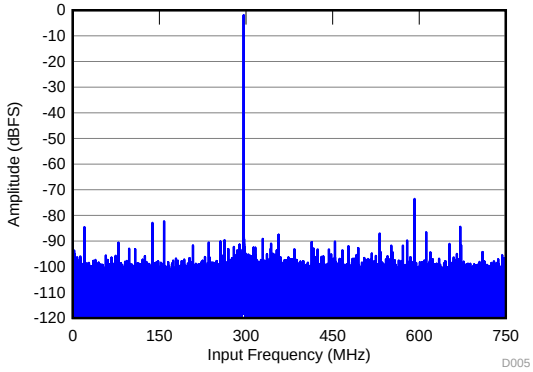
SFDR = 65 dBc, SNR = 62.3 dBFS, SINAD = 61 dBFS,
THD = 64 dBc, HD2 = –67 dBFS, HD3 = –75 dBFS,
SFDR (non HD2, HD3) = 74 dBc, IL spur = 82 dBFS

Figure 5. FFT for 300-MHz Input Signal



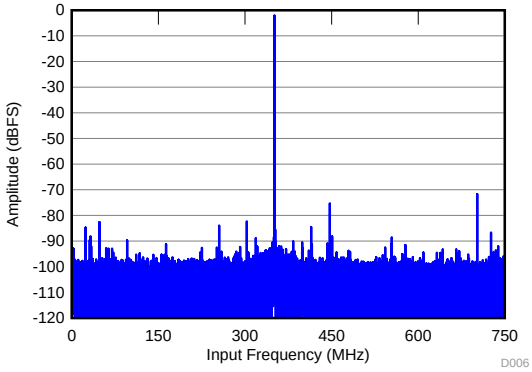
SFDR = 70 dBc, SNR = 60.8 dBFS, SINAD = 60 dBFS,
THD = 69 dBc, HD2 = –72 dBFS, HD3 = –78 dBFS,
SFDR (non HD2, HD3) = 81 dBc, IL spur = 82 dBFS

Figure 6. FFT for 950-MHz Input Signal



SFDR = 72 dBc, SNR = 60.2 dBFS, SINAD = 60 dBFS,
THD = 71 dBc, HD2 = –74 dBFS, HD3 = –87 dBFS,
SFDR (non HD2, HD3) = 80 dBFS, IL spur = 80 dBFS

Figure 7. FFT for 1200-MHz Input Signal



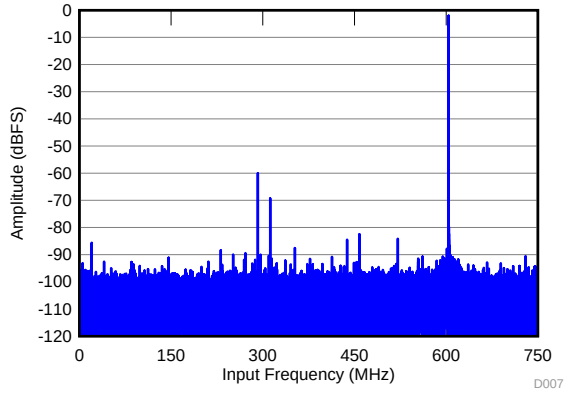
SFDR = 70 dBc, SNR = 58.7 dBFS, SINAD = 58 dBFS,
HD2 = –72 dBFS, HD3 = –75 dBFS,
SFDR (non HD2, HD3) = 79 dBc, THD = 68 dBc,
IL spur = 80 dBFS

Figure 8. FFT for 1850-MHz Input Signal

Copyright © 2017, Texas Instruments Incorporated

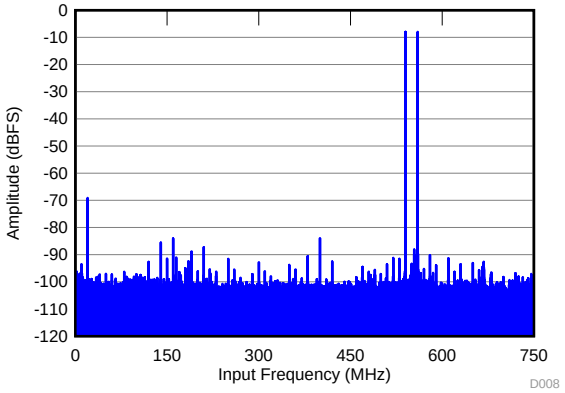
Typical Characteristics (continued)

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 65536 points FFT, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)



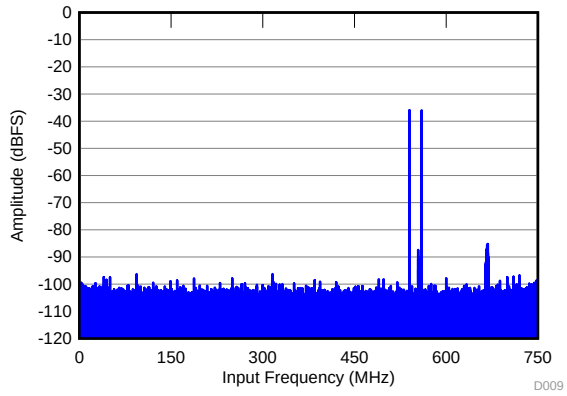
SFDR = 59 dBc, SNR = 57.9 dBFS, SINAD = 56 dBFS,
HD2 = –61 dBFS, HD3 = –69 dBFS,
SFDR (non HD2, HD3) = 81 dBc, THD = 58 dBc,
IL spur = 83 dBFS

Figure 9. FFT for 2100-MHz Input Signal



f_{IN1} = 940 MHz, f_{IN2} = 960 MHz,
A_{OUT} = –8 dBFS, IMD = 75 dBFS

Figure 10. FFT for Two-Tone Input Signal (–8 dBFS)



f_{IN1} = 940 MHz, f_{IN2} = 960 MHz,
A_{OUT} = –36 dBFS, IMD = 94 dBFS

Figure 11. FFT for Two-Tone Input Signal (–36 dBFS)

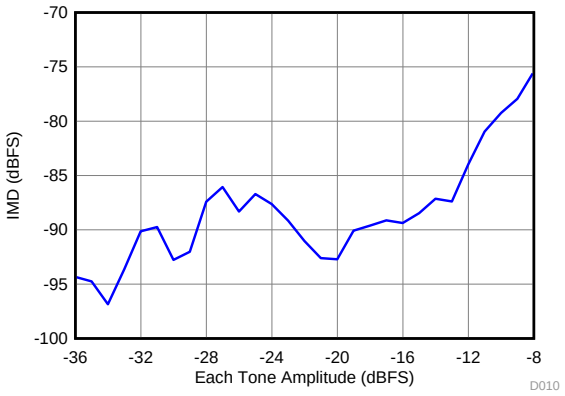


Figure 12. Intermodulation Distortion vs Input Amplitude (940 MHz and 960 MHz)



Figure 13. Spurious-Free Dynamic Range vs Input Frequency

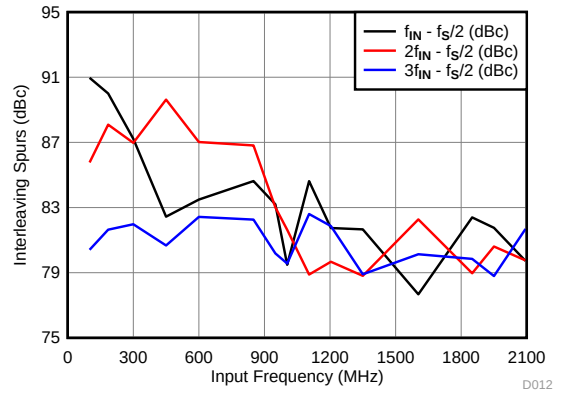


Figure 14. IL Spur vs Input Frequency

Copyright © 2017, Texas Instruments Incorporated

Typical Characteristics (continued)

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 65536 points FFT, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)

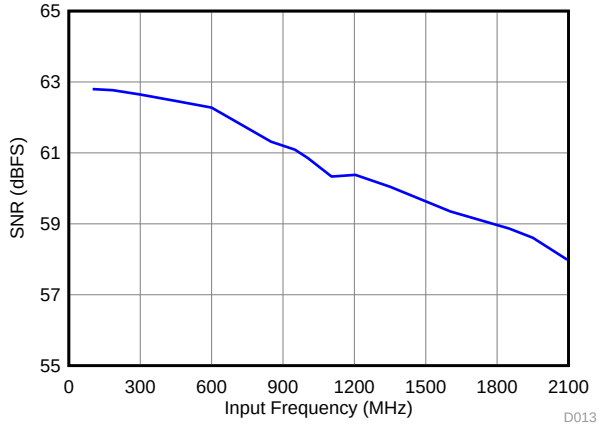
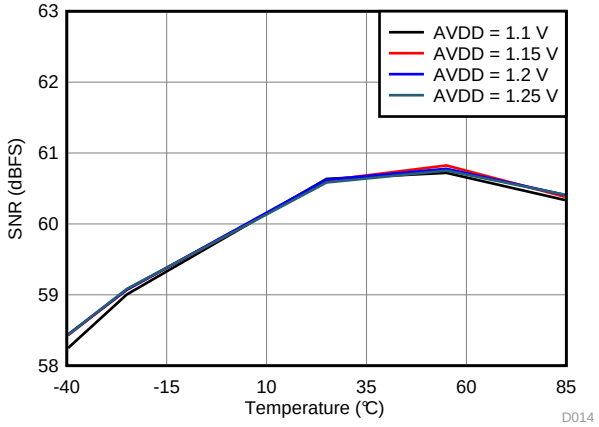
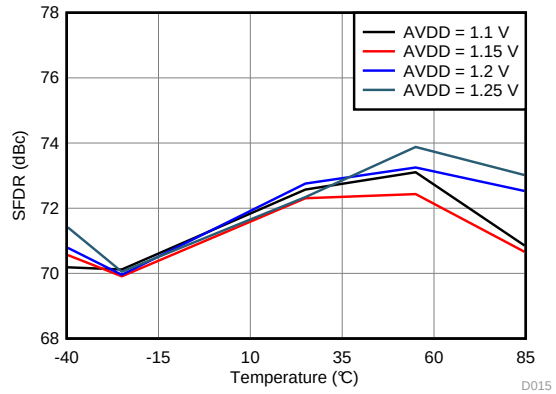


Figure 15. Signal-to-Noise Ratio vs Input Frequency



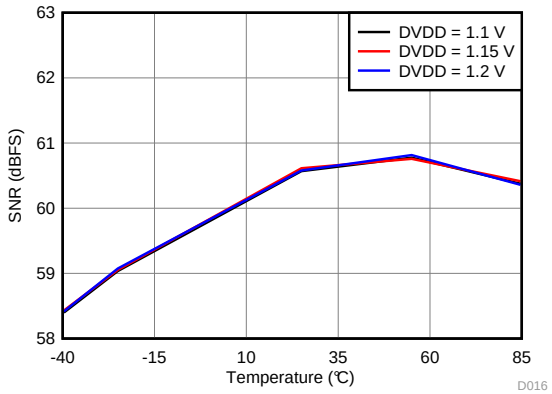
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 16. Signal-to-Noise Ratio vs AVDD Supply and Temperature



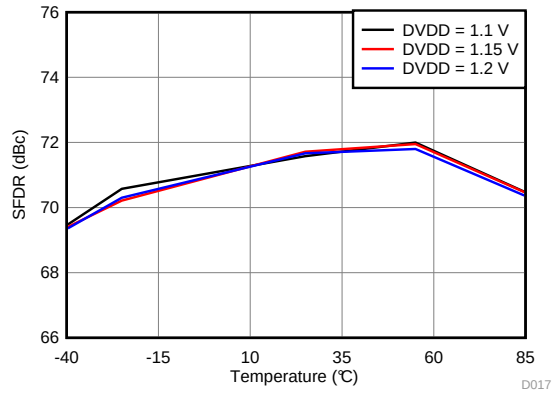
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 17. Spurious-Free Dynamic Range vs AVDD Supply and Temperature



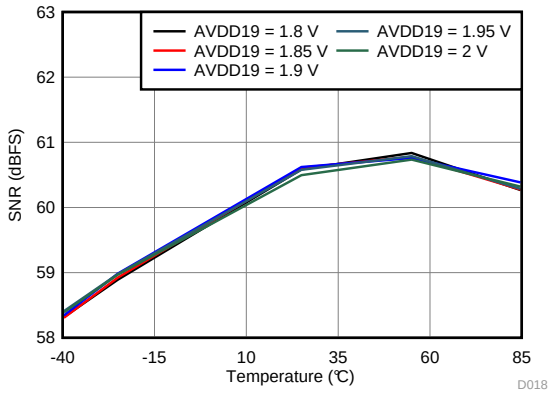
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 18. Signal-to-Noise Ratio vs DVDD Supply and Temperature



f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 19. Spurious-Free Dynamic Range vs DVDD Supply and Temperature



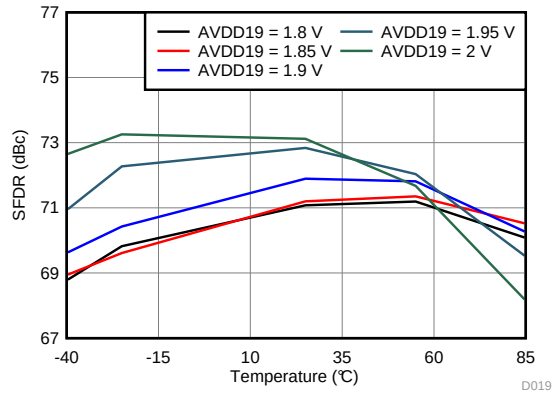
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 20. Signal-to-Noise Ratio vs AVDD19 Supply and Temperature

Copyright © 2017, Texas Instruments Incorporated

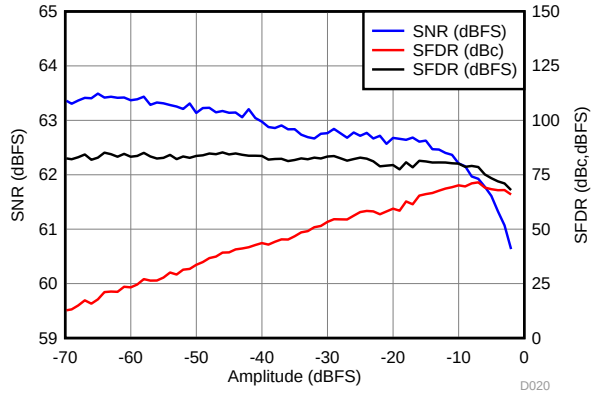
Typical Characteristics (continued)

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 65536 points FFT, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)



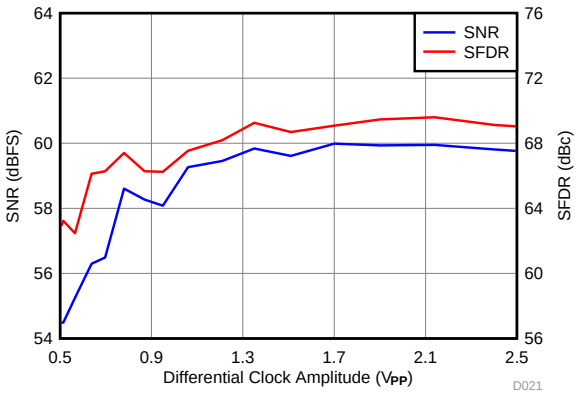
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 21. Spurious-Free Dynamic Range vs AVDD19 Supply and Temperature



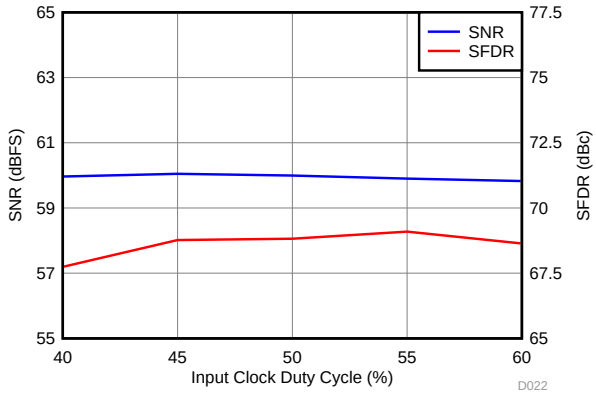
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 22. Performance vs Amplitude



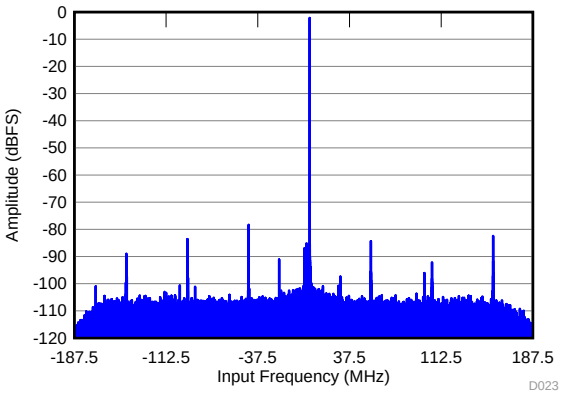
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 23. Performance vs Clock Amplitude



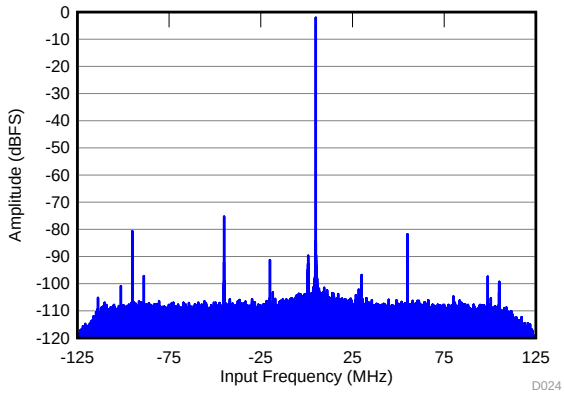
f_{IN} = 950 MHz, A_{IN} = –2 dBFS

Figure 24. Performance vs Clock Duty Cycle



f_{IN} = 1850 MHz, A_{IN} = –2 dBFS, SNR = 63.8 dBFS, SFDR (includes IL) = 78 dBc, f_S = 1500 MSPS

Figure 25. FFT in 4x Decimation



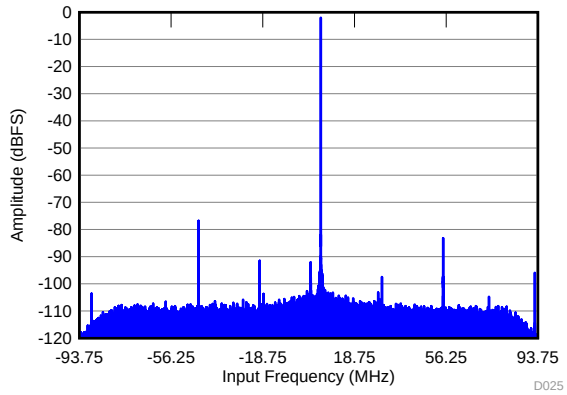
f_{IN} = 1850 MHz, A_{IN} = –2 dBFS, SNR = 65 dBFS, SFDR (includes IL) = 75 dBc, f_S = 1500 MSPS

Figure 26. FFT in 6x Decimation

Copyright © 2017, Texas Instruments Incorporated

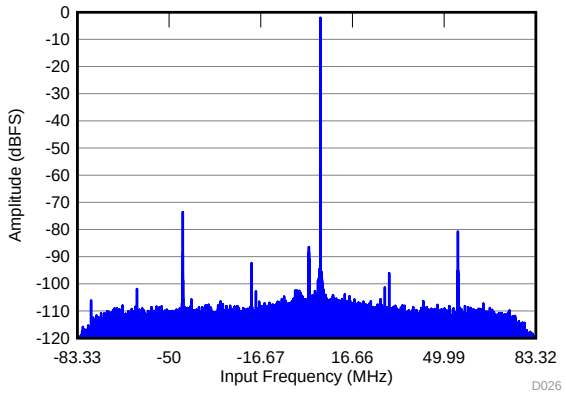
Typical Characteristics (continued)

typical values are specified at an ambient temperature of 25°C; minimum and maximum values are specified over an ambient temperature range of –40°C to +85°C; and ADC sampling rate = 1.5 GHz, 65536 points FFT, 50% clock duty cycle, AVDD19 = 1.9 V, AVDD = 1.15 V, DVDD = 1.15 V, –2-dBFS differential input, and 0-dB digital gain (unless otherwise noted)



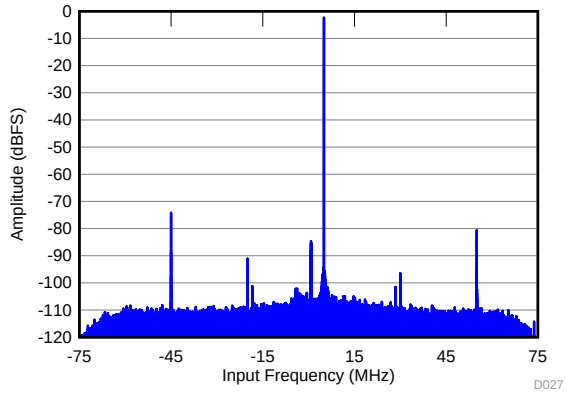
f_{IN} = 1850 MHz, A_{IN} = –2 dBFS, SNR = 66 dBFS, SFDR (includes IL) = 77 dBc, f_S = 1500 MSPS

Figure 27. FFT in 8x Decimation



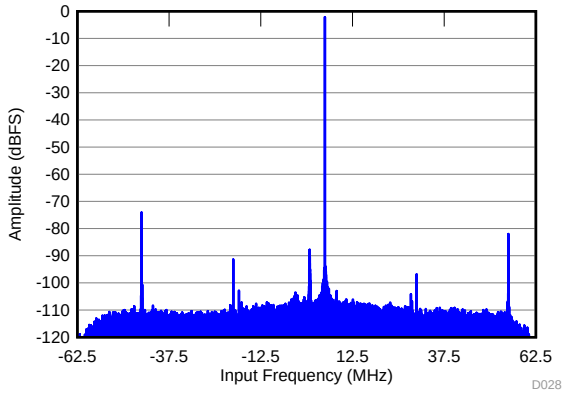
f_{IN} = 1850 MHz, A_{IN} = –2 dBFS, SNR = 65.8 dBFS, SFDR (includes IL) = 74 dBc, f_S = 1500 MSPS

Figure 28. FFT in 9x Decimation



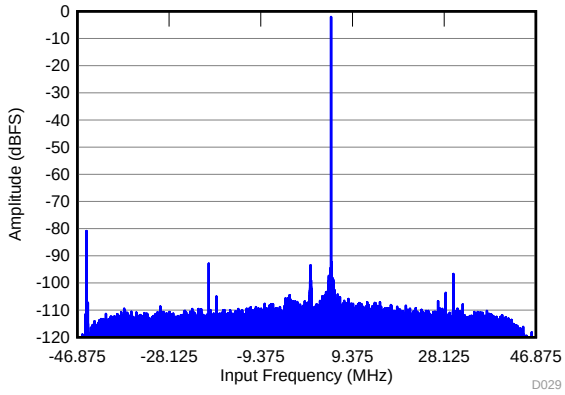
f_{IN} = 1850 MHz, A_{IN} = –2 dBFS, SNR = 65.9 dBFS, SFDR (includes IL) = 74 dBc, f_S = 1500 MSPS

Figure 29. FFT in 10x Decimation



f_{IN} = 1850 MHz, A_{IN} = –2 dBFS, SNR = 66.4 dBFS, SFDR (includes IL) = 74.1 dBc, f_S = 1500 MSPS

Figure 30. FFT in 12x Decimation



f_{IN} = 1850 MHz, A_{IN} = –2 dBFS, SNR = 68.1 dBFS, SFDR (includes IL) = 80.9 dBc, f_S = 1500 MSPS

Figure 31. FFT in 16x Decimation

Copyright © 2017, Texas Instruments Incorporated

8 Parameter Measurement Information

8.1 Input Clock Diagram

Figure 32 shows the input clock diagram.

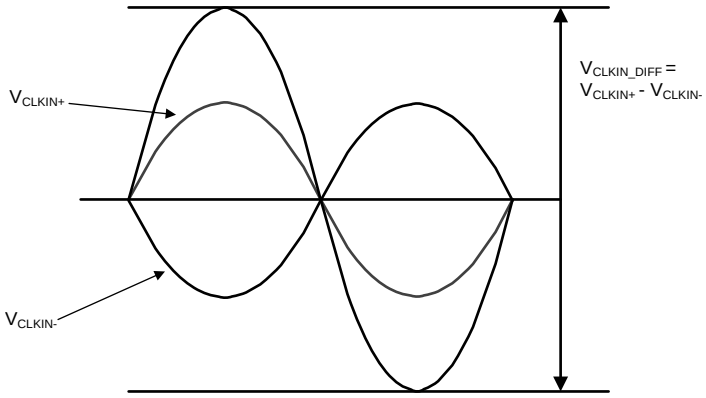


Figure 32. Input Clock Diagram

Copyright © 2017, Texas Instruments Incorporated

9 Detailed Description

9.1 Overview

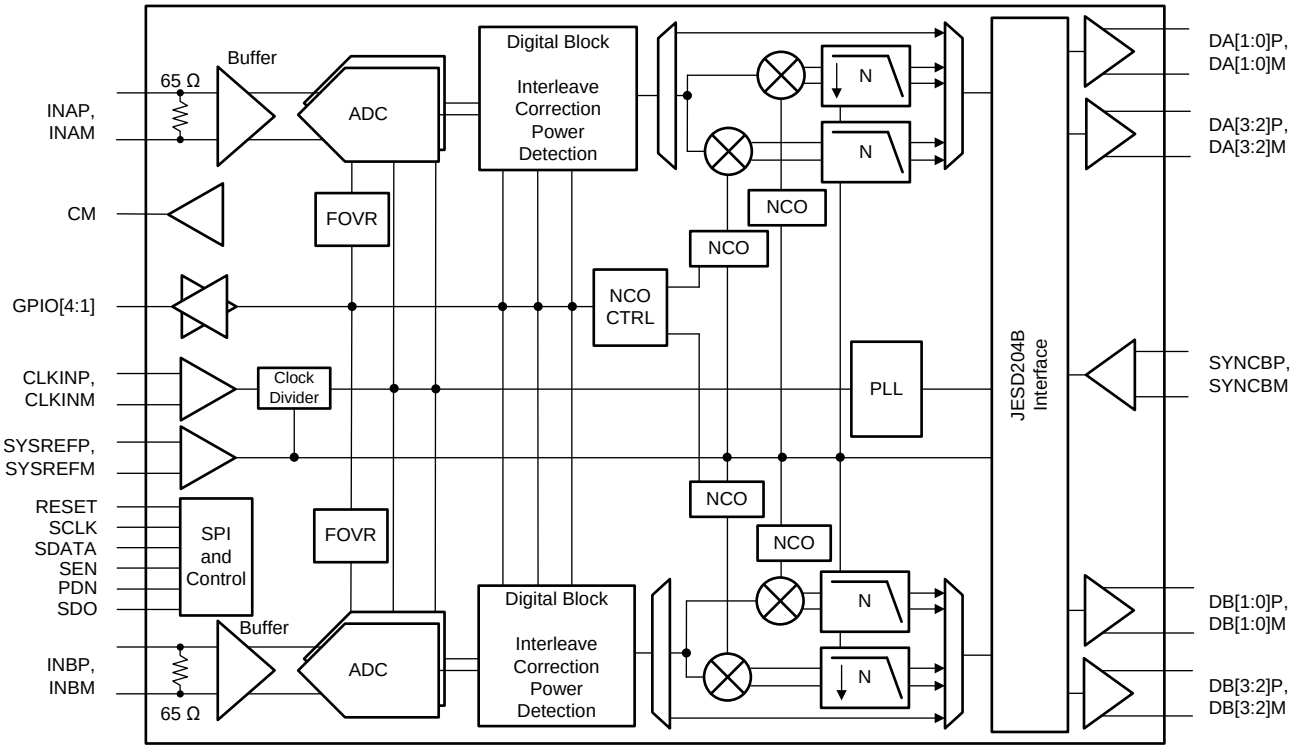
The ADC32RF42 is a dual, 14-bit, 1.5-GSPS, analog-to-digital converter (ADC) followed by a multi-band digital down-converter (DDC) that can be bypassed, and a back-end JESD204B digital interface.

The ADCs are preceded by an input buffer and on-chip termination to provide a uniform input impedance over a large input frequency range. Furthermore, an internal differential clamping circuit provides first-level protection against overvoltage conditions. Each ADC channel is internally interleaved two times and equipped with background, analog and digital, and interleaving correction.

The on-chip DDC enables single- or dual-band internal processing to pre-select and filter smaller bands of interest and also reduces the digital output data traffic. Each DDC is equipped with up to three independent, 16-bit numerically-controlled oscillators (NCOs) for phase coherent frequency hopping; the NCOs can be controlled through the SPI or GPIO pins. The ADC32RF42 also provides three different power detectors on-chip with alarm outputs in order to support external automatic gain control (AGC) loops.

The processed data are passed into the JESD204B interface where the data are framed, encoded, serialized, and output on one to four lanes per channel, depending on the ADC sampling rate and decimation. The CLKIN, SYSREF, and SYNCB inputs provide the device clock and the SYSREF and SYNCB signals to the JESD204B interface that are used to derive the internal local frame and local multiframe clocks and establish the serial link. All features of the ADC32RF42 are configurable through the SPI.

9.2 Functional Block Diagram



Copyright © 2017, Texas Instruments Incorporated

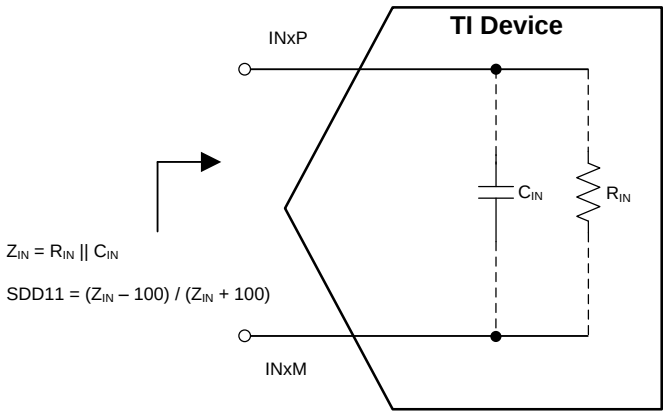
Copyright © 2017, Texas Instruments Incorporated

9.3 Feature Description

9.3.1 Analog Inputs

The ADC32RF42 analog signal inputs are designed to be driven differentially. The analog input pins have internal analog buffers that drive the sampling circuit. The ADC32RF42 provides on-chip, differential termination to minimize reflections. The buffer also helps isolate the external driving circuit from the internal switching currents of the sampling circuit, thus resulting in a more constant SFDR performance across input frequencies.

The common-mode voltage of the signal inputs is internally biased to CM using the 32.5-Ω termination resistors that allow for ac-coupling of the input drive network. Figure 33 and Figure 34 show SDD11 at the analog inputs from dc to 5 GHz with a 100-Ω reference impedance.



Copyright © 2016, Texas Instruments Incorporated

Figure 33. Equivalent Input Impedance

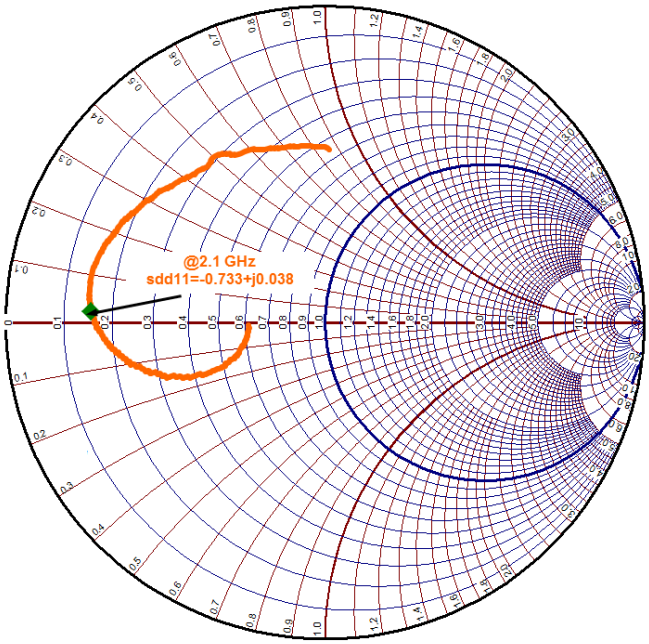


Figure 34. SDD11 Over the Input Frequency Range

Feature Description (continued)

The input impedance of analog inputs can also be modelled as parallel combination of equivalent resistance and capacitance. Figure 35 and Figure 36 show how equivalent impedance (C_{IN} and R_{IN}) vary over frequency.

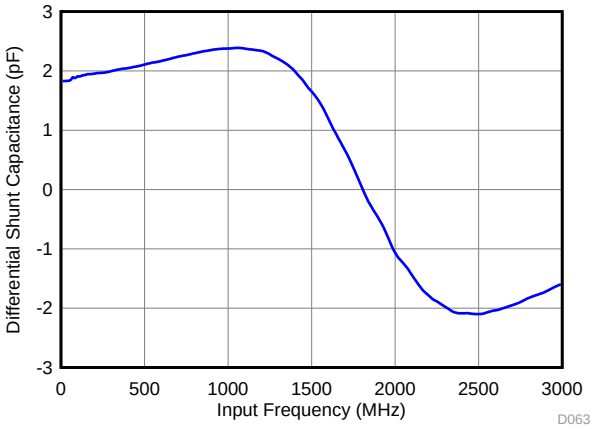


Figure 35. Differential Input Capacitance vs Input Frequency

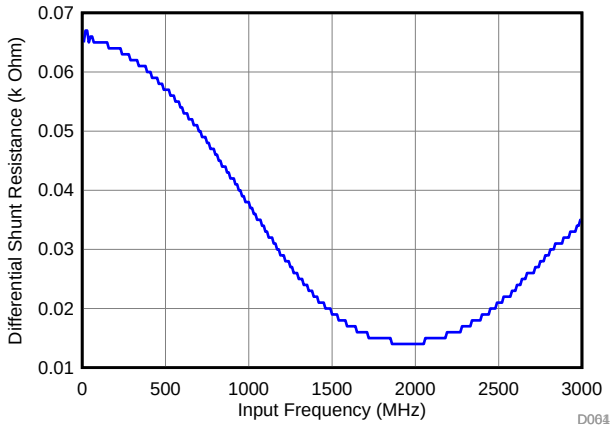


Figure 36. Differential Input Resistance vs Input Frquency

Each input pin (INP, INM) must swing symmetrically between (CM + 0.3375 V) and (CM – 0.3375 V), resulting in a 1.35-V_{PP} (default) differential input swing. As shown in Figure 37, the input sampling circuit has a 3-dB bandwidth that extends up to approximately 3.2 GHz.

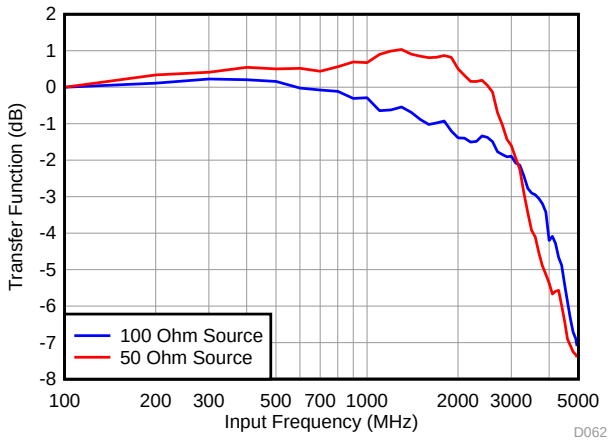


Figure 37. Input Bandwidth with a 100-Ω Source Resistance

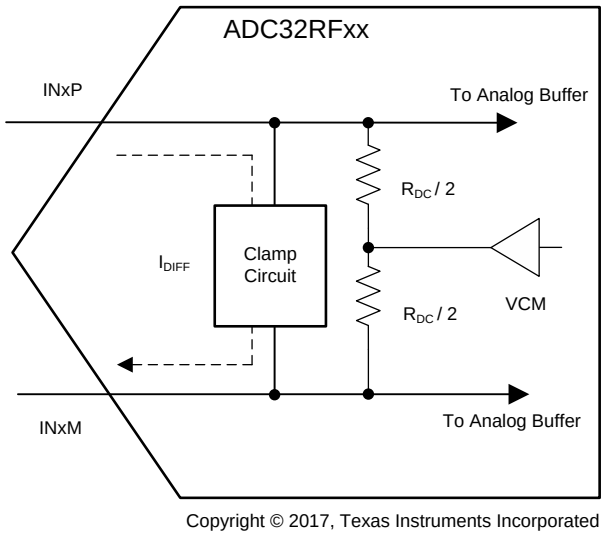
Copyright © 2017, Texas Instruments Incorporated

Feature Description (continued)

9.3.1.1 Input Clamp Circuit

The ADC32RF42 analog inputs include an internal, differential clamp for overvoltage protection. As shown in Figure 38 and Figure 39, the clamp triggers for any input signals at approximately 600 mV above the input common-mode voltage, effectively limiting the maximum input signal to approximately 2.4 V_{PP}.

When the clamp circuit conducts, the maximum differential current flowing through the circuit (via input pins) must be limited to 20 mA.



Copyright © 2017, Texas Instruments Incorporated

Figure 38. Clamp Circuit in the ADC32RF42

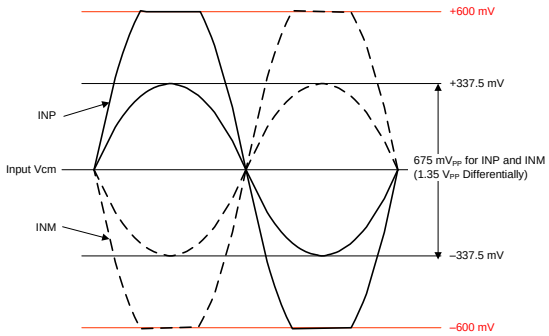


Figure 39. Clamp Response Timing Diagram

Feature Description (continued)

9.3.2 Clock Input

The ADC32RF42 sampling clock input includes internal 100-Ω differential termination along with on-chip biasing. The clock input is recommended to be ac-coupled externally. The input bandwidth of the clock input is approximately 3 GHz; the smith chart of Figure 40 shows a clock input impedance with a 100-Ω reference impedance.

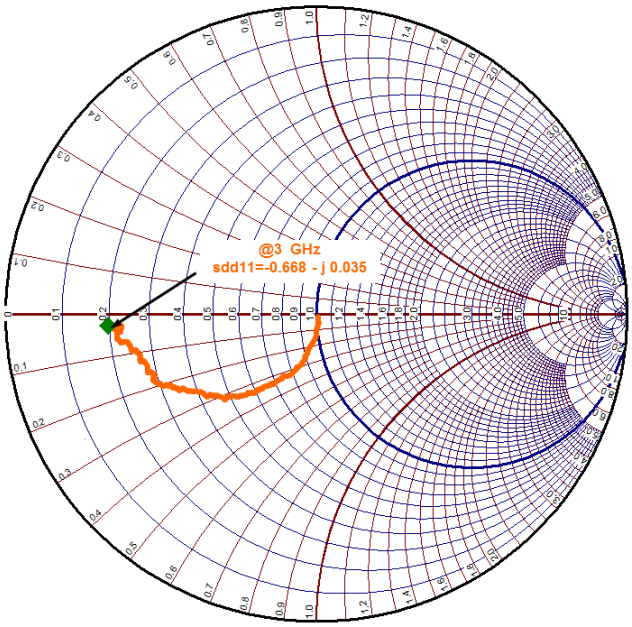


Figure 40. SDD11 of the Clock Input

Copyright © 2017, Texas Instruments Incorporated

Feature Description (continued)

The analog-to-digital converter (ADC) aperture jitter is a function of the clock amplitude applied to the pins. Figure 41 shows the equivalent aperture jitter for input frequencies at a 1-GHz and a 2-GHz input (f_S = 1.5 GSPS). Depending on the clock frequency, a matching circuit can be designed in order to maximize the clock amplitude.

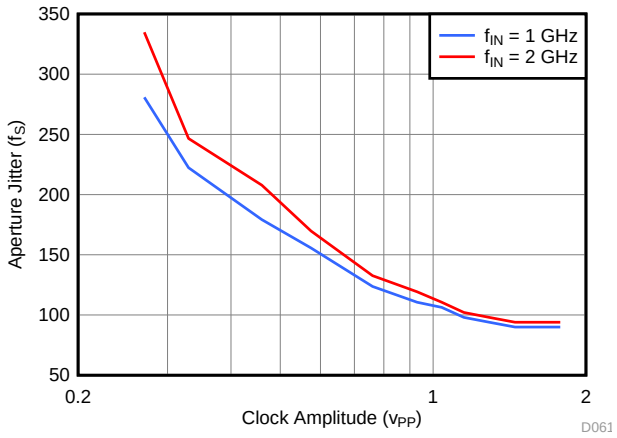


Figure 41. Equivalent Aperture Jitter vs Input Clock Amplitude

9.3.3 SYSREF Input

The SYSREF signal is a periodic signal that is sampled by the ADC32RF42 device clock and is used to align the boundary of the local multiframe clock inside the data converter. SYSREF is also used to reset critical blocks [such as the clock divider for the interleaved ADCs, numerically-controlled oscillators (NCOs), decimation filters and so forth].

The SYSREF input requires external biasing. Furthermore, SYSREF must be established before the SPI registers are programmed. A programmable delay on the SYSREF input, as shown in Figure 42, is available to help with skew adjustment when the sampling clock and SYSREF are not provided from the same source.

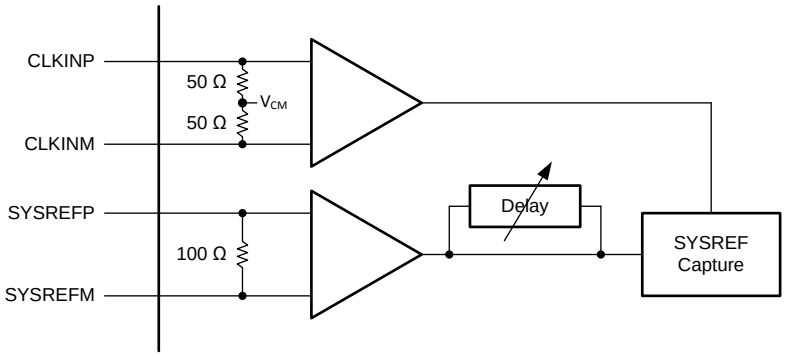


Figure 42. SYSREF Internal Circuit Diagram

Copyright © 2017, Texas Instruments Incorporated

Feature Description (continued)

9.3.3.1 Using SYSREF

The ADC32RF42 uses SYSREF information to reset the clock divider, the NCO phase, and the LMFC counter of the JESD interface. The device provides flexibility to provide SYSREF information either from dedicated pins or through SPI register bits. As Figure 43 shows, SYSREF is asserted by a low-to-high transition on the SYSREF pins or a 0-to-1 change in the ASSERT SYSREF REG bit when using SPI registers.

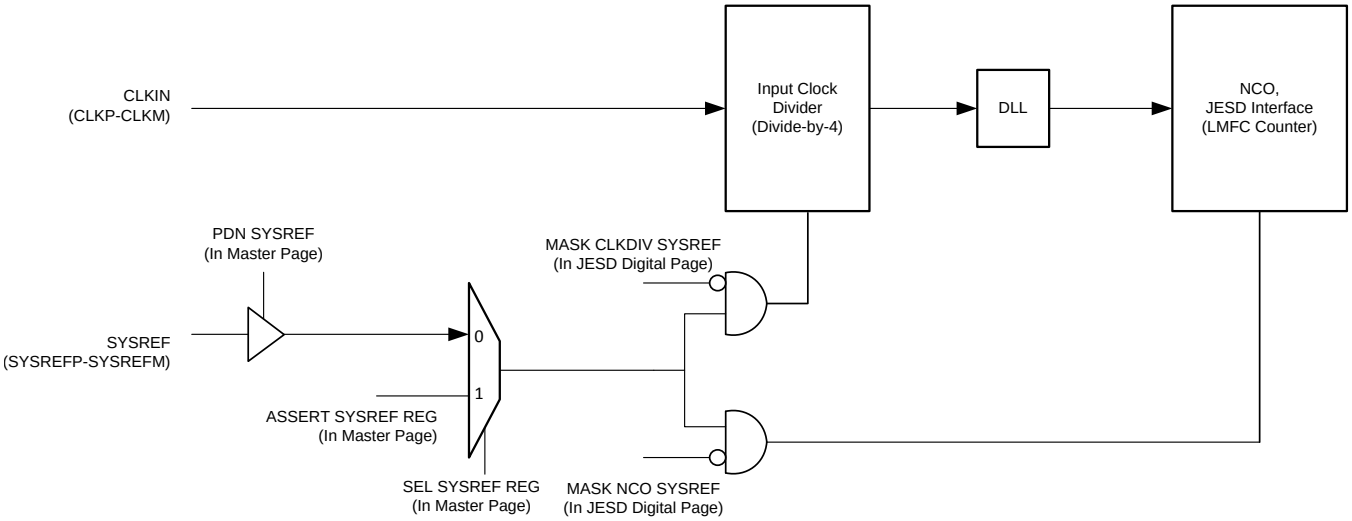


Figure 43. Using SYSREF to Reset the Clock Divider, the NCO, and the LMFC Counter

The ADC32RF42 samples the SYSREF signal on the input clock rising edge. Required setup and hold time are listed in the *Timing Requirements* table. Table 1 shows that the input clock divider gets reset each time that SYSREF is asserted, whereas the NCO phase and the LMFC counter of the JESD interface are reset on each SYSREF assertion after disregarding the first two assertions.

Table 1. Asserting SYSREF

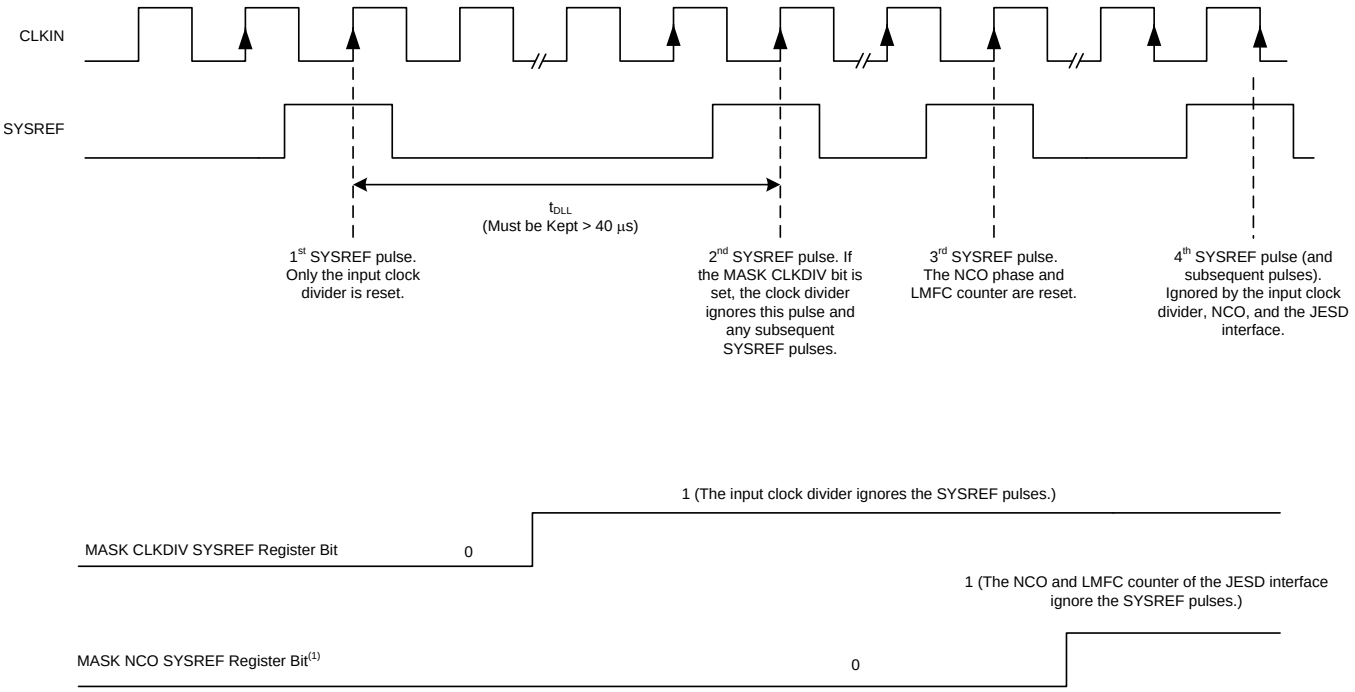
SYSREF ASSERTION INDEX	ACTION		
	INPUT CLOCK DIVIDER	NCO PHASE	LMFC COUNTER
1	Gets reset	Does not get reset	Does not get reset
2	Gets reset	Does not get reset	Does not get reset
3	Gets reset	Gets reset	Gets reset
4 and onwards	Gets reset	Gets reset	Gets reset

Copyright © 2017, Texas Instruments Incorporated

The SESREF use-cases can be classified broadly into two categories:

1. SYSREF is applied as aperiodic multi-shot pulses.

   Figure 44 shows a case when only a counted number of pulses are applied as SYSREF to the ADC.



   Alternatively, the SYSREF buffer can be powered down with the PDN SYSREF bit.

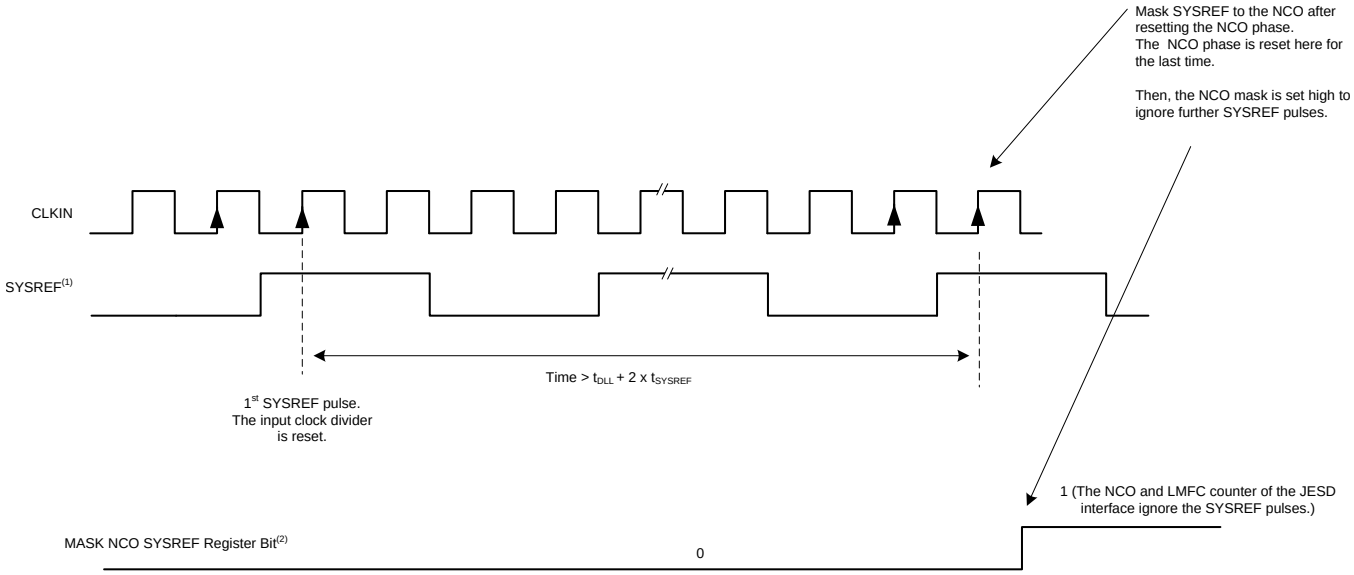
Figure 44. SYSREF Used as Aperiodic, Finite Number of Pulses

After the first SYSREF pulse is applied, allow the DLL in the clock path to settle by waiting for the t_{DLL} time (> 40 µs) before applying the second pulse. During this time, mask the SYSREF going to the input clock divider by setting the MASK CLKDIV SYSREF bit so that the divider output phase remains stable. The NCO phase and LMFC counter are reset on the third SYSREF pulse. After the third SYSREF pulse, the SYSREF going to the NCO and JESD block can be disabled by setting the MASK NCO SYSREF bit to avoid any unwanted resets.

Copyright © 2017, Texas Instruments Incorporated

2. SYSREF is applied as a periodic pulse.

Figure 45 shows how SYSREF can be applied as a continuous periodic waveform.



t_{SYSREF} is a period of the SYSREF waveform.

Alternatively, the SYSREF buffer can be powered down using the PDN SYSREF bit.

Figure 45. SYSREF Used as a Periodic Waveform

After applying the SYSREF signal, DLL must be allowed to lock, and the NCO phase and LMFC counter must be allowed to reset by waiting for at least the t_{DLL} (40 µs) + 2 × t_{SYSREF} time. Then, the SYSREF going to the NCO and JESD can be masked by setting the MASK NCO SYSREF register bit.

9.3.3.2 Frequency of the SYSREF Signal

Equation 1 describes that when SYSREF is a periodic signal, its frequency is required to be a sub-harmonic of the internal local multi-frame clock (LMFC) frequency. The LMFC frequency is determined by the selected decimation, frames per multi-frame setting (K), samples per frame (S), and device input clock frequency.

SYSREF = LMFC / N

where

- N is an integer value (1, 2, 3, and so forth) (1)

In order for the interleaving correction engine to synchronize properly, the SYSREF frequency must also be a multiple of f_S / 64. Table 2 provides a summary of the valid LMFC clock settings.

Table 2. SYSREF and LMFC Clock Frequency

OPERATING MODE	LMFS SETTING	LMFC CLOCK FREQUENCY	SYSREF FRQUENCY
Bypass mode	42810	f_S (1) / (10 × K)	f_S / [N × LCM (2) (64, 10 × K (3))]
Bypass mode	4222	f_S / (2 × K)	f_S / [N × LCM (64, 2 × K)]
Decimation	Various	f_S / (D × S (4) × K)	f_S / [N × LCM (64, D (5) × S × K)]

(1) f_S = sampling (device) clock frequency.
(2) LCM = least-common multiple.
(3) K = number of frames per multi-frame.
(4) S = samples per frame.
(5) D = decimation ratio.

The SYSREF signal is recommended to be a low-frequency signal less than 5 MHz in order to reduce coupling to the signal path both on the printed circuit board (PCB) as well as internal to the device.

Copyright © 2017, Texas Instruments Incorporated

Example 1: f_S = 1.5 GSPS, Bypass Mode (LMFS = 42810), K = 16

SYSREF = 1.5 GSPS / LCM (64, 10 × 16) / N = 4.6875 MHz / N

Operate SYSREF at 2.34375 MHz (effectively divide-by-640, N = 2)

Example 2: f_S = 1.5 GSPS, Divide-by-8 (LMFS = 8411), K = 16

SYSREF = 2.6 GSPS / LCM (4 ,64, 16) = 40.625 MHz / N

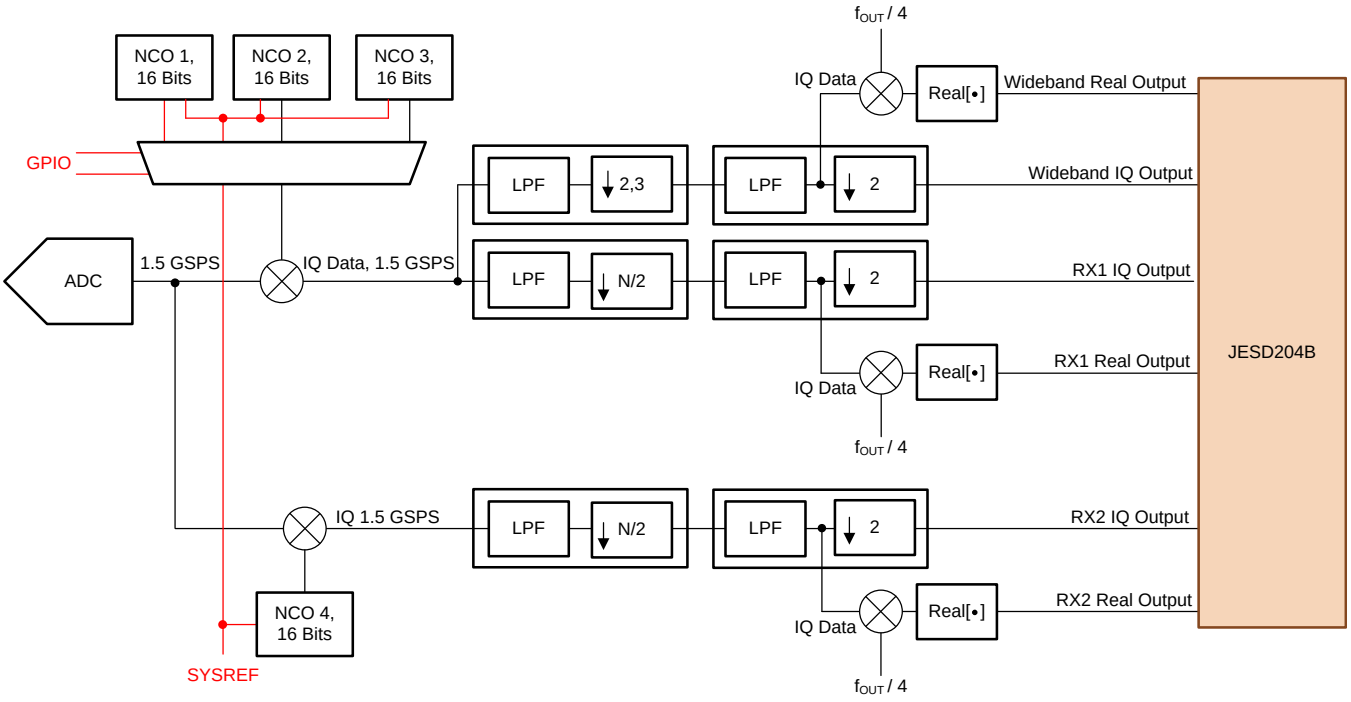
Operate SYSREF at 2.539063 MHz (effectively divide-by-1024, N = 16)

For proper device operation, disable the SYSREF signal after the JESD synchronization is established.

9.3.4 DDC Block

The ADC32RF42 provides a sophisticated on-chip, digital down converter (DDC) block that can be controlled through SPI register settings and the general-purpose input/output (GPIO) pins. The DDC block supports two basic operating modes: receiver (RX) mode with single- or dual-band DDC and wide-bandwidth observation receiver mode.

Figure 46 shows that each ADC channel is followed by two DDC chains consisting of the digital filter along with a complex digital mixer with a 16-bit numerically-controlled oscillator (NCO). The NCOs allow accurate frequency tuning within the Nyquist zone prior to the digital filtering. One DDC chain is intended for supporting a dual-band DDC configuration in receiver mode and the second DDC chain supports the wide-bandwidth output option for the observation configuration. At any given time, either the single-band DDC, the dual-band DDC, or the wideband DDC can be enabled. Furthermore, three different NCO frequencies can be selected on that path and are quickly switched using the SPI or the GPIO pins to enable wide-bandwidth observation in a multi-band application.



NOTE: Red traces show SYSREF going to the NCO blocks.

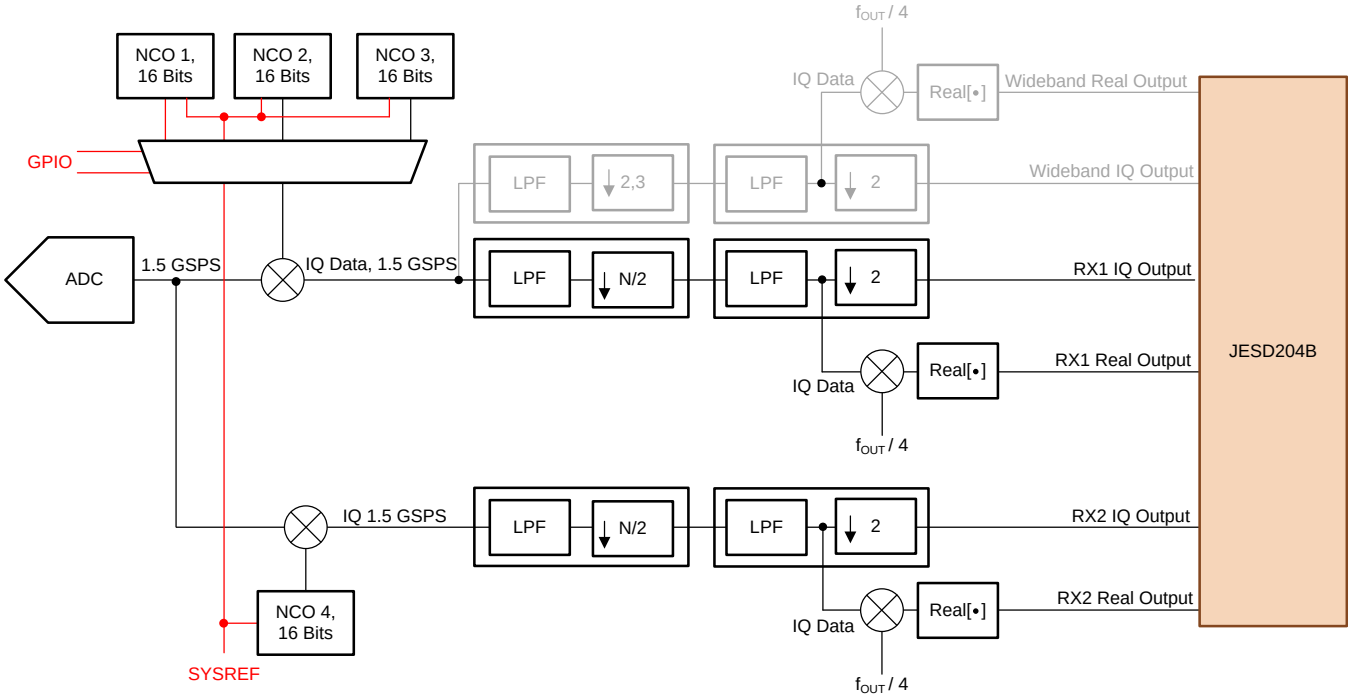
Figure 46. DDC Chains Overview (One ADC Channel Shown)

Additionally, the decimation filter block provides the option to convert the complex output back to real format at twice the decimated, complex output rate. The filter response with a real output is identical to a complex output. The band is centered in the middle of the Nyquist zone (mixed with f_{OUT} / 4) based on a final output data rate of f_{OUT}.

Copyright © 2017, Texas Instruments Incorporated

9.3.4.1 Operating Mode: Receiver

In receiver mode (and as shown in Figure 47), the DDC block can be configured to single- or dual-band operation. Both DDC chains use the same decimation filter setting and the available options are discussed in the *Decimation Filters* section. The decimation filter setting also directly affects the interface rate and number of lanes of the JESD204B interface.



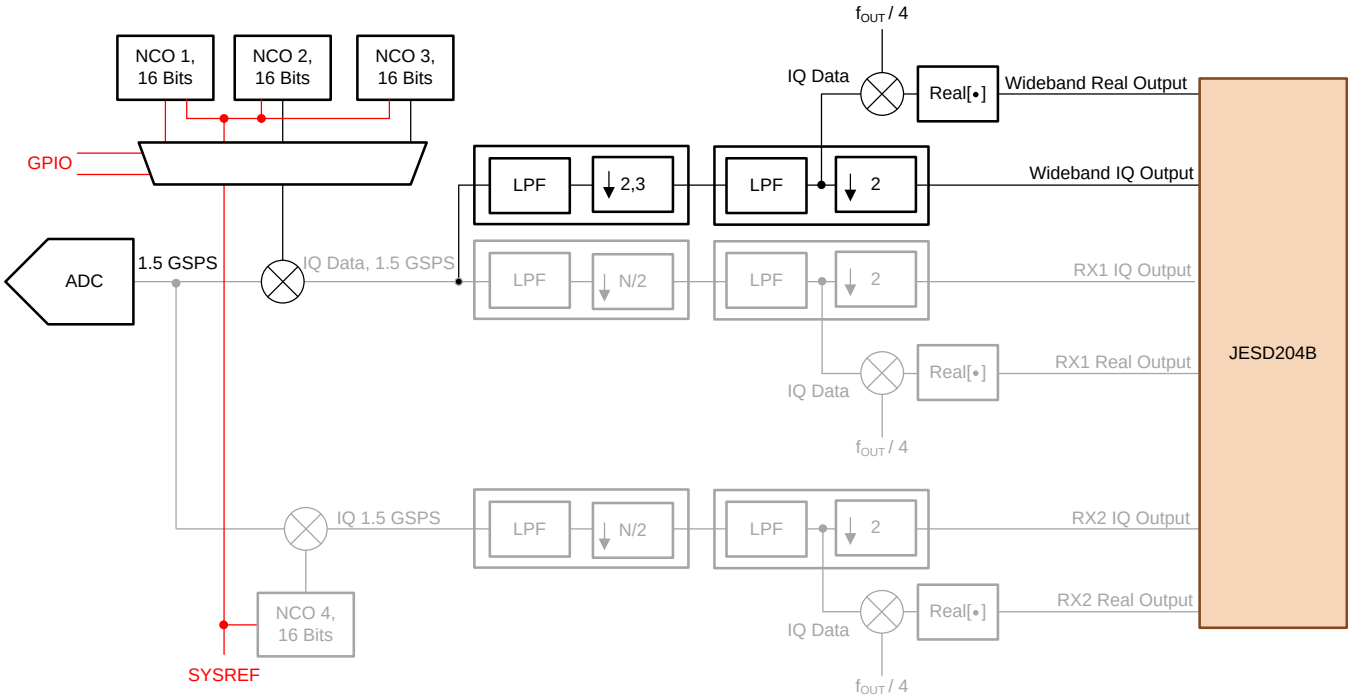
NOTE: Red traces show SYSREF going to the NCO blocks.

Figure 47. Decimation Filter Option for Single- or Dual-Band Operation

Copyright © 2017, Texas Instruments Incorporated

9.3.4.2 Operating Mode: Wide-Bandwidth Observation Receiver

This mode is intended for using a DDC with a wide bandwidth output, but for multiple bands. Figure 48 shows that this mode uses a single DDC chain where up to three NCOs can be used to perform wide-bandwidth observation in a multi-band environment. The three NCOs can be switched dynamically using either the GPIO pins or an SPI command. All three NCOs operate continuously to ensure phase continuity; however, when the NCO is switched, the output data are invalid until the decimation filters are completely flushed with data from the new band.



NOTE: Red traces show SYSREF going to the NCO blocks.

Figure 48. Decimation Filter Implementation for Single-Band and Wide-Bandwidth Mode

9.3.4.3 Decimation Filters

The stop-band rejection of the decimation filters is approximately 90 dB with a pass-band bandwidth of approximately 80%. Table 3 gives an overview of the pass-band bandwidth depending on decimation filter setting and ADC sampling rate.

Table 3. Decimation Filter Summary and Maximum Available Output Bandwidth

DECIMATION SETTING	NO. OF DDCS AVAILABLE PER CHANNEL	NOMINAL PASSBAND GAIN	BANDWIDTH		ADC SAMPLE RATE = N MSPS		ADC SAMPLE RATE = 2.6 GSPS	
			3 dB (%)	1 dB (%)	OUTPUT RATE (MSPS) PER BAND	OUTPUT BANDWIDTH (MHz) PER BAND	COMPLEX OUTPUT RATE (MSPS) PER BAND	OUTPUT BANDWIDTH (MHz) PER BAND
Divide-by-4 complex	1	–0.4 dB	90.9	86.8	N / 4 complex	0.4 × N / 2	650	520
Divide-by-6 complex	1	–0.65 dB	90.6	86.1	N / 6 complex	0.4 × N / 3	433.3	346.64
Divide-by-8 complex	2	–0.27 dB	91.0	86.8	N / 8 complex	0.4 × N / 4	325	260
Divide-by-9 complex	2	–0.45 dB	90.7	86.3	N / 9 complex	0.4 × N / 4.5	288.9	231.12
Divide-by-10 complex	2	–0.58 dB	90.7	86.3	N / 10 complex	0.4 × N / 5	260	208
Divide-by-12 complex	2	–0.55 dB	90.7	86.4	N / 12 complex	0.4 × N / 6	216.7	173.36
Divide-by-16 complex	2	–0.42 dB	90.8	86.4	N / 16 complex	0.4 × N / 8	162.5	130

Figure 49 shows a dual-band example with a divide-by-8 complex.

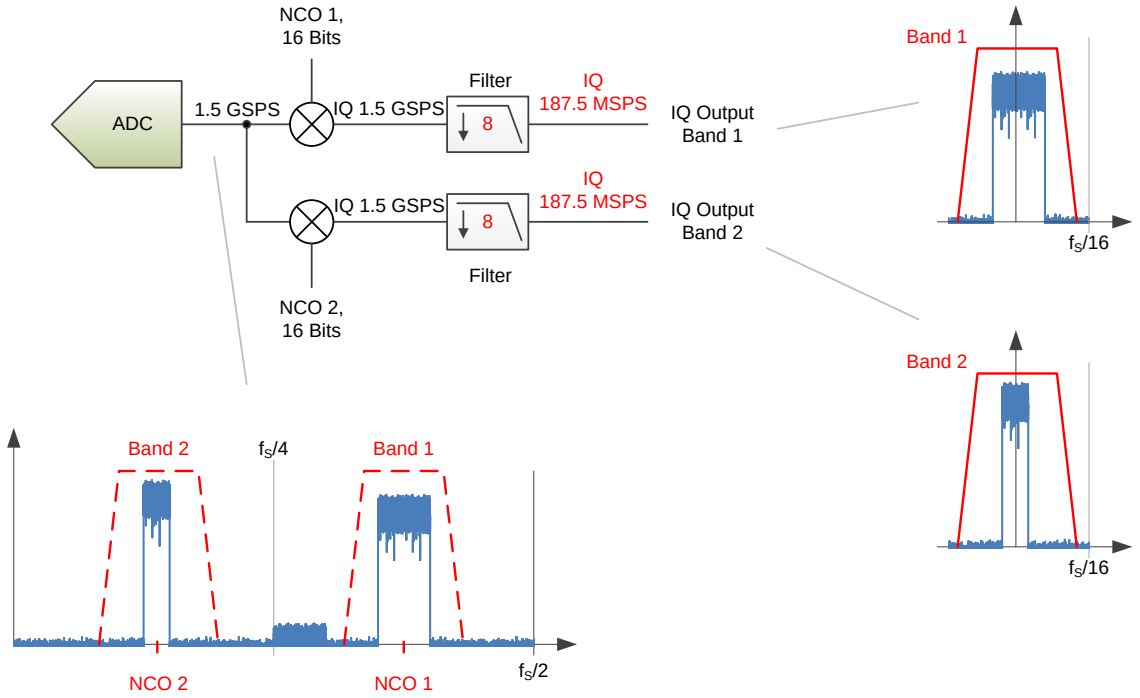


Figure 49. Dual-Band Example

The decimation filter responses normalized to the ADC sampling clock are illustrated in Figure 49 to Figure 64.

Copyright © 2017, Texas Instruments Incorporated

As shown in Figure 50, each figure contains the filter pass-band, transition bands, and alias bands. The x-axis in Figure 50 shows the offset frequency (after the NCO frequency shift) normalized to the ADC sampling clock frequency.

For example, in the divide-by-4 complex, the output data rate is an f_S / 4 complex with a Nyquist zone of f_S / 8 or 0.125 × f_S. The transition band is centered around 0.125 × f_S and the alias transition band is centered at 0.375 × f_S. The alias bands that alias on top of the wanted signal band are centered at 0.25 × f_S and 0.5 × f_S (and are colored in red).

The decimation filters of the ADC32RF42 provide greater than 90-dB attenuation for the alias bands.

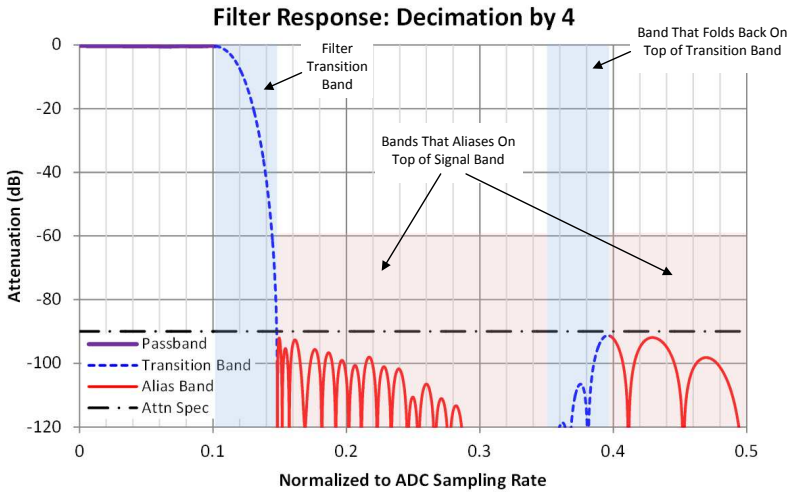


Figure 50. Interpretation of the Decimation Filter Plots

Copyright © 2017, Texas Instruments Incorporated

9.3.4.3.1 Divide-by-4

Peak-to-peak pass-band ripple: approximately 0.22 dB

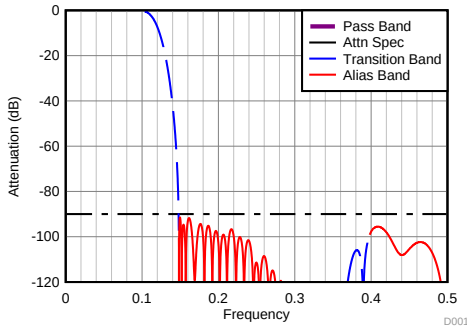


Figure 51. Filter Response Decimate-by-4

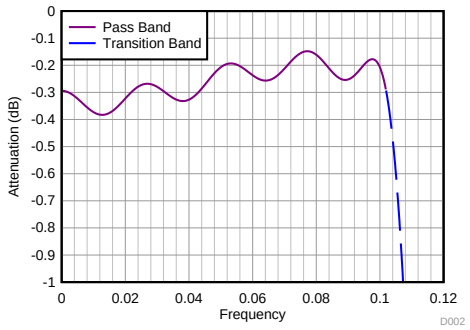


Figure 52. Filter Response Decimate-by-4 (Zoomed)

9.3.4.3.2 Divide-by-6

Peak-to-peak pass-band ripple: approximately 0.38 dB

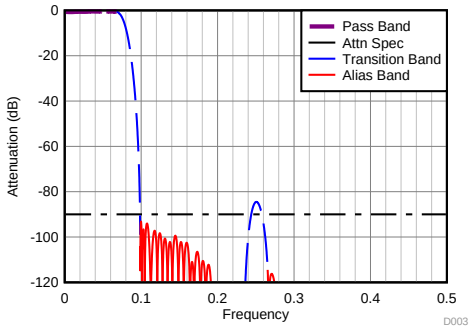


Figure 53. Filter Response Decimate-by-6

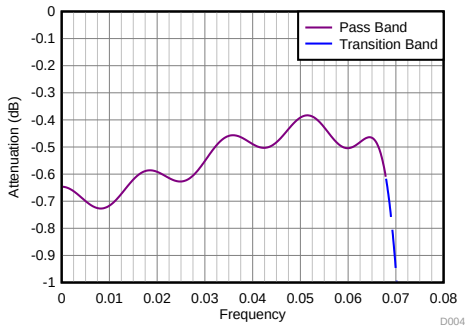


Figure 54. Filter Response Decimate-by-6 (Zoomed)

9.3.4.3.3 Divide-by-8

Peak-to-peak pass-band ripple: approximately 0.25 dB

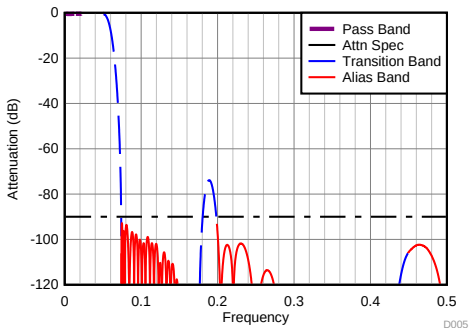


Figure 55. Filter Response Decimate-by-8

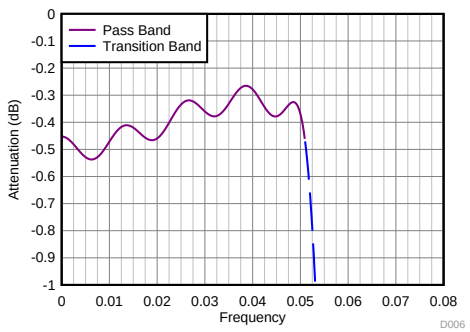


Figure 56. Filter Response Decimate-by-8 (Zoomed)

Copyright © 2017, Texas Instruments Incorporated

9.3.4.3.4 Divide-by-9

Peak-to-peak pass-band ripple: approximately 0.39 dB

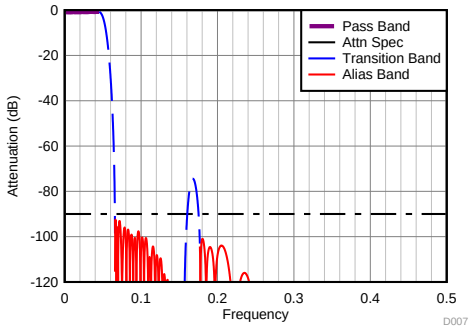


Figure 57. Filter Response Decimate-by-9

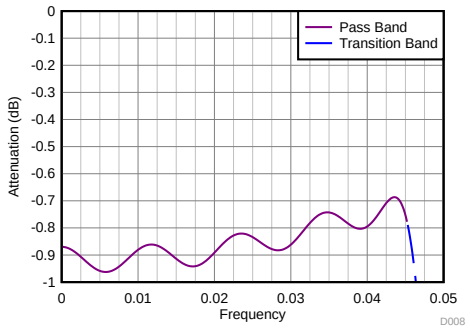


Figure 58. Filter Response Decimate-by-9 (Zoomed)

9.3.4.3.5 Divide-by-10

Peak-to-peak pass-band ripple: approximately 0.39 dB

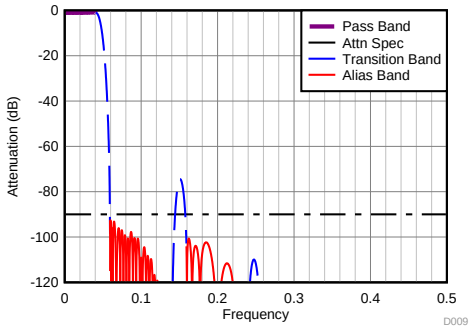


Figure 59. Filter Response Decimate-by-10

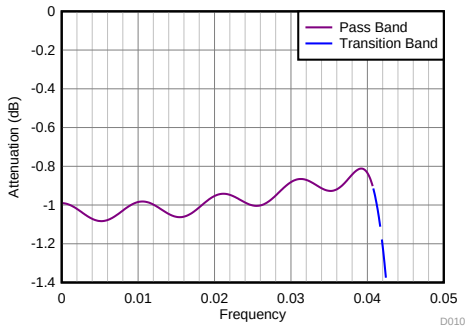


Figure 60. Filter Response Decimate-by-10 (Zoomed)

9.3.4.3.6 Divide-by-12

Peak-to-peak pass-band ripple: approximately 0.36 dB

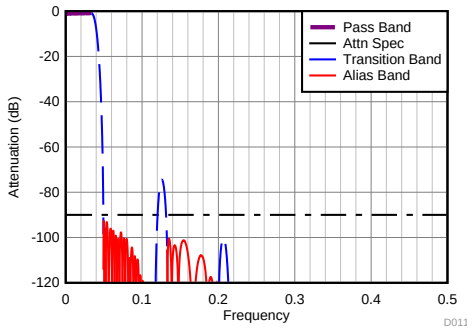


Figure 61. Filter Response Decimate-by-12

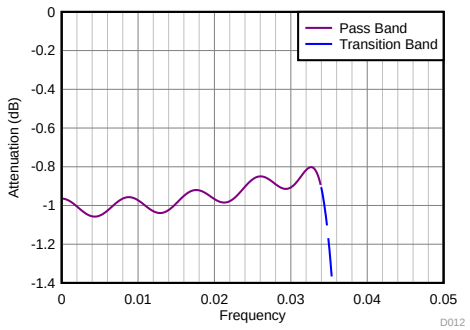


Figure 62. Filter Response Decimate-by-12 (Zoomed)

Copyright © 2017, Texas Instruments Incorporated

9.3.4.3.7 Divide-by-16

Peak-to-peak pass-band ripple: approximately 0.29 dB

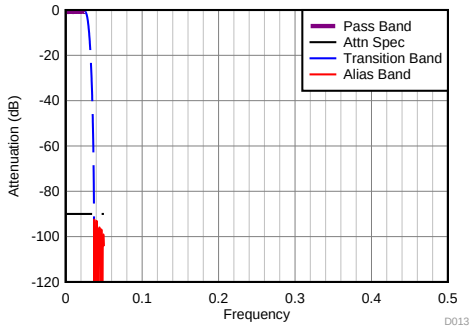


Figure 63. Filter Response Decimate-by-16

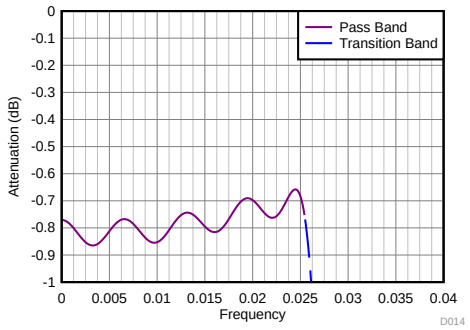


Figure 64. Filter Response Decimate-by-16 (Zoomed)

9.3.4.4 Digital Multiplexer (MUX)

The ADC32RF42 supports a mode where the output data of the ADC channel A can be routed internally to the digital blocks of both channel A and channel B. Figure 65 shows how ADC channel B can be powered down. In this manner, the ADC32RF42 can be configured as a single-channel ADC with up to four independent DDC chains or two wideband DDC chains. All decimation filters and JESD204B format configurations are identical to the two ADC channel operation.

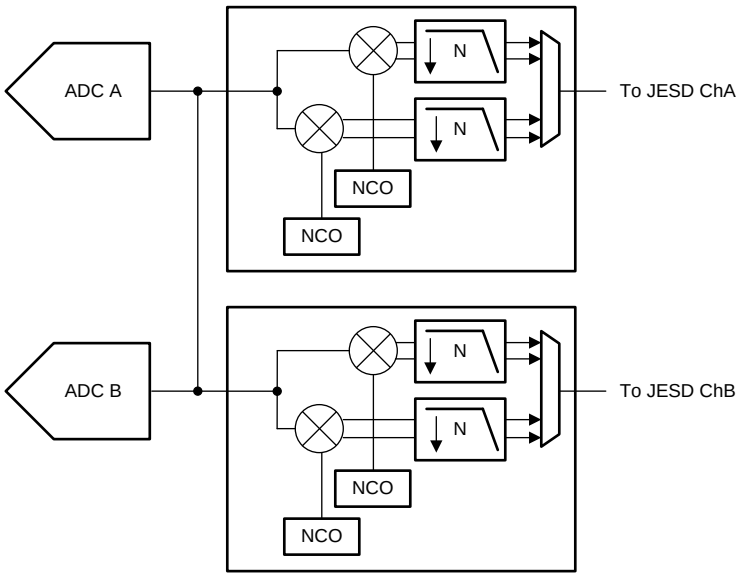


Figure 65. Digital Multiplexer Option

9.3.4.5 Numerically-Controlled Oscillators (NCOs) and Mixers

The ADC32RF42 is equipped with three independent, complex NCOs per ADC channel. Equation 2 describes how the oscillator generates a complex exponential sequence.

$$x[n] = e^{-j\omega n} \quad (2)$$

where

- frequency (ω) is specified as a signed number by the 16-bit register setting

The complex exponential sequence is multiplied by the real input from the ADC to mix the desired carrier down to 0 Hz.

Copyright © 2017, Texas Instruments Incorporated

Each ADC channel has two DDCs. The first DDC has three NCOs and the second DDC has one NCO. The first DDC can dynamically select one of the three NCOs based on the GPIO pin or SPI selection. In wide-bandwidth mode (lower decimation factors 4 and 6), there can only be one DDC for each ADC channel. The NCO frequencies can be programmed independently through the DDCx, NCO[4:1], and the MSB and LSB register settings.

Equation 3 provides the 16-bit register value that sets the NCO frequency setting:

$$f_{NCO} = \frac{DDCxNCOy \times f_S}{2^{16}} \quad (3)$$

where

- x = 0, 1
- y = 1 to 4

For example:

If f_S = 1.5 GSPS, then the NCO register setting = 38230 (decimal).

Thus, Equation 4 defines f_{NCO}:

$$f_{NCO} = 38230 \times \frac{1.5\ GSPS}{2^{16}} = 875.0153\ MHz \quad (4)$$

Any register setting changes that occur after the JESD204B interface is operational results in a non-deterministic NCO phase. If a deterministic phase is required, the JESD204B interface must be reinitialized after changing the register setting.

In bypass mode (when decimation filters are not used), the NCOs are powered down in order to avoid creating unwanted spurs.

9.3.5 NCO Switching

The first DDC (DDC0) on each ADC channel provides three different NCOs that can be used for phase-coherent frequency hopping. This feature is available in both single-band and dual-band mode, but only affects DDC0.

The NCOs can be switched through an SPI control or by using the GPIO pins with the register configurations shown in Table 4 for channel A (50xxh) and channel B (58xxh). The assignment of which GPIO pin to use for INSEL0 and INSEL1 is done based on Table 5, using registers 5438h and 5C38h. The NCO selection is done based on the logic selection on the GPIO pins; see Table 6 and Figure 66.

Table 4. NCO Register Configurations

REGISTER	ADDRESS	DESCRIPTION
NCO CONTROL THROUGH GPIO PINS		
NCO SEL pin	500Fh, 580Fh	Selects the NCO control through the SPI (default) or a GPIO pin.
INSEL0, INSEL1	5438h, 5C38h	Selects which two GPIO pins are used to control the NCO.
NCO CONTROL THROUGH SPI CONTROL		
NCO SEL pin	500Fh, 580Fh	Selects the NCO control through the SPI (default) or a GPIO pin.
NCO SEL	5010h, 5810h	Selects which NCO to use for DDC0.

Table 5. GPIO Pin Assignment

INSELx[1:0] (Where x = 0 or 1)	GPIO PIN SELECTED
00	GPIO4
01	GPIO1
10	GPIO3
11	GPIO2

Copyright © 2017, Texas Instruments Incorporated

Table 6. NCO Selection

NCO SEL[1]	NCO SEL[0]	NCO SELECTED
0	0	NCO1
0	1	NCO2
1	0	NCO3
1	1	n/a

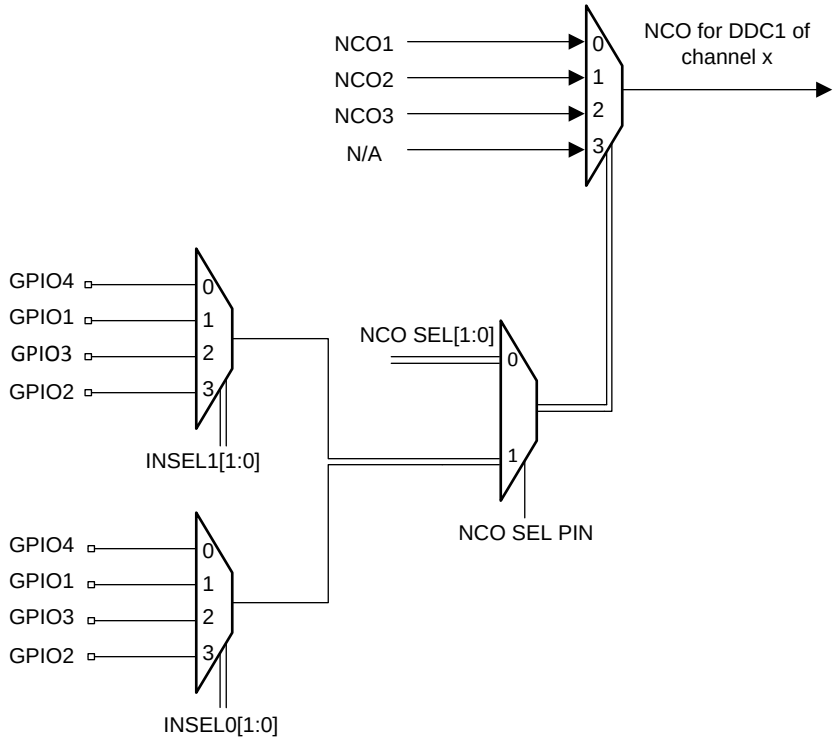


Figure 66. NCO Switching from GPIO and SPI

9.3.6 SerDes Transmitter Interface

Each 12.5-Gbps serializer, deserializer (SerDes) LVDS transmitter output requires ac-coupling between the transmitter and receiver. Terminate the differential pair as shown in Figure 67 with 100-Ω resistance (that is, two 50-Ω resistors) as close to the receiving device as possible to avoid unwanted reflections and signal degradation.

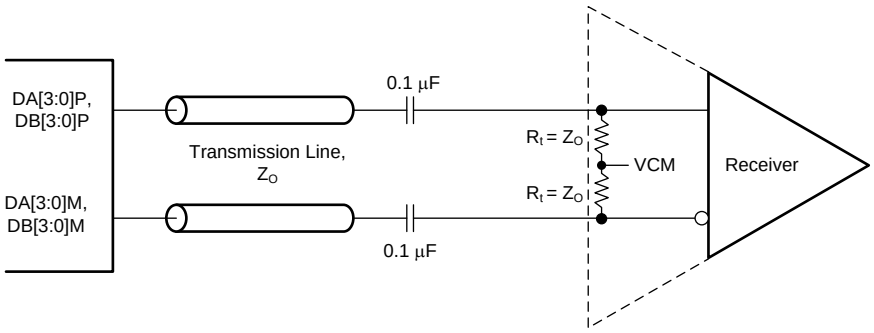


Figure 67. External Serial JESD204B Interface Connection

Copyright © 2017, Texas Instruments Incorporated

9.3.7 Eye Diagrams

Figure 68 and Figure 69 show the serial output eye diagrams of the ADC32RF42 at 5.0 Gbps and 12 Gbps against the JESD204B mask.

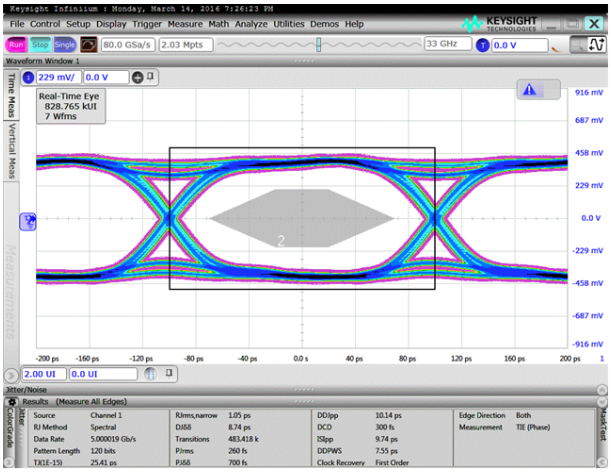


Figure 68. Data Eye at 5 Gbps

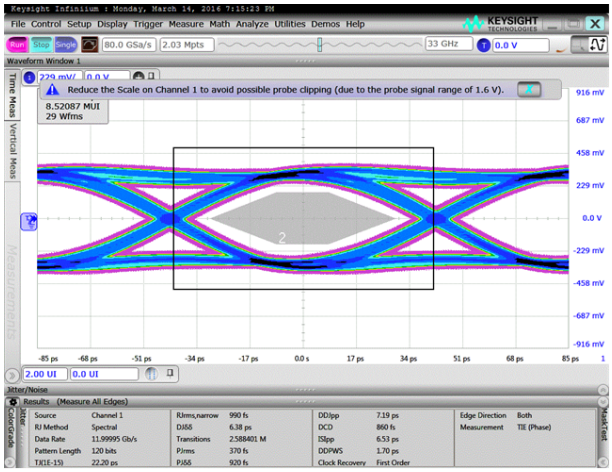


Figure 69. Data Eye at 12 Gbps

9.3.8 Alarm Outputs: Power Detectors for AGC Support

The GPIO pins can be configured as alarm outputs for channels A and B. The ADC32RF42 supports three different power detectors (an absolute peak power detector, crossing detector, and RMS power detector) as well as fast overrange from the ADC. The power detectors operate off the full-rate ADC output prior to the decimation filters.

9.3.8.1 Absolute Peak Power Detector

In this detector mode, the peak is computed over eight samples of the ADC output. Next (as illustrated in Figure 70 and Figure 71), the peak for a block of N samples (N × S`) is computed over a programmable block length and then compared against a threshold to either set or reset the peak detector output. There are two sets of thresholds and each set has two thresholds for hysteresis. The programmable DWELL-time counter is used for clearing the block detector alarm output.

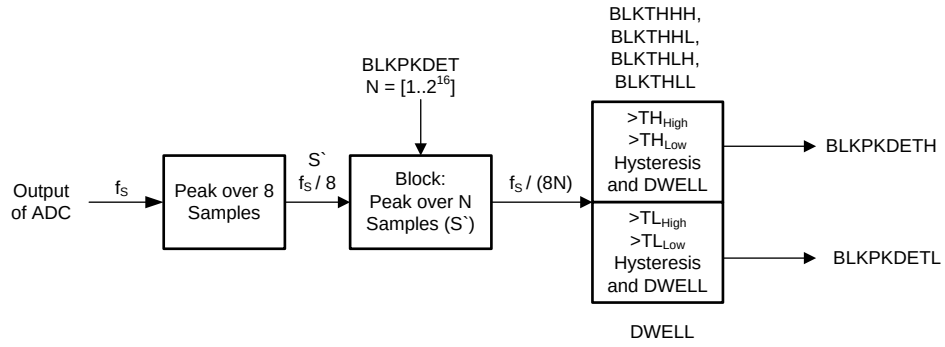


Figure 70. Peak Power Detector Implementation

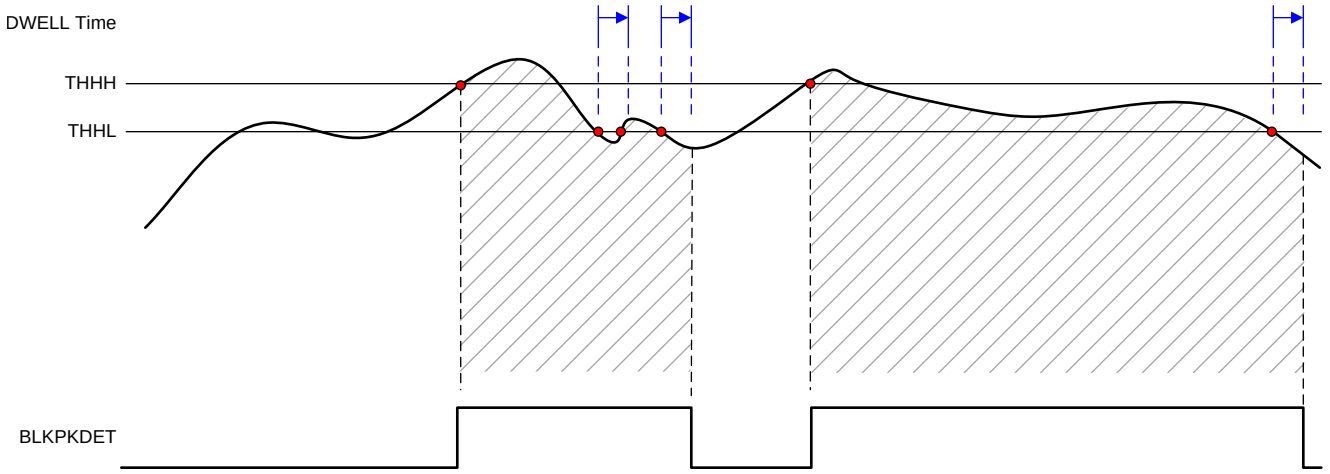


Figure 71. Peak Power Detector Timing Diagram

Table 7 shows the register configurations required to set up the absolute peak power detector. The detector operates in the f_S / 8 clock domain; one peak sample is calculated over eight actual samples.

The automatic gain control (AGC) modes can be configured separately for channel A (54xxh) and channel B (5Cxxh), although some registers are common in 54xxh (such as the GPIO pin selection).

Table 7. Registers Required for the Peak Power Detector

REGISTER	ADDRESS	DESCRIPTION
PKDET EN	5400, 5C00h	Enables peak detector
BLKPKDET	5401h, 5402h, 5403h, 5C01h, 5C02h, 5C03h	Sets the block length N of number of samples (S`). Number of actual ADC samples is 8x this value: N is 17 bits: 1 to 2^{16}.
BLKTHHH, BLKTHHL, BLKTHLH, BLKTHLL	5407h, 5408h, 5409h, 540Ah, 5C07h, 5C08h, 5C09h, 5C0Ah	Sets the different thresholds for the hysteresis function values from 0 to 256 (where 256 is equivalent to the peak amplitude). For example: if BLKTHHH is to –2 dBFS from peak, $10^{(-2 / 20)} \times 256 = 203$, then set 5407h and 5C07h = CBh.
DWELL	540Bh, 540Ch, 5C0Bh, 5C0Ch	When the computed block peak crosses the upper thresholds BLKTHHH or BLKTHLH, the peak detector output flags are set. In order to be reset, the computed block peak must remain continuously lower than the lower threshold (BLKTHHL or BLKTHLL) for the period specified by the DWELL value. This threshold is 16 bits and is specified in terms of f_S / 8 clock cycles.
OUTSEL GPIO[4:1]	5432h, 5433h, 5434h, 5435h	Connects the BLKPKDETH, BLKPKDETL alarms to the GPIO pins; common register.
IODIR	5437h	Selects the direction for the four GPIO pins; common register.
RESET AGC	542Bh, 5C2Bh	After configuration, reset the AGC module to start operation.

Copyright © 2017, Texas Instruments Incorporated

9.3.8.2 Crossing Detector

In this detector mode the peak is computed over eight samples of the ADC output. Next, the peak for a block of N samples (N × S`) is computed over a programmable block length and then the peak is compared against two sets of programmable thresholds (with hysteresis). The crossing detector counts how many f_S / 8 clock cycles that the block detector outputs are set high over a programmable time period and compares the counter value against the programmable thresholds. Figure 72 and Figure 73 show how the alarm outputs are updated at the end of the time period, routed to the GPIO pins, and held in that state through the next cycle. Alternatively, a 2-bit format can be used but (because the ADC32RF42 has four GPIO pins available) this feature uses all four pins for a single channel.

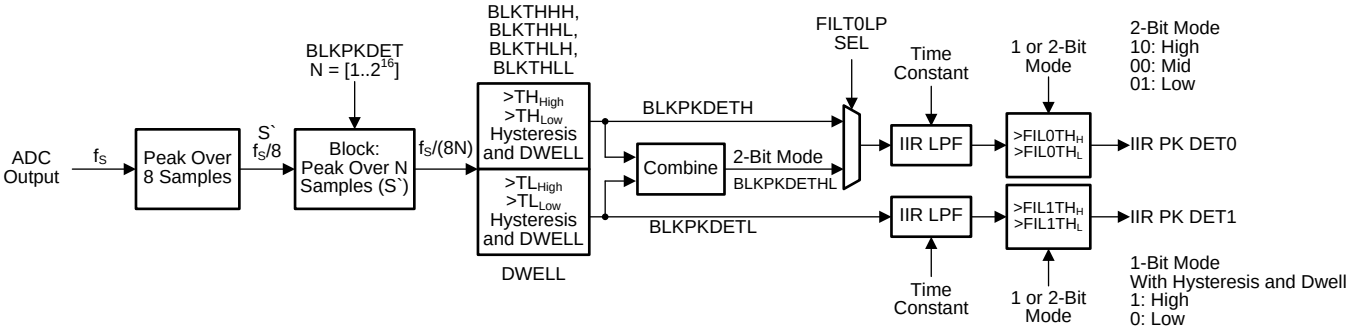


Figure 72. Crossing Detector Implementation

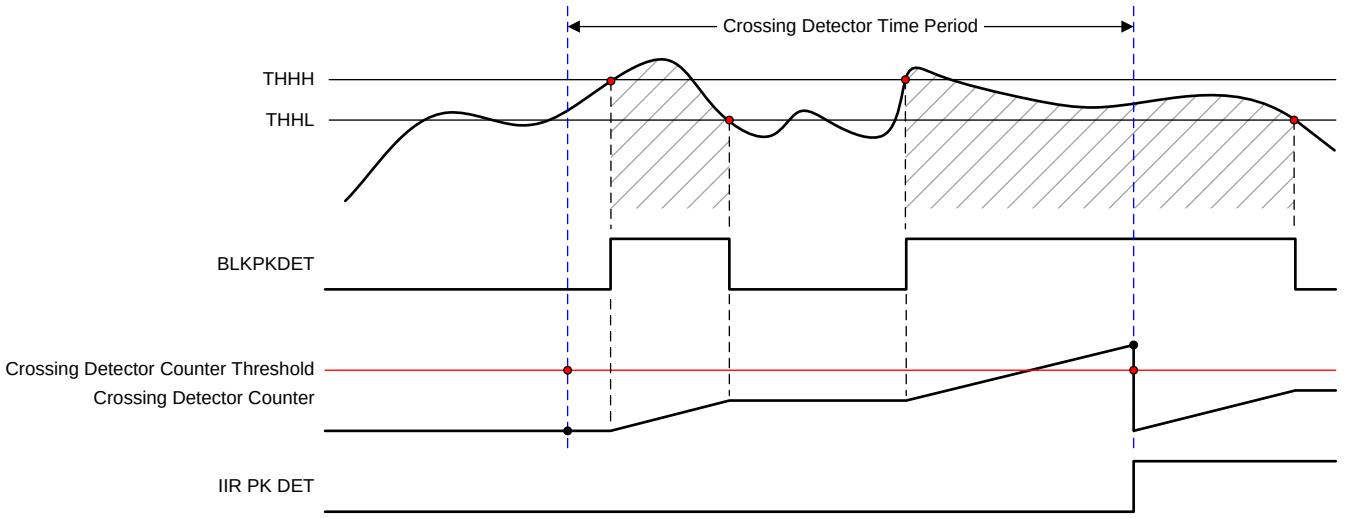


Figure 73. Crossing Detector Timing Diagram

Table 8 shows the register configurations required to set up the crossing detector. The detector operates in the f_S / 8 clock domain. The AGC modes can be configured separately for channel A (54xxh) and channel B (5Cxxh), although some registers are common in 54xxh (such as the GPIO pin selection).

Table 8. Registers Required for the Crossing Detector Operation

REGISTER	ADDRESS	DESCRIPTION
PKDET EN	5400h, 5C00h	Enables peak detector
BLKPKDET	5401h, 5402h, 5403h, 5C01h, 5C02h, 5C03h	Sets the block length N of number of samples (S`). Number of actual ADC samples is 8x this value: N is 17 bits: 1 to 2^{16}.
BLKTHHH, BLKTHHL, BLKTHLH, BLKTHLL	5407h, 5408h, 5409h, 540Ah, 5C07h, 5C08h, 5C09h, 5C0Ah	Sets the different thresholds for the hysteresis function values from 0 to 256 (where 256 is equivalent to the peak amplitude). For example: if BLKTHHH is to –2 dBFS from peak, $10^{(-2 / 20)} \times 256 = 203$, then set 5407h and 5C07h = CBh.
FILT0LPSEL	540Dh, 5C0Dh	Select block detector output or 2-bit output mode as the input to the interrupt identification register (IIR) filter.
TIMECONST	540Eh, 540Fh, 5C0Eh, 5C0Fh	Sets the crossing detector time period for N = 0 to 15 as 2N × f_S / 8 clock cycles. The maximum time period is 32768 × f_S / 8 clock cycles (approximately 174 µs at 2.6 GSPS).
FIL0THH, FIL0THL, FIL1THH, FIL1THL	540Fh-5412h, 5C0Fh-5C12h, 5416h-5419h, 5C16h-5C19h	Comparison thresholds for the crossing detector counter. These thresholds are 16-bit thresholds in 2.14-signed notation. A value of 1 (4000h) corresponds to 100% crossings, a value of 0.125 (0800h) corresponds to 12.5% crossings.
DWELLIIR	541Dh, 541Eh, 5C1Dh, 5C1Eh	DWELL counter for the IIR filter hysteresis.
IIR0 2BIT EN, IIR1 2BIT EN	5413h, 54114h, 5C13h, 5C114h	Enables 2-bit output format for the crossing detector.
OUTSEL GPIO[4:1]	5432h, 5433h, 5434h, 5435h	Connects the IIRPKDET0, IIRPKDET1 alarms to the GPIO pins; common register.
IODIR	5437h	Selects the direction for the four GPIO pins; common register.
RESET AGC	542Bh, 5C2Bh	After configuration, reset the AGC module to start operation.

Copyright © 2017, Texas Instruments Incorporated

9.3.8.3 RMS Power Detector

In this detector mode the peak power is computed for a block of N samples over a programmable block length and then compared against two sets of programmable thresholds (with hysteresis).

The RMS power detector circuit shown in Figure 74 provides configuration options. The RMS power value (1 or 2 bit) can be output onto the GPIO pins. In 2-bit output mode, two different thresholds are used whereas the 1-bit output provides one threshold together with hysteresis.

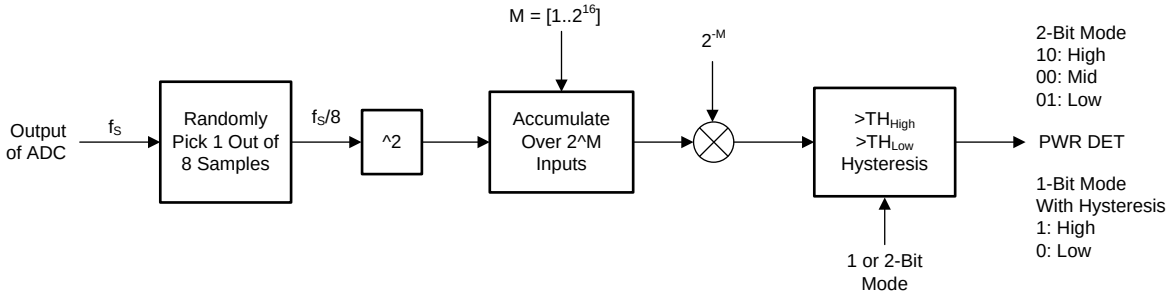


Figure 74. RMS Power Detector Implementation

Table 9 shows the register configurations required to set up the RMS power detector. The detector operates in the f_S / 8 clock domain. The AGC modes can be configured separately for channel A (54xxh) and channel B (5Cxxh), although some registers are common in 54xxh (such as the GPIO pin selection).

Table 9. Registers Required for Using the RMS Power Detector Feature

REGISTER	ADDRESS	DESCRIPTION
RMSDET EN	5420h, 5C20h	Enables RMS detector
PWRDETACCU	5421h, 5C21h	Programs the block length to be used for RMS power computation. The block length is defined in terms of f_S / 8 clocks. The block length can be programmed as 2^M with M = 0 to 16.
PWRDETH, PWRDETL	5422h, 5423h, 5424h, 5425h, 5C22h, 5C23h, 5C24h, 5C25h	The computed average power is compared against these high and low thresholds. One LSB of the thresholds represents 1 / 2^{16}. For example: is PWRDETH is set to –14 dBFS from peak, $[10^{(-14 / 20)}]^2 \times 2^{16}$ = 2609, then set 5422h, 5423h, 5C22h, 5C23h = 0A31h.
RMS2BIT EN	5427h, 5C27h	Enables 2-bit output format for the RMS detector output.
OUTSEL GPIO[4:1]	5432h, 5433h, 5434h, 5435h	Connects the PWRDET alarms to the GPIO pins; common register.
IODIR	5437h	Selects the direction for the four GPIO pins; common register.
RESET AGC	542Bh, 5C2Bh	After configuration, reset the AGC module to start operation.

Copyright © 2017, Texas Instruments Incorporated

9.3.8.4 GPIO AGC MUX

The GPIO pins can be used to control the NCO in wideband DDC mode or as alarm outputs for channel A and B. The GPIO pins can be configured as shown in Figure 75 through the SPI control to output the alarm from the peak power (1 bit), crossing detector (1 or 2 bit), faster overrange, or the RMS power output.

The programmable output MUX allows connecting any signal (including the NCO control) to any of the four GPIO pins. These pins can be configured as outputs (AGC alarm) or inputs (NCO control) through SPI programming.

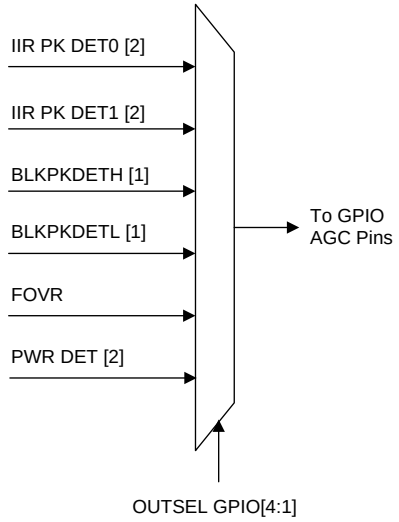


Figure 75. GPIO Output MUX Implementation

9.3.9 Power-Down Mode

The ADC32RF42 provides a lot of configurability for the power-down mode. Power-down can be enabled using the PDN pin or the SPI register writes.

9.3.10 ADC Test Pattern

The ADC32RF42 provides several different options to output test patterns instead of the actual output data of the ADC in order to simplify the serial interface and system debug of the JESD204B digital interface link. Figure 76 shows the output data path.

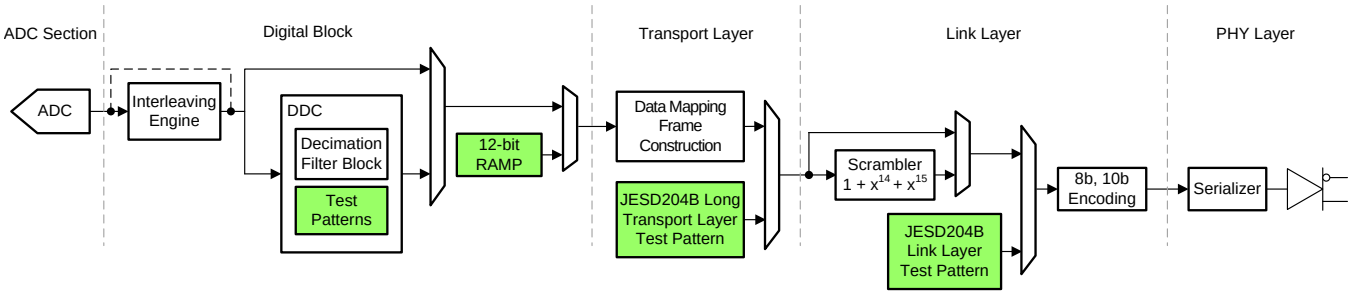


Figure 76. Test Pattern Generator Implementation

9.3.10.1 Digital Block

The ADC test pattern replaces the actual output data of the ADC. The test patterns listed in Table 10 are available when the DDC is enabled and located in register 37h of the decimation filter page. When programmed, the test patterns are output for each converter (M) stream. The number of converter streams per channel increases by 2 when complex (I, Q) output or dual-band DDC is selected. The test patterns can be synchronized for both ADC channels using the SYSREF signal.

Additionally, a 12-bit ramp test pattern is available in DDC bypass mode.

Copyright © 2017, Texas Instruments Incorporated

NOTE

The number of converters increases in dual-band DDC mode and with a complex output.

Table 10. Test Pattern Options (Register 37h)

BIT	NAME	DEFAULT	DESCRIPTION
7-4	TEST PATTERN	0000	Test pattern outputs on channel A and B. 0000 = Normal operation using ADC output data 0001 = Outputs all 0s 0010 = Outputs all 1s 0011 = Outputs toggle pattern: output data are an alternating sequence of 10101010101010 and 01010101010101 0100 = Output digital ramp: output data increment by one LSB every clock cycle from code 0 to 65535 0110 = Single pattern: output data are a custom pattern 1 (75h and 76h) 0111 Double pattern: output data alternate between custom pattern 1 and custom pattern 2 1000 = Deskew pattern: output data are AAAAh 1001 = SYNC pattern: output data are FFFFh

9.3.10.2 Transport Layer

The transport layer maps the ADC output data into 8-bit octets and constructs the JESD204B frames using the LMFS parameters. Tail bits or 0's are added when needed. Alternatively, as described in Table 11, the JESD204B long transport layer test pattern can be substituted instead of the ADC data with the JESD frame.

Table 11. Transport Layer Test Mode EN (Register 01h)

BIT	NAME	DEFAULT	DESCRIPTION
4	TESTMODE EN	0	Generates long transport layer test pattern mode according to section 5.1.6.3 of the JESD204B specification. 0 = Test mode disabled 1 = Test mode disabled

9.3.10.3 Link Layer

The link layer contains the scrambler and the 8b, 10b encoding of any data passed on from the transport layer. Additionally, the link layer also handles the initial lane alignment sequence that can be manually restarted.

The link layer test patterns are intended for testing the quality of the link (jitter testing and so forth). Table 12 lists the test pattern options.

Table 12. Link Layer Test Mode (Register 03h)

BIT	NAME	DEFAULT	DESCRIPTION
7-5	LINK LAYER TESTMODE	000	Generates a pattern according to section 5.3.3.8.2 of the JESD204B document. 000 = Normal ADC data 001 = D21.5 (high-frequency jitter pattern) 010 = K28.5 (mixed-frequency jitter pattern) 011 = Repeat the initial lane alignment (generates a K28.5 character and repeats lane alignment sequences continuously) 100 = 12-octet random pattern (RPAT) jitter pattern

Furthermore, a 2^{15} pseudo-random binary sequence (PRBS) can be enabled by setting up a custom test pattern (AAAAh) in the ADC section and running AAAAh through the 8b, 10b encoder with scrambling enabled.

Copyright © 2017, Texas Instruments Incorporated

9.4 Device Functional Modes

9.4.1 Device Configuration

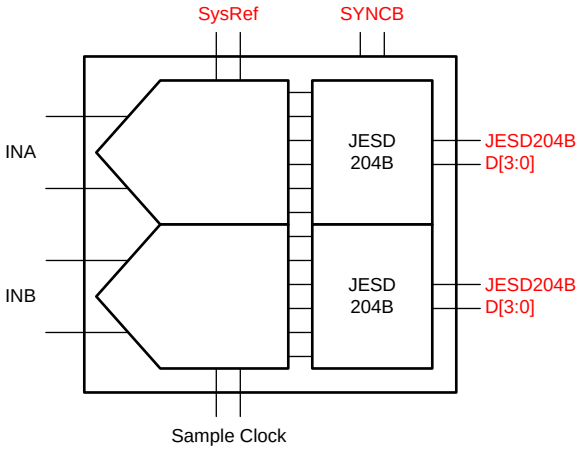
The ADC32RF42 can be configured using a serial programming interface, as described in the *Serial Interface* section. In addition, the device has one dedicated parallel pin (PDN) for controlling the power-down modes.

9.4.2 JESD204B Interface

The ADC32RF42 supports device subclass 1 with a maximum output data rate of 12.5 Gbps for each serial transmitter.

An external SYSREF signal is used to align all internal clock phases and the local multiframe clock to a specific sampling clock edge. This alignment allows synchronization of multiple devices in a system and minimizes timing and alignment uncertainty. Figure 77 shows how the SYNCB input is used to control the JESD204B SerDes blocks.

Depending on the ADC sampling rate, the JESD204B output interface can be operated with one, two, or four lanes per ADC channel. The JESD204B setup and configuration of the frame assembly parameters is controlled through the SPI interface.



Copyright © 2016, Texas Instruments Incorporated

Figure 77. JESD Signal Overview

Copyright © 2017, Texas Instruments Incorporated

Device Functional Modes (continued)

The JESD204B transmitter block shown in Figure 78 consists of the transport layer, the data scrambler, and the link layer. The transport layer maps the ADC output data into the selected JESD204B frame data format and manages if the ADC output data or test patterns are transmitted. The link layer performs the 8b, 10b data encoding as well as the synchronization and initial lane alignment using the SYNC input signal. Optionally, data from the transport layer can be scrambled.

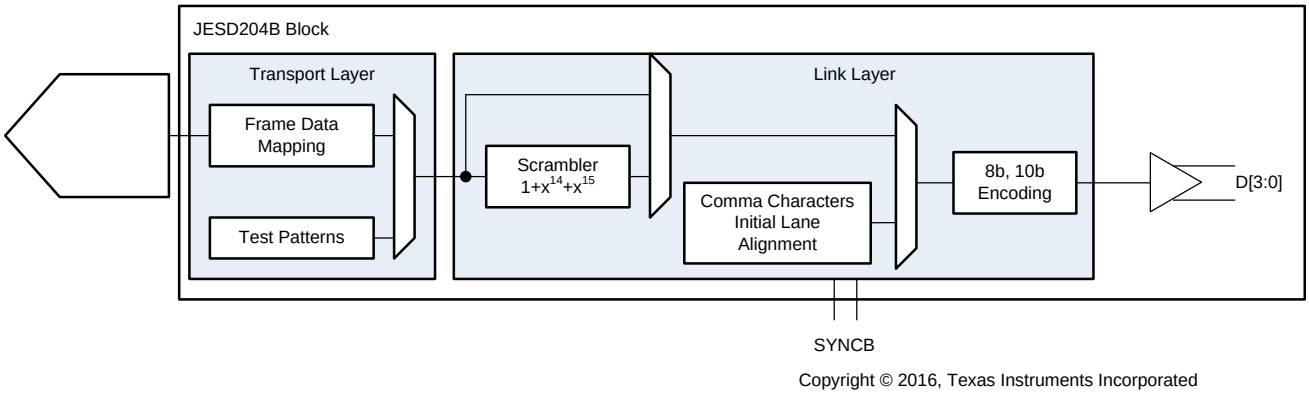


Figure 78. JESD Digital Block Implementation

9.4.2.1 JESD204B Initial Lane Alignment (ILA)

The receiving device starts the initial lane alignment process by deasserting the SYNCB signal. The SYNCB signal can be issued using the SYNCB input pins or by setting the proper SPI bits. When a logic low is detected on the SYNCB input (as shown in Figure 79), the ADC32RF42 starts transmitting comma (K28.5) characters to establish the code group synchronization.

When synchronization completes, the receiving device reasserts the SYNCB signal and the ADC32RF42 starts the initial lane alignment sequence with the next local multiframe clock boundary. The ADC32RF42 transmits four multiframes, each containing K frames (K is SPI programmable). Each of the multiframes contains the frame start and end symbols. The second multiframe also contains the JESD204 link configuration data.

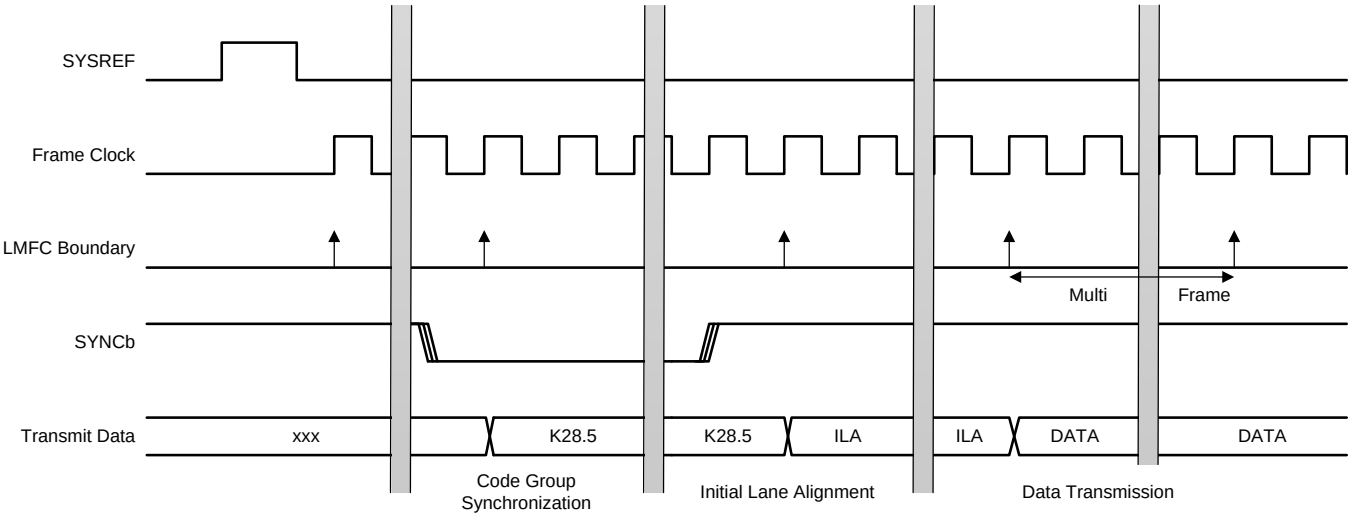


Figure 79. JESD Internal Timing Information

Device Functional Modes (continued)

9.4.2.2 JESD204B Frame Assembly

The JESD204B standard defines the following parameters:

- F is the number of octets per frame clock period
- L is the number of lanes per link
- M is the number of converters for the device
- S is the number of samples per frame

9.4.2.3 JESD204B Frame Assembly in Bypass Mode

Table 13 lists the available JESD204B formats and valid ranges for the ADC32RF42. The ranges are limited by the SerDes line rate and the maximum ADC sample frequency. Table 14 shows the sample alignment for the bypass modes on the different lanes.

Table 13. JESD Mode Options: Bypass Mode

DECIMATION SETTING (Complex)	OUTPUT RESOLUTION (Bits)	L	M	F	S	12-BIT MODE	PLL MODE	JESD MODE 0	JESD MODE 1	JESD MODE 2	MAX f_{CLK} (Gsps)	RATIO [f_{SerDes} / f_{CLK} (Gbps / GSPS)]
Bypass	12(1)	4	2	8	10	3	16x	3	0	0	1.5	8
	14	4	2	2	2	0	20x	1	0	0	1.25	10

(1) In full rate output, the two LSBs are truncated to a 12-bit output.

Table 14. JESD Sample Lane Alignments: Bypass Mode(1)

OUTPUT LANE	LMFS = 4222		LMFS = 42810							
DA0	A_0[13:6]	A_0[5:0], 00	A_0[11:4]	A_0[3:0], A_1[11:8]	A_1[7:0]	A_2[11:4]	A_2[3:0], A_3[11:8]	A_3[7:0]	A_4[11:4]	A_4[3:0], 0000
DA1	A_1[13:6]	A_1[5:0], 00	A_5[11:4]	A_5[3:0], A_6[11:8]	A_6[7:0]	A_7[11:4]	A_7[3:0], A_8[11:8]	A_8[7:0]	A_9[11:4]	A_9[3:0], 0000
DA2	—	—	—	—	—	—	—	—	—	—
DA3	—	—	—	—	—	—	—	—	—	—
DB0	B_0[13:6]	B_0[5:0], 00	B_0[11:4]	B_0[3:0], B_1[11:8]	B_1[7:0]	B_2[11:4]	B_2[3:0], B_3[11:8]	B_3[7:0]	B_4[11:4]	B_4[3:0], 0000
DB1	B_1[13:6]	B_1[5:0], 00	B_5[11:4]	B_5[3:0], B_6[11:8]	B_6[7:0]	B_7[11:4]	B_7[3:0], B_8[11:8]	B_8[7:0]	B_9[11:4]	B_9[3:0], 0000
DB2	—	—	—	—	—	—	—	—	—	—
DB3	—	—	—	—	—	—	—	—	—	—

(1) Blue shading indicates channel A and yellow shading indicates channel B.

Copyright © 2017, Texas Instruments Incorporated

9.4.2.4 JESD204B Frame Assembly with Decimation (Single-Band DDC): Complex Output

Table 15 lists the available JESD204B interface formats and valid ranges for the ADC32RF42 with decimation (single-band DDC) when using a complex output format. The ranges are limited by the SerDes line rate and the maximum ADC sample frequency. Table 16 shows the sample alignment on the different lanes.

Table 15. JESD Mode Options: Single-Band Complex Output

DECIMATION SETTING (Complex)	NUMBER OF ACTIVE DDCS	L	M	F	S	PLL MODE	JESD MODE0	JESD MODE1	JESD MODE2	RATIO [f_{SerDes} / f_{CLK} (Gbps / GSPS)]
Divide-by-4	1 per channel	4	4	2	1	20x	1	0	0	5
		2	4	4	1	40x	2	0	0	2.5
Divide-by-6	1 per channel	4	4	2	1	20x	1	0	0	3.33
		2	4	4	1	40x	2	0	0	6.66
Divide-by-8	1 per channel	4	4	2	1	20x	1	0	0	2.5
		2	4	4	1	40x	2	0	0	5
Divide-by-9	1 per channel	4	4	2	1	20x	1	0	0	2.22
		2	4	4	1	40x	2	0	0	4.44
Divide-by-10	1 per channel	4	4	2	1	20x	1	0	0	2
		2	4	4	1	40x	2	0	0	4
Divide-by-12	1 per channel	2	4	4	1	40x	1	0	0	3.33
Divide-by-16	1 per channel	2	4	4	1	40x	2	0	0	2.5

Table 16. JESD Sample Lane Alignments: Single-Band Complex Output(1)

OUTPUT LANE	LMFS = 4421 20x		LMFS = 4421 40x		LMFS = 4442				LMFS = 2441			
DA0	AI_0 [15:8]	AI_0 [7:0]										
DA1	AQ_0 [15:8]	AQ_0 [7:0]	AI_0 [15:8]	AI_0 [7:0]	AI_0 [15:8]	AI_0 [7:0]	AI_1 [15:8]	AI_1 [7:0]	AI_0 [15:8]	AI_0 [7:0]	AQ_0 [15:8]	AQ_0 [7:0]
DA2			AQ_0 [15:8]	AQ_0 [7:0]	AQ_0 [15:8]	AQ_0 [7:0]	AQ_1 [15:8]	AQ_1 [7:0]				
DA3												
DB0	BI_0 [15:8]	BI_0 [7:0]										
DB1	BQ_0 [15:8]	BQ_0 [7:0]	BI_0 [15:8]	BI_0 [7:0]	BI_0 [15:8]	BI_0 [7:0]	BI_1 [15:8]	BI_1 [7:0]	BI_0 [15:8]	BI_0 [7:0]	BQ_0 [15:8]	BQ_0 [7:0]
DB2			BQ_0 [15:8]	BQ_0 [7:0]	BQ_0 [15:8]	BQ_0 [7:0]	BQ_1 [15:8]	BQ_1 [7:0]				
DB3												

(1) Blue shading indicates channel A and yellow shading indicates channel B.

Copyright © 2017, Texas Instruments Incorporated

9.4.2.5 JESD204B Frame Assembly with Decimation (Single-Band DDC): Real Output

Table 17 lists the available JESD204B formats and valid ranges for the ADC32RF42 with decimation (single-band DDC) when using real output format. The ranges are limited by the SerDes line rate and the maximum ADC sample frequency.

Table 17. JESD Mode Options: Single-Band Real Output (Wide Bandwidth)

DECIMATION SETTING (Complex)	NUMBER OF ACTIVE DDCS	L	M	F	S	PLL MODE	JESD MODE0	JESD MODE1	JESD MODE2	RATIO [f_{SerDes} / f_{CLK} (Gbps / GSPS)]
Divide-by-4 (Divide-by-2 real)	1 per channel	4	2	1	1	20x	1	1	0	5
		4	2	2	2	20x	1	0	0	10
		2	2	2	1	40x	0	0	1	
		2	2	4	2	40x	2	0	0	
Divide-by-6 (Divide-by-3 real)	1 per channel	4	2	1	1	20x	1	1	0	3.33
		4	2	2	2	20x	1	0	0	6.66
		2	2	2	1	40x	0	0	1	
		2	2	4	2	40x	2	0	0	

9.4.2.6 JESD204B Frame Assembly with Decimation (Single-Band DDC): Real Output

Table 18 lists the available JESD204B formats and valid ranges for the ADC32RF42 with decimation (dual-band DDC) when using a complex output format. Table 19 shows the sample alignment on the different lanes.

Table 18. JESD Mode Options: Single-Band Real Output

DECIMATION SETTING (Complex)	NUMBER OF ACTIVE DDCS	L	M	F	S	PLL MODE	JESD MODE0	JESD MODE1	JESD MODE2	RATIO [f_{SerDes} / f_{CLK} (Gbps / GSPS)]
Divide-by-8 (Divide-by-4 real)	1 per channel	4	2	1	1	20x	1	1	0	2.5
		4	2	2	2	20x	1	0	0	
		2	2	2	1	40x	0	0	1	5
		2	2	4	2	40x	2	0	0	
Divide-by-9 (Divide-by-4.5 real)	1 per channel	4	2	1	1	20x	1	1	0	2.22
		4	2	2	2	20x	1	0	0	
		2	2	2	1	40x	0	0	1	4.44
		2	2	4	2	40x	2	0	0	
Divide-by-10 (Divide-by-5 real)	1 per channel	4	2	1	1	20x	1	1	0	2
		4	2	2	2	20x	1	0	0	
		2	2	2	1	40x	0	0	1	4
		2	2	4	2	40x	2	0	0	
Divide-by-12 (Divide-by-6 real)	1 per channel	2	2	2	1	40x	0	0	1	3.33
		2	2	4	2	40x	2	0	0	
Divide-by-16 (Divide-by-8 real)	1 per channel	2	2	2	1	40x	0	0	1	2.5
		2	2	4	2	40x	2	0	0	

Table 19. JESD Sample Lane Assignment: Single-Band Real Output(1)

OUTPUT LANE	LMFS = 4211	LMFS = 4222		LMFS = 2221		LMFS = 2242			
DA0	A_0[15:8]	A_0[15:8]	A_0[7:0]						
DA1	A_0[7:0]	A_1[15:8]	A_1[7:0]	A_0 [15:8]	A_0[7:0]	A_0[15:8]	A_0[7:0]	A_1[15:8]	A_1[7:0]
DB0	B_0[15:8]	B_0[15:8]	B_0[7:0]						
DB1	B_0[7:0]	B_1[15:8]	B_1[7:0]	B_0[15:8]	B_0[7:0]	B_0[15:8]	B_0[7:0]	B_1[15:8]	B_1[7:0]

(1) Blue shading indicates channel A and yellow shading indicates channel B.

Copyright © 2017, Texas Instruments Incorporated

9.4.2.7 JESD204B Frame Assembly with Decimation (Dual-Band DDC): Complex Output

Table 20 lists the available JESD204B formats and valid ranges for the ADC32RF42 with decimation (dual-band DDC) when using a complex output format. The ranges are limited by the SerDes line rate and the maximum ADC sample frequency. Table 21 shows the sample alignment on the different lanes.

Table 20. JESD Mode Options: Dual-Band Complex Output

DECIMATION SETTING (Complex)	NUMBER OF ACTIVE DDCS	L	M	F	S	PLL MODE	JESD MODE0	JESD MODE1	JESD MODE2	RATIO [f_{SerDes} / f_{CLK} (Gbps / GSPS)]
Divide-by-8	2 per channel	8	8	2	1	20x	1	0	0	2.5
		4	8	4	1	40x	2	0	0	5
Divide-by-9	2 per channel	8	8	2	1	20x	1	0	0	2.22
		4	8	4	1	40x	2	0	0	4.44
Divide-by-10	2 per channel	8	8	2	1	20x	1	0	0	2
		4	8	4	1	40x	2	0	0	4
Divide-by-12	2 per channel	4	8	4	1	40x	2	0	0	3.33
Divide-by-16	2 per channel	4	8	4	1	40x	2	0	0	2.5

Table 21. JESD Sample Lane Assignment: Dual-Band Complex Output(1)

OUTPUT LANE	LMFS = 8821		LMFS = 4841			
DA0	$A1_0$[15:8]	$A1_0$[7:0]				
DA1	$A1Q_0$[15:8]	$A1Q_0$[7:0]	$A1I_0$[15:8]	$A1I_0$[7:0]	$A1Q_0$[15:8]	$A1Q_0$[7:0]
DA2	$A2I_0$[15:8]	$A2I_0$[7:0]	$A2I_0$[15:8]	$A2I_0$[7:0]	$A2Q_0$[15:8]	$A2Q_0$[7:0]
DA3	$A2Q_0$[15:8]	$A2Q_0$[7:0]				
DB0	$B1I_0$[15:8]	$B1I_0$[7:0]				
DB1	$B1Q_0$[15:8]	$B1Q_0$[7:0]	$B1I_0$[15:8]	$B1I_0$[7:0]	$B1Q_0$[15:8]	$B1Q_0$[7:0]
DB2	$B2I_0$[15:8]	$B2I_0$[7:0]	$B2I_0$[15:8]	$B2I_0$[7:0]	$B2Q_0$[15:8]	$B2Q_0$[7:0]
DB3	$B2Q_0$[15:8]	$B2Q_0$[7:0]				

(1) Blue and green shading indicates the two bands for channel A; yellow and orange shading indicates the two bands for channel B.

Copyright © 2017, Texas Instruments Incorporated

9.4.2.8 JESD204B Frame Assembly with Decimation (Dual-Band DDC): Real Output

Table 22 lists the available JESD204B formats and valid ranges for the ADC32RF42 with decimation (dual-band DDC) when using real output format. The ranges are limited by the SerDes line rate and the maximum ADC sample frequency. Table 23 shows the sample alignment on the different lanes.

Table 22. JESD Mode Options: Dual-Band Real Output

DECIMATION SETTING (Complex)	NUMBER OF ACTIVE DDCS	L	M	F	S	PLL MODE	JESD MODE0	JESD MODE1	JESD MODE2	RATIO [f_{SerDes} / f_{CLK} (Gbps / GSPS)]
Divide-by-8 (Divide-by-4 real)	2 per channel	8	4	1	1	20x	1	1	0	2.5
		8	4	2	2	20x	1	0	0	
		4	4	2	1	40x	0	0	1	5
		4	4	4	2	40x	2	0	0	
Divide-by-9 (Divide-by-4.5 real)	2 per channel	8	4	1	1	20x	1	1	0	2.22
		8	4	2	2	20x	1	0	0	
		4	4	2	1	40x	0	0	1	4.44
		4	4	4	2	40x	2	0	0	
Divide-by-10 (Divide-by-5 real)	2 per channel	8	4	1	1	20x	1	1	0	2
		8	4	2	2	20x	1	0	0	
		4	4	2	1	40x	0	0	1	4
		4	4	4	2	40x	2	0	0	
Divide-by-12 (Divide-by-6 real)	2 per channel	4	4	2	1	40x	0	0	1	3.33
		4	4	4	2	40x	2	0	0	
Divide-by-16 (Divide-by-8 real)	2 per channel	4	4	2	1	40x	0	0	1	2.5
		4	4	4	2	40x	2	0	0	

Table 23. JESD Sample Lane Assignment: Dual-Band Complex Output(1)

OUTPUT LANE	LMFS = 8411	LMFS = 8422		LMFS = 4421		LMFS = 4442			
DA0	$A1_0$[15:8]	$A1_0$[15:8]	$A1_0$[7:0]						
DA1	$A1_0$[7:0]	$A1_1$[15:8]	$A1_1$[7:0]	$A1_0$[15:8]	$A1_0$[7:0]	$A1_0$[15:8]	$A1_0$[7:0]	$A1_1$[15:8]	$A1_1$[7:0]
DA2	$A2_0$[15:8]	$A2_0$[15:8]	$A2_0$[7:0]	$A2_0$[15:8]	$A2_0$[7:0]	$A2_0$[15:8]	$A2_0$[7:0]	$A2_1$[15:8]	$A2_1$[7:0]
DA3	$A2_0$[7:0]	$A2_1$[15:8]	$A2_1$[7:0]						
DB0	$B1_0$[15:8]	$B1_0$[15:8]	$B1_0$[7:0]						
DB1	$B1_0$[7:0]	$B1_1$[15:8]	$B1_1$[7:0]	$B1_0$[15:8]	$B1_0$[7:0]	$B1_0$[15:8]	$B1_0$[7:0]	$B1_1$[15:8]	$B1_1$[7:0]
DB2	$B2_0$[15:8]	$B2_0$[15:8]	$B2_0$[7:0]	$B2_0$[15:8]	$B2_0$[7:0]	$B2_0$[15:8]	$B2_0$[7:0]	$B2_1$[15:8]	$B2_1$[7:0]
DB3	$B2_0$[7:0]	$B2_1$[15:8]	$B2_1$[7:0]						

(1) Blue and green shading indicates the two bands for channel A; yellow and orange shading indicates the two bands for channel B.

Copyright © 2017, Texas Instruments Incorporated

9.4.3 Serial Interface

The ADC has a set of internal registers that can be accessed by the serial interface formed by the SEN (serial interface enable), SCLK (serial interface clock), and SDIN (serial interface data) pins. Serially shifting bits into the device is enabled when SEN is low. Figure 80 shows that SDIN serial data are latched at every SCLK rising edge when SEN is active (low). Table 24 shows that the interface can function with SCLK frequencies from 20 MHz down to low speeds (of a few hertz) and also with a non-50% SCLK duty cycle.

The SPI access described in Table 25 uses 24 bits consisting of eight register data bits, 12 register address bits, and four special bits to distinguish between read/write, page and register, and individual channel access.

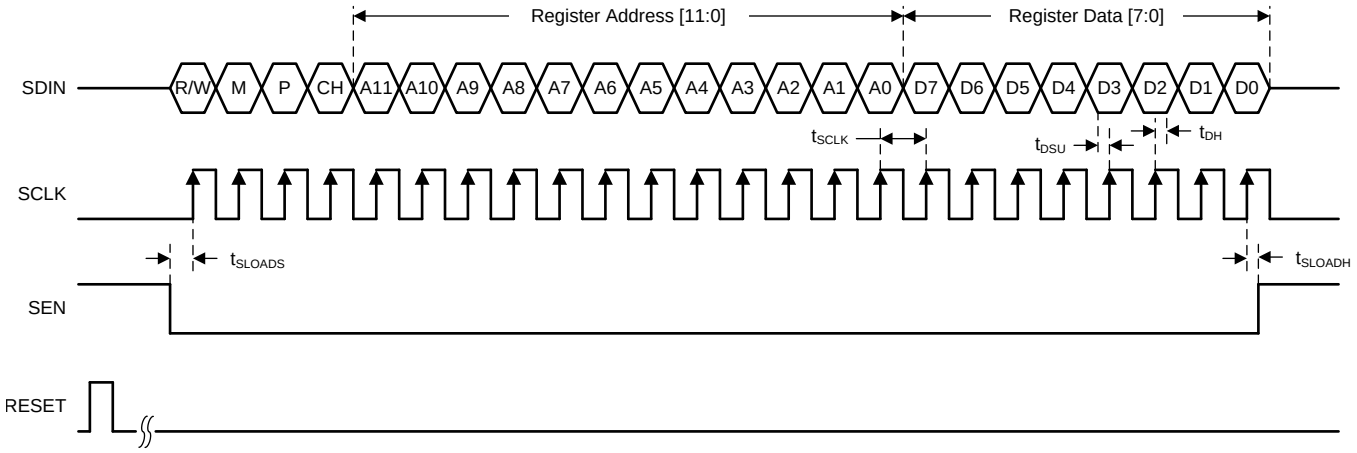


Figure 80. SPI Timing Diagram

Table 24. SPI Timing Information

		MIN	TYP	MAX	UNIT
f_{SCLK}	SCLK frequency (equal to 1 / t_{SCLK})	1		20	MHz
t_{SLOADS}	SEN to SCLK setup time	50			ns
t_{SLOADH}	SCLK to SEN hold time	50			ns
t_{DSU}	SDIN setup time	10			ns
t_{DH}	SDIN hold time	10			ns
t_{SDOUT}	Delay between SCLK falling edge to SDOUT		10		ns

Copyright © 2017, Texas Instruments Incorporated

Table 25. SPI Input Description

SPI BIT	DESCRIPTION	OPTIONS
R/W bit	Read/write bit	0 = SPI write 1 = SPI read back
M bit	SPI bank access	0 = Analog SPI bank (master) 1 = All digital SPI banks (main digital, interleaving, decimation filter, JESD digital, and so forth)
P bit	Digital page selection bit	0 = Page access 1 = Register access
CH bit	SPI access for a specific channel of the JESD digital page	0 = Channel B 1 = Channel A
ADDR[11:0]	SPI address bits	—
DATA[7:0]	SPI data bits	—

Figure 81 shows the SDOUT timing when data are read back from a register. Data are placed on the SDOUT bus at the SCLK falling edge so that the data can be latched at the SCLK rising edge by the external receiver.

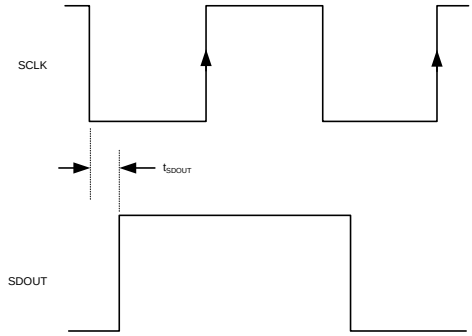


Figure 81. SDOUT Timing

Copyright © 2017, Texas Instruments Incorporated

9.4.3.1 Serial Register Write: Analog Bank

The internal register of the ADC32RF42 analog bank (Figure 82) can be programmed by:

1. Driving the SEN pin low.
2. Initiating a serial interface cycle selecting the page address of the register whose content must be written. To select the master page: write address 0012h with 04h. To select the ADC page: write address 0011h with FFh.
3. Writing the register content. When a page is selected, multiple registers located in the same page can be programmed.

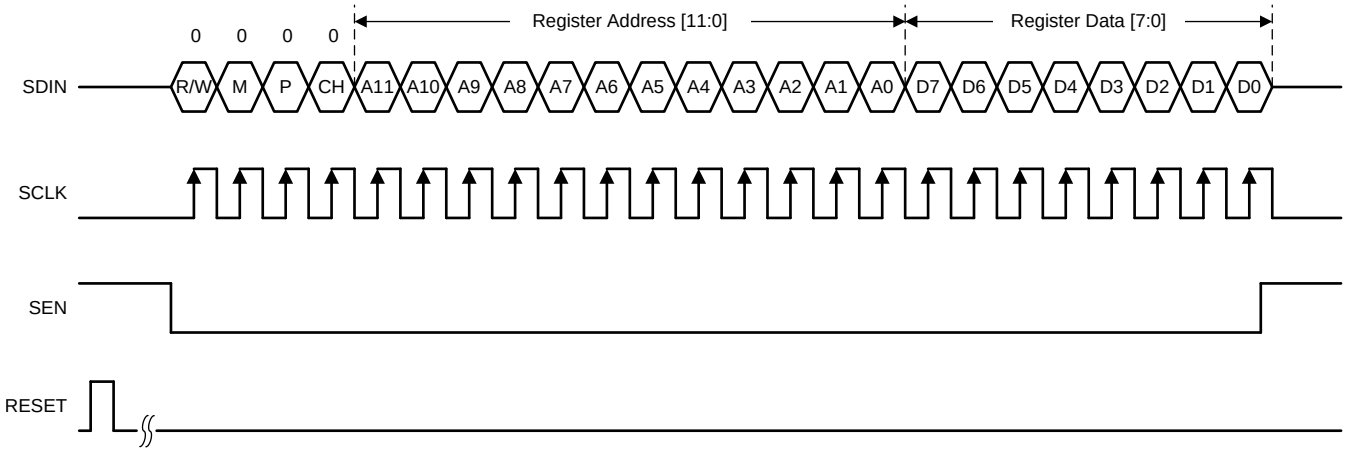


Figure 82. SPI Write Timing Diagram for the Analog Bank

9.4.3.2 Serial Register Readout: Analog Bank

Contents of the registers located in the two pages of the analog bank (Figure 83) can be readback by:

1. Driving the SEN pin low.
2. Selecting the page address of the register whose content must be read. Master page: write address 0012h with 04h. ADC page: write address 0011h with FFh.
3. Setting the R/W bit to 1 and writing the address to be read back.
4. Reading back the register content on the SDOUT pin. When a page is selected, the contents of multiple registers located in same page can be readback.

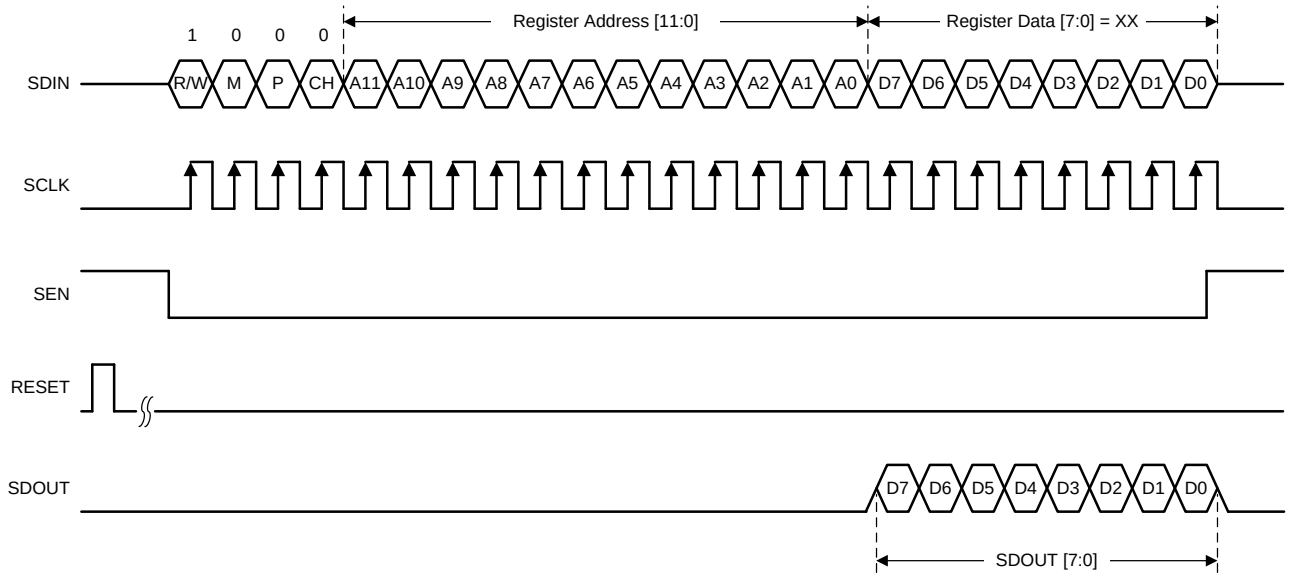


Figure 83. SPI Read Timing Diagram for the Analog Bank

Copyright © 2017, Texas Instruments Incorporated

9.4.3.3 Serial Register Write: Digital Bank

The digital bank contains seven pages (offset corrector page for channel A and B; digital gain page for channel A and B; main digital page for channel A and B; and JESD digital page). Figure 84 shows the timing for the individual page selection. The registers located in the pages of the digital bank can be programmed by:

1. Driving the SEN pin low.
2. Setting the M bit to 1 and specifying the page with the desired register. There are seven pages in digital bank. These pages can be selected by appropriately programming register bits DIGITAL BANK PAGE SEL, located in addresses 002h, 003h, and 004h, using three consecutive SPI cycles. Addressing in a SPI cycle begins with 4xxx when selecting a page from digital bank because the M bit must be set to 1.
   - To select the offset corrector page channel A: write address 4004h with 61h, 4003h with 00h, and 4002h with 00h.
   - To select the offset corrector page channel B: write address 4004h with 61h, 4003h with 01h, and 4002h with 00h.
   - To select the digital gain page channel A: write address 4004h with 61h, 4003h with 00h, and 4002h with 05h.
   - To select the digital gain page channel B: write address 4004h with 61h, 4003h with 01h, and 4002h with 05h.
   - To select the main digital page channel A: write address 4004h with 68h, 4003h with 00h, and 4002h with 00h.
   - To select the main digital page channel B: write address 4004h with 68h, 4003h with 01h, and 4002h with 00h.
   - To select the JESD digital page: write address 4004h with 69h, 4003h with 00h, and 4002h with 00h.

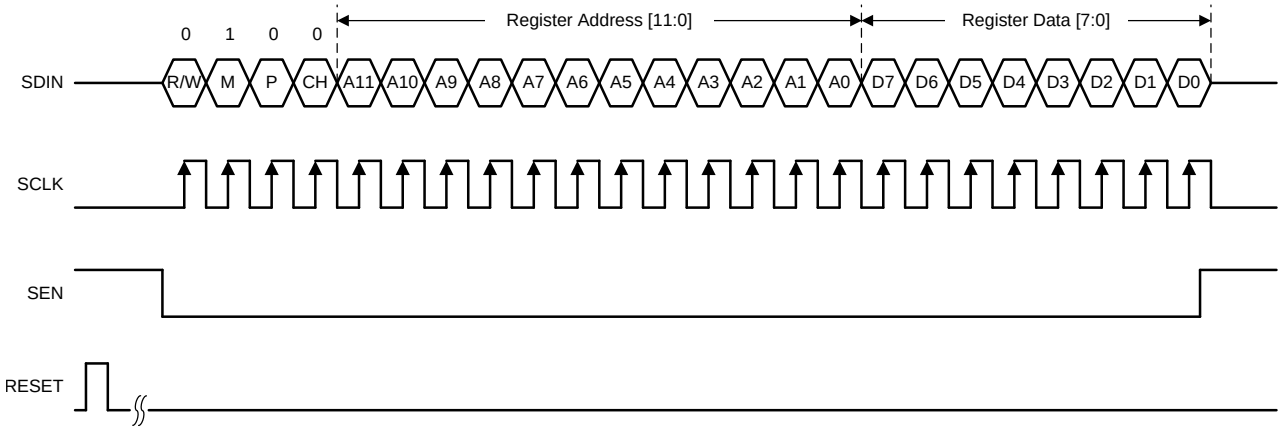


Figure 84. SPI Write Timing Diagram for Digital Bank Page Selection

Copyright © 2017, Texas Instruments Incorporated

3. Writing into the desired register by setting both the M bit and P bit to 1. Write register content. When a page is selected, multiple writes into the same page can be done. As shown in Figure 85, addressing in an SPI cycle begins with 6xxx when selecting a page from the digital bank because the M bit must be set to 1.

   The JESD digital page is common for both channels. The CH bit can be used to distinguish between two channels when programming registers in the JESD digital page. When CH = 0, registers are programmed for channel B; when CH = 1, registers are programmed for channel A. Thus, an SPI cycle to program registers for channel B begins with 6xxx and channel A begins with 7xxx.

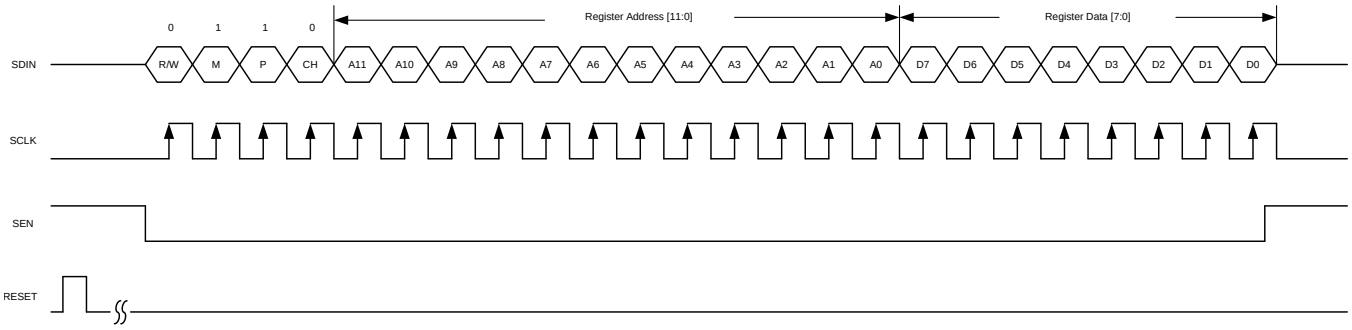


Figure 85. SPI Write Timing Diagram for Digital Bank Register Write

Copyright © 2017, Texas Instruments Incorporated

9.4.3.4 Serial Register Readout: Digital Bank

Readback of the register in one of the digital banks (as shown in Figure 86) can be accomplished by:

1. Driving the SEN pin low.
2. Selecting the page in the digital page: follow step 2 in the *Serial Register Write: Digital Bank* section.
3. Set the R/W, M, and P bits to 1, select channel A or channel B, and write the address to be read back.
   – JESD digital page: use the CH bit to select channel B (CH = 0) or channel A (CH = 1).
4. Read back the register content on the SDOUT pin. When a page is selected, multiple read backs from the same page can be done.

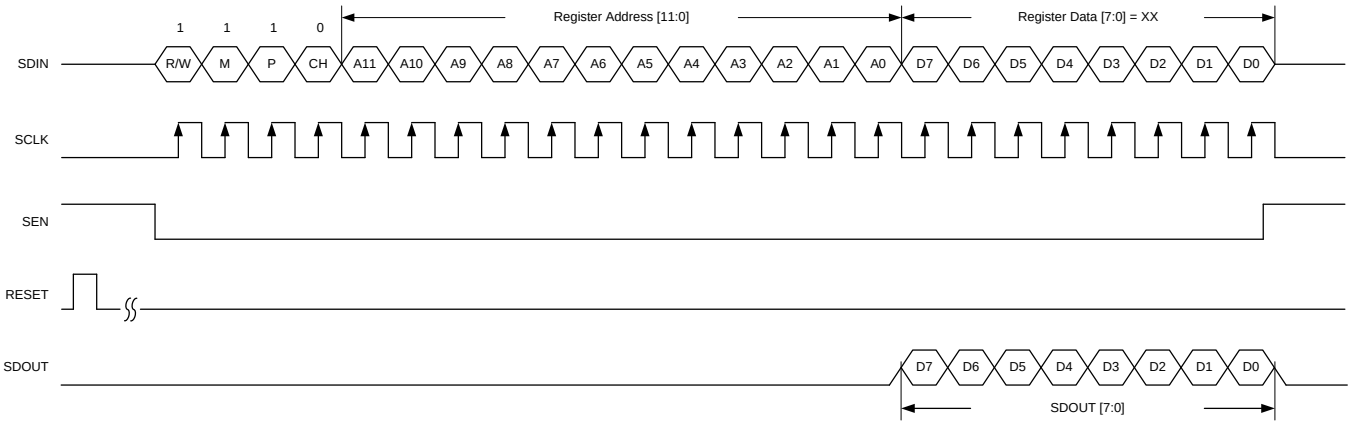


Figure 86. SPI Read Timing Diagram for the Digital Bank

9.4.3.5 Serial Register Write: Decimation Filter and Power Detector Pages

The decimation filter and power detector pages are special pages that accept direct addressing. The sampling clock and SYSREF signal are required to properly configure the decimation settings. Figure 87 shows that registers located in these pages can be programmed in one SPI cycle.

1. Drive the SEN pin low.
2. Directly write to the decimation filter or power detector pages. To program registers in these pages, set M = 1 and CH = 1. Additionally, address bit A[10] selects the decimation filter page (A[10] = 0) or the power detector page (A[10] = 1). Address bit A[11] selects channel A (A[11] = 0) or channel B (A[11] = 1).
   – Decimation filter page: write address 50xxh for channel A or 58xxh for channel B.
   – Power detector page: write address 54xxh for channel A or 5Cxxh for channel B.

Example: Writing address 5001h with 02h selects the decimation filter page for channel A and programs decimation factor of divide-by-8 (complex output).

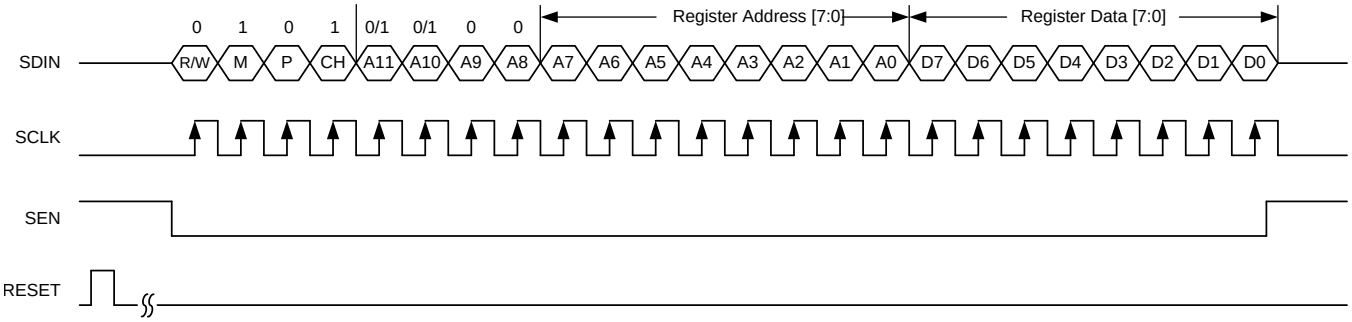
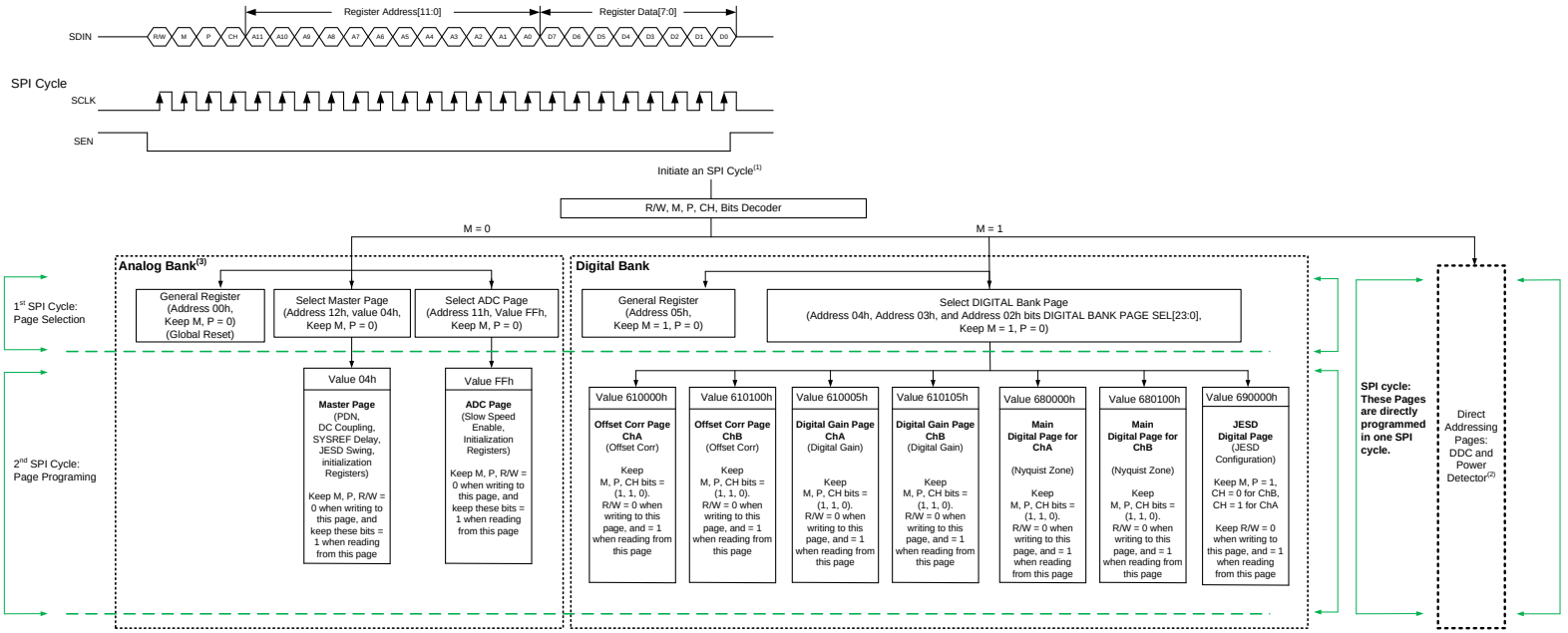


Figure 87. SPI Write Timing Diagram for the Decimation and Power Detector Pages

Copyright © 2017, Texas Instruments Incorporated

9.5 Register Maps

The ADC32RF42 contains two main SPI banks. The analog SPI bank provides access to the ADC core and the digital SPI bank controls the digital blocks (including the serial JESD interface). Figure 88 and Figure 89 provide a conceptual view of the SPI registers inside the ADC32RF42. The analog SPI bank contains the master and ADC pages. The digital SPI bank is divided into multiple pages (the main digital, digital gain, decimation filter, JESD digital, and power detector pages). STOPPED HERE



(1) In general, SPI writes are completed in two steps. The first step is to access the necessary page. The second step is to program the desired register in that page. When a page is accessed, the registers in that page can be programmed multiple times.

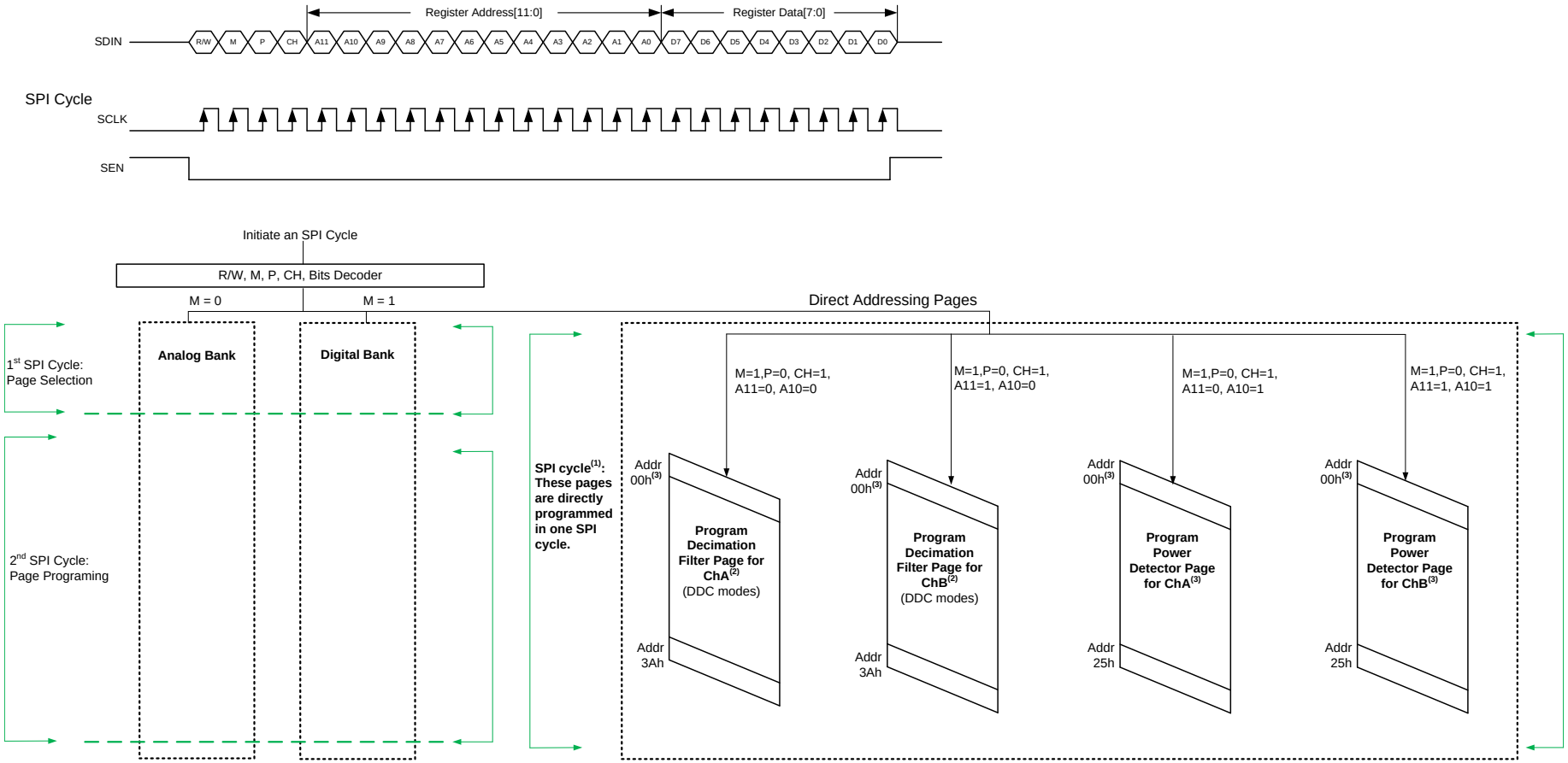
(2) Registers in the decimation filter page and the power detector page can be directly programmed in one SPI cycle.

(3) The CH bit is a *don't care* bit and is recommended to be kept at 0.

Figure 88. SPI Registers, Two-Step Addressing

Copyright © 2017, Texas Instruments Incorporated

Register Maps (continued)



(1) Registers in the decimation filter page and the power detector page can be directly programmed in one SPI cycle.

(2) To program registers in the decimation filter page, aet M = 1, CH = 1, A[10] = 0, and A[11] = 0 or 1 for channel A or B. Addressing begins at 50xx for channel A and 58xx for channel B.

(3) To program registers in power detector page, set M = 1, CH = 1, A[10] = 1, and A[11] = 0 or 1 for channel A or B. Addressing begins at 54xx for channel A and 5Cxx for channel B.

Figure 89. SPI Registers: Direct Addressing

Copyright © 2017, Texas Instruments Incorporated

Register Maps (continued)

Table 26 lists the register map for the ADC32RF42.

Table 26. Register Map

REGISTER ADDRESS A[11:0] (Hex)	REGISTER DATA							
	7	6	5	4	3	2	1	0
GENERAL REGISTERS AND PAGE SELECTION								
000	RESET	0	0	0	0	0	0	RESET
002	DIGITAL BANK PAGE SEL[7:0]							
003	DIGITAL BANK PAGE SEL[15:8]							
004	DIGITAL BANK PAGE SEL[23:16]							
010	0	0	0	0	0	0	0	3 or 4 WIRE
011	ADC PAGE SEL							
012	0	0	0	0	0	MASTER PAGE SEL	0	0
MASTER PAGE (M = 0)								
020	0	0	0	PDN SYSREF	0	0	PDN CHB	GLOBAL PDN
032	0	0	INCR CM IMPEDANCE	0	0	0	0	0
039	0	ALWAYS WRITE 1	0	ALWAYS WRITE 1	0	0	PDN CHB EN	SYNC TERM DIS
03C	0	SYSREF DEL EN	0	0	0	0	SYSREF DEL[4:3]	
03D	0	0	0	0	0	JESD OUTPUT SWING		
05A	SYSREF DEL[2:0]			0	0	0	0	0
057	0	0	0	SEL SYSREF REG	ASSERT SYSREF REG	0	0	0
058	0	0	SYNCB POL	0	0	0	0	0
ADC PAGE (FFh, M = 0)								
03F	0	0	0	0	0	SLOW SP EN1	0	0
042	0	0	0	SLOW SP EN2	0	0	ALWAYS WRITE 1	ALWAYS WRITE 1
Offset Corr Page Channel A (610000h, M = 1)								
68	FREEZE OFFSET CORR	0	ALWAYS WRITE 1	0	0	DIS OFFSET CORR	ALWAYS WRITE 1	0
Offset Corr Page Channel B (610100h, M = 1)								
68	FREEZE OFFSET CORR	0	ALWAYS WRITE 1	0	0	DIS OFFSET CORR	ALWAYS WRITE 1	0
Digital Gain Page Channel A (610005, M = 1)								
0A6	0	0	0	0	DIGITAL GAIN			

Copyright © 2017, Texas Instruments Incorporated

Register Maps (continued)

Table 26. Register Map (continued)

REGISTER ADDRESS A[11:0] (Hex)	REGISTER DATA							
	7	6	5	4	3	2	1	0
Digital Gain Page Channel B (610105, M = 1)								
0A6	0	0	0	0	DIGITAL GAIN			
Main Digital Page Channel A (680000h, M = 1)								
000	0	0	0	0	0	0	0	DIG CORE RESET GBL
0A2	0	0	0	0	NQ ZONE EN	NYQUIST ZONE		
Main Digital Page Channel B (680100h, M = 1)								
0A2	0	0	0	0	NQ ZONE EN	NYQUIST ZONE		
JESD DIGITAL PAGE (690000h, M = 1)								
001	CTRL K	0	0	TESTMODE EN	0	LANE ALIGN	FRAME ALIGN	TX LINK DIS
002	SYNC REG	SYNC REG EN	0	0	12BIT MODE		JESD MODE0	
003	LINK LAYER TESTMODE			LINK LAY RPAT	LMFC MASK RESET	JESD MODE1	JESD MODE2	RAMP 12BIT
004	0	0	0	0	0	0	REL ILA SEQ	
006	SCRAMBLE EN	0	0	0	0	0	0	0
007	0	0	0	FRAMES PER MULTIFRAME (K)				
016	LANE 0		LANE 1		LANE 2		LANE 3	
017	0	0	0	0	LANE0 POL	LANE1 POL	LANE2 POL	LANE3 POL
032	SEL EMP LANE 0						0	0
033	SEL EMP LANE 1						0	0
034	SEL EMP LANE 2						0	0
035	SEL EMP LANE 3						0	0
036	80X MODE EN	CMOS SYNCB	0	0	0	0	0	0
037	0	0	0	0	0	0	PLL MODE	
03C	0	0	0	0	0	0	0	EN CMOS SYNCB
03E	0	MASK CLKDIV SYSREF	MASK NCO SYSREF	0	0	0	0	0
SPECIAL PAGE CHANNEL A (6A0100h, M = 1)								
019	0	0	0	ALWAYS WRITE 1		0	0	0
SPECIAL PAGE CHANNEL B (6A0000h, M = 1)								
019	0	0	0	ALWAYS WRITE 1		0	0	0

Copyright © 2017, Texas Instruments Incorporated

Register Maps (continued)

Table 26. Register Map (continued)

REGISTER ADDRESS A[11:0] (Hex)	REGISTER DATA							
	7	6	5	4	3	2	1	0
DECIMATION FILTER PAGE (Direct Addressing, 16-Bit Address, 5000h for Channel A and 5800h for Channel B)								
000	0	0	0	0	0	0	0	DDC EN
001	0	0	0	0	DECIM FACTOR			
002	0	0	0	0	0	0	0	DUAL BAND EN
005	0	0	0	0	0	0	0	REAL OUT EN
006	0	0	0	0	0	0	0	DDC MUX
007	DDC0 NCO1 LSB							
008	DDC0 NCO1 MSB							
009	DDC0 NCO2 LSB							
00A	DDC0 NCO2 MSB							
00B	DDC0 NCO3 LSB							
00C	DDC0 NCO3 MSB							
00D	DDC1 NCO4 LSB							
00E	DDC1 NCO4 MSB							
00F	0	0	0	0	0	0	0	NCO SEL PIN
010	0	0	0	0	0	0	NCO SEL	
011	0	0	0	0	0	0	LMFC RESET MODE	
014	0	0	0	0	0	0	0	DDC0 6DB GAIN
016	0	0	0	0	0	0	0	DDC1 6DB GAIN
01E	0	DDC DET LAT			0	0	0	0
01F	0	0	0	0	0	0	0	WBF 6DB GAIN
020	0	0	0	0	0	0	0	ALWAYS WRITE 1
033	CUSTOM PATTERN1[7:0]							
034	CUSTOM PATTERN1[15:8]							
035	CUSTOM PATTERN2[7:0]							
036	CUSTOM PATTERN2[15:8]							
037	0	0	0	0	TEST PATTERN SEL			
038	TEST PATTERN DDC2 Q-DATA				TEST PATTERN DDC2 I -DATA			
039	0	0	0	0	0	0	0	USE COMMON TEST PATTERN
03A	0	0	0	0	0	0	TEST PAT RES	TP RES EN

Copyright © 2017, Texas Instruments Incorporated

Register Maps (continued)

Table 26. Register Map (continued)

REGISTER ADDRESS A[11:0] (Hex)	REGISTER DATA							
	7	6	5	4	3	2	1	0
POWER DETECTOR PAGE (Direct Addressing, 16-Bit Address, 5400h for Channel A and 5C00h for Channel B)								
000	0	0	0	0	0	0	0	PKDET EN
001	BLKPKDET [7:0]							
002	BLKPKDET [15:8]							
003	0	0	0	0	0	0	0	BLKPKDET [16]
007	BLKTHHH							
008	BLKTHHL							
009	BLKTHLH							
00A	BLKTHLL							
00B	DWELL[7:0]							
00C	DWELL[15:8]							
00D	0	0	0	0	0	0	0	FILT0LPSEL
00E	0	0	0	0	TIMECONST			
00F	FIL0THH[7:0]							
010	FIL0THH[15:8]							
011	FIL0THL[7:0]							
012	FIL0THL[15:8]							
013	0	0	0	0	0	0	0	IIR0 2BIT EN
016	FIL1THH[7:0]							
017	FIL1THH[15:8]							
018	FIL1THL[7:0]							
019	FIL1THL[15:8]							
01A	0	0	0	0	0	0	0	IIR1 2BIT EN
01D	DWELLIIR[7:0]							
01E	DWELLIIR[15:8]							
020	0	0	0	0	0	0	0	IIR0 2BIT EN
021	0	0	0	PWRDETACCU				
022	PWRDETH[7:0]							
023	PWRDETH[15:8]							
024	PWRDETL[7:0]							
025	PWRDETL[15:8]							

Copyright © 2017, Texas Instruments Incorporated

Register Maps (continued)

Table 26. Register Map (continued)

REGISTER ADDRESS A[11:0] (Hex)	REGISTER DATA							
	7	6	5	4	3	2	1	0
POWER DETECTOR PAGE (continued)								
027	0	0	0	0	0	0	0	RMS 2BIT EN
02B	0	0	0	RESET AGC	0	0	0	0
037	0	0	0	0	IODIR GPIO4	IODIR GPIO3	IODIR GPIO2	IODIR GPIO1
038	0	0	INSEL1		0	0	INSEL0	
POWER DETECTOR PAGE (Direct Addressing, 16-Bit Address, 5400h)								
032	OUTSEL GPIO1							
033	OUTSEL GPIO2							
034	OUTSEL GPIO3							
035	OUTSEL GPIO4							

Copyright © 2017, Texas Instruments Incorporated

9.5.1 Example Register Writes

This section provides three different example register writes. Table 27 describes a global power-down register write, Table 28 describes the register writes when the scrambler is enabled, and Table 29 describes the register writes for 8x decimation for channels A and B (complex output, 1 DDC mode) with the NCO set to 1.56 GHz (f_S = 2.6 GSPS) and the JESD format configured to LMFS = 4421.

Table 27. Global Power-Down

ADDRESS	DATA	COMMENT
12h	04h	Set the master page
20h	01h	Set the global power-down

Table 28. Scrambler Enable

ADDRESS	DATA	COMMENT
4004h	69h	Select the digital JESD page
4003h	00h	
6006h	80h	Scrambler enable, channel A
7006h	80h	Scrambler enable, channel B

Table 29. 8x Decimation for Channel A and B

ADDRESS	DATA	COMMENT
4004h	68h	Select the main digital page for channel A
4003h	00h	
6000h	01h	Issue a digital reset for channel A
6000h	00h	Clear the digital for reset channel A
4003h	01h	Select the main digital page for channel B
6000h	01h	Issue a digital reset for channel B
6000h	00h	Clear the digital reset for channel B
4004h	69h	Select the digital JESD page
4003h	00h	
6002h	01h	Set JESD MODE0 = 1, channel A
7002h	01h	Set JESD MODE0 = 1, channel B
5000h	01h	Enable the DDC, channel A
5001h	02h	Set decimation to 8x complex
5007h	9Ah	Set the LSB of DDC0, NCO1 to 9Ah (f_{NCO} = 1.56GHz, f_S = 2.6 GSPS)
5008h	99h	Set the MSB of DDC0, NCO1 to 99h (f_{NCO} = 1.56 GHz, f_S = 2.6 GSPS)
5014h	01h	Enable the 6-dB digital gain of DDC0
5801h	02h	Set decimation to 8x complex
5807h	9Ah	Set the LSB of DDC0, NCO1 to 9Ah (f_{NCO} = 1.56 GHz, f_S = 2.6 GSPS)
5808h	99h	Set the MSB of DDC0, NCO1 to 99h (f_{NCO} = 1.56 GHz, f_S = 2.6 GSPS)
5814h	01h	Enable the 6-dB digital gain of DDC0

Copyright © 2017, Texas Instruments Incorporated

9.5.2 Register Descriptions

Table 30. ADC32RF42 Access Type Codes

Access Type	Code	Description
R	R	Read
R-W	R/W	Read or Write
W	W	Write
-n		Value after reset or the default value

9.5.2.1 General Registers

9.5.2.1.1 Register 000h (address = 000h), General Registers

Figure 90. Register 000h

7	6	5	4	3	2	1	0
RESET	0	0	0	0	0	0	RESET
R/W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 31. Register 000h Field Descriptions

Bit	Field	Type	Reset	Description
7	RESET	R/W	0h	0 = Normal operation 1 = Internal software reset, clears back to 0
6-1	0	W	0h	Must write 0
0	RESET	R/W	0h	0 = Normal operation(1) 1 = Internal software reset, clears back to 0

(1) Both bits (7, 0) must be set simultaneously to perform a reset.

9.5.2.1.2 Register 002h (address = 002h), General Registers

Figure 91. Register 002h

7	6	5	4	3	2	1	0
DIGITAL BANK PAGE SEL[7:0]							
R/W-0h							

Table 32. Register 002h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DIGITAL BANK PAGE SEL[7:0]	R/W	0h	Program the JESD BANK PAGE SEL[23:0] bits to access the desired page in the digital bank. 610000h = Offset corr page channel A selected 610100h = Offset corr page channel B selected 610005h = Digital gain page channel A selected 610105h = Digital gain page channel B selected 680000h = Main digital page channel A selected 680100h = Main digital page channel B selected 690000h = JESD digital page selected

Copyright © 2017, Texas Instruments Incorporated

9.5.2.1.3 Register 003h (address = 003h), General Registers

Figure 92. Register 003h

7	6	5	4	3	2	1	0
DIGITAL BANK PAGE SEL[15:8]							
R/W-0h							

Table 33. Register 003h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DIGITAL BANK PAGE SEL[15:8]	R/W	0h	Program the JESD BANK PAGE SEL[23:0] bits to access the desired page in the digital bank. 610000h = Offset corr page channel A selected 610100h = Offset corr page channel B selected 610005h = Digital gain page channel A selected 610105h = Digital gain page channel B selected 680000h = Main digital page channel A selected 680100h = Main digital page channel B selected 690000h = JESD digital page selected

9.5.2.1.4 Register 004h (address = 004h), General Registers

Figure 93. Register 004h

7	6	5	4	3	2	1	0
DIGITAL BANK PAGE SEL[23:16]							
R/W-0h							

Table 34. Register 004h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DIGITAL BANK PAGE SEL[23:16]	R/W	0h	Program the JESD BANK PAGE SEL[23:0] bits to access the desired page in the digital bank. 610000h = Offset corr page channel A selected 610100h = Offset corr page channel B selected 610005h = Digital gain page channel A selected 610105h = Digital gain page channel B selected 680000h = Main digital page channel A selected 680100h = Main digital page channel B selected 690000h = JESD digital page selected

9.5.2.1.5 Register 010h (address = 010h), General Registers

Figure 94. Register 010h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	3 or 4 WIRE
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 35. Register 010h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	3 or 4 WIRE	R/W	0h	0 = 4-wire SPI (default) 1 = 3-wire SPI where SDIN become input or output

Copyright © 2017, Texas Instruments Incorporated

9.5.2.1.6 Register 011h (address = 011h), General Registers

Figure 95. Register 011h

7	6	5	4	3	2	1	0
ADC PAGE SEL							
R/W-0h							

Table 36. Register 011h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	ADC PAGE SEL	R/W	0h	00000000 = Normal operation, ADC page is not selected 11111111 = ADC page is selected; MASTER PAGE SEL must be set to 0

9.5.2.1.7 Register 012h (address = 012h), General Registers

Figure 96. Register 012h

7	6	5	4	3	2	1	0
0	0	0	0	0	MASTER PAGE SEL	0	0
W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	W-0h	W-0h

Table 37. Register 012h Field Descriptions

Bit	Field	Type	Reset	Description
7-3	0	W	0h	Must write 0
2	MASTER PAGE SEL	R/W	0h	0 = Normal operation 1 = Selects the master page address; ADC PAGE must be set to 0
1-0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.3 Master Page (M = 0)

9.5.3.1 Register 020h (address = 020h), Master Page

Figure 97. Register 020h

7	6	5	4	3	2	1	0
0	0	0	PDN SYSREF	0	0	PDN CHB	GLOBAL PDN
W-0h	W-0h	W-0h	R/W-0h	W-0h	R/W-0h	R/W-0h	R/W-0h

Table 38. Register 020h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4	PDN SYSREF	R/W	0h	This bit powers down the SYSREF input buffer. 0 = Normal operation 1 = SYSREF input capture buffer is powered down and further SYSREF input pulses are ignored
3-2	0	W	0h	Must write 0
1	PDN CHB	R/W	0h	This bit powers down channel B. 0 = Normal operation 1 = Channel B is powered down
0	GLOBAL PDN	R/W	0h	This bit enables the global power-down. 0 = Normal operation 1 = Global power-down enabled

9.5.3.2 Register 032h (address = 032h), Master Page

Figure 98. Register 032h

7	6	5	4	3	2	1	0
0	0	INCR CM IMPEDANCE	0	0	0	0	0
W-0h	W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h	W-0h

Table 39. Register 032h Field Descriptions

Bit	Field	Type	Reset	Description
7-6	0	W	0h	Must write 0
5	INCR CM IMPEDANCE	R/W	0h	Only use this bit when analog inputs are dc-coupled to the driver. 0 = VCM buffer directly drives the common point of biasing resistors. 1 = VCM buffer drives the common point of biasing resistors with > 5 kΩ
4-0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.3.3 Register 039h (address = 039h), Master Page

Figure 99. Register 039h

7	6	5	4	3	2	1	0
0	ALWAYS WRITE 1	0	ALWAYS WRITE 1	0	0	PDN CHB EN	SYNC TERM DIS
W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	R/W-0h	R/W-0h

Table 40. Register 039h Field Descriptions

Bit	Field	Type	Reset	Description
7	0	W	0h	Must write 0
6	ALWAYS WRITE 1	W	0h	Always set this bit to 1
5	0	W	0h	Must write 0
4	ALWAYS WRITE 1	W	0h	Always set this bit to 1
3-2	0	W	0h	Must write 0
1	PDN CHB EN	R/W	0h	This bit enables the power-down control of channel B through the SPI in register 20h. 0 = PDN control disabled 1 = PDN control enabled
0	SYNC TERM DIS	R/W	0h	This bit disables the on-chip, 100-Ω termination resistors on the SYNCB input. 0 = On-chip, 100-Ω termination enabled 1 = On-chip, 100-Ω termination disabled

9.5.3.4 Register 03Ch (address = 03Ch), Master Page

Figure 100. Register 03Ch

7	6	5	4	3	2	1	0
0	SYSREF DEL EN	0	0	0	0	SYSREF DEL[4:3]	
W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	

Table 41. Register 03Ch Field Descriptions

Bit	Field	Type	Reset	Description
7	0	W	0h	Must write 0
6	SYSREF DEL EN	R/W	0h	This bit allows an internal delay to be added to the SYSREF input. 0 = SYSREF delay disabled 1 = SYSREF delay enabled through register settings [3Ch (bits 1-0), 5Ah (bits 7-5)]
5-2	0	W	0h	Must write 0
1-0	SYSREF DEL[4:3]	R/W	0h	When the SYSREF delay feature is enabled (3Ch, bit 6) the delay can be adjusted in 25-ps steps; the first step is 175 ps. The PVT variation of each 25-ps step is ±10 ps. The 175-ps step is ±50 ps; see Table 43.

Copyright © 2017, Texas Instruments Incorporated

9.5.3.5 Register 05Ah (address = 05Ah), Master Page

Figure 101. Register 05Ah

7	6	5	4	3	2	1	0
SYSREF DEL[2:0]			0	0	0	0	0
W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h

Table 42. Register 05Ah Field Descriptions

Bit	Field	Type	Reset	Description
7	SYSREF DEL2	W	0h	When the SYSREF delay feature is enabled (3Ch, bit 6) the delay can be adjusted in 25-ps steps; the first step is 175 ps. The PVT variation of each 25-ps step is ±10 ps. The 175-ps step is ±50 ps; see Table 43.
6	SYSREF DEL1	R/W		
5	SYSREF DEL0	W		
4-0	0	W	0h	Must write 0

Table 43. SYSREF DEL[2:0] Bit Settings

STEP	SETTING	STEP (NOM)	TOTAL DELAY (NOM)
1	01000	175 ps	175 ps
2	00111	25 ps	200 ps
3	00110	25 ps	225 ps
4	00101	25 ps	250 ps
5	00100	25 ps	275 ps
6	00011	25 ps	300 ps

9.5.3.6 Register 03Dh (address = 3Dh), Master Page

Figure 102. Register 03Dh

7	6	5	4	3	2	1	0
0	0	0	0	0	JESD OUTPUT SWING		
W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h		

Table 44. Register 03Dh Field Descriptions

Bit	Field	Type	Reset	Description
7-3	0	W	0h	Must write 0
2-0	JESD OUTPUT SWING	R/W	0h	These bits select the output amplitude, V_{OD} (mV_{PP}), of the JESD transmitter for all lanes. 0 = 860 mV_{PP} 1= 810 mV_{PP} 2 = 770 mV_{PP} 3 = 745 mV_{PP} 4 = 960 mV_{PP} 5 = 930 mV_{PP} 6 = 905 mV_{PP} 7 = 880 mV_{PP}

Copyright © 2017, Texas Instruments Incorporated

9.5.3.7 Register 057h (address = 057h), Master Page

Figure 103. Register 057h

7	6	5	4	3	2	1	0
0	0	0	SEL SYSREF REG	ASSERT SYSREF REG	0	0	0
W-0h	W-0h	W-0h	R/W-0h	R/W-0h	W-0h	W-0h	W-0h

Table 45. Register 057h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4	SEL SYSREF REG	R/W	0h	Set this bit to use the SPI register to assert SYSREF. 0 = SYSREF is asserted by device pins 1 = SYSREF can be asserted by the ASSERT SYSREF REG register bit Other bits = 0
3	ASSERT SYSREF REG	R/W	0h	SYSREF can be asserted using this bit. Ensure that the SEL SYSREF REG register bit is set high before using this bit; see the *Using SYSREF* section. 0 = SYSREF is logic low 1 = SYSREF is logic high
2-0	0	W	0h	Must write 0

9.5.3.8 Register 058h (address = 058h), Master Page

Figure 104. Register 058h

7	6	5	4	3	2	1	0
0	0	SYNCB POL	0	0	0	0	0
W-0h	W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h	W-0h

Table 46. Register 058h Field Descriptions

Bit	Field	Type	Reset	Description
7-6	0	W	0h	Must write 0
5	SYNCB POL	R/W	0h	This bit inverts the SYNCB polarity. 0 = Polarity is not inverted; this setting matches the timing diagrams in this document and is the proper setting to use 1 = Polarity is inverted
4-0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.4 ADC Page (FFh, M = 0)

9.5.4.1 Register 03Fh (address = 03Fh), ADC Page

Figure 105. Register 03Fh

7	6	5	4	3	2	1	0
0	0	0	0	0	SLOW SP EN1	0	0
W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	W-0h	W-0h

Table 47. Register 03Fh Field Descriptions

Bit	Field	Type	Reset	Description
7-3	0	W	0h	Must write 0
2	SLOW SP EN1	R/W	0h	This bit must be enabled for clock rates below 2.5 GSPS. 0 = ADC sampling rates are faster than 2.5 GSPS 1 = ADC sampling rates are slower than 2.5 GSPS
1-0	0	W	0h	Must write 0

9.5.4.2 Register 042h (address = 042h), ADC Page

Figure 106. Register 042h

7	6	5	4	3	2	1	0
0	0	0	SLOW SP EN2	0	0	ALWAYS WRITE 1	ALWAYS WRITE 1
W-0h	W-0h	W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h

Table 48. Register 042h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4	SLOW SP EN2	R/W	0h	This bit must be enabled for clock rates below 2.5 GSPS. 0 = ADC sampling rates are faster than 2.5 GSPS 1 = ADC sampling rates are slower than 2.5 GSPS
3-2	0	W	0h	Must write 0
1-0	ALWAYS WRITE 1	W	1h	Always set this bit to 1

Copyright © 2017, Texas Instruments Incorporated

9.5.5 Offset Corr Page Channel A (610000h, M = 1)

9.5.5.1 Register 068h (address = 068h), Offset Corr Page Channel A

Figure 107. Register 068h

7	6	5	4	3	2	1	0
FREEZE OFFSET CORR	0	ALWAYS WRITE 1	0	0	DIS OFFSET CORR	ALWAYS WRITE 1	0
R/W-0h	W-0h	R/W-0h	W-0h	W-0h	R/W-0h	R/W-0h	R/W-0h

Table 49. Register 068h Field Descriptions

Bit	Field	Type	Reset	Description
7	FREEZE OFFSET CORR	R/W	0h	Use this bit and bits 5 and 1 to freeze the offset estimation process of the offset corrector; see the *Using DC Coupling in the ADC32RF42* section. 011 = Apply this setting after powering up the device 111 = Offset corrector is frozen, does not estimate offset anymore, and applies the last computed value. Others = Do not use
6	0	W	0h	Must write 0
5	ALWAYS WRITE 1	R/W	0h	Always set this bit to 1 for the offset correction block to work properly.
4-3	0	W	0h	Must write 0
2	DIS OFFSET CORR	R/W	0h	0 = Offset correction block works and removes $f_{S/8}$, $f_{S/4}$, $3f_{S/8}$, and $f_{S/2}$ spurs 1 = Offset correction block is disabled
1	ALWAYS WRITE 1	R/W	0h	Always set this bit to 1 for the offset correction block to work properly.
0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.6 Offset Corr Page Channel B (610100h, M = 1)

9.5.6.1 Register 068h (address = 068h), Offset Corr Page Channel B

Figure 108. Register 068h

7	6	5	4	3	2	1	0
FREEZE OFFSET CORR	0	ALWAYS WRITE 1	0	0	DIS OFFSET CORR	ALWAYS WRITE 1	0
R/W-0h	W-0h	R/W-0h	W-0h	W-0h	R/W-0h	R/W-0h	R/W-0h

Table 50. Register 068h Field Descriptions

Bit	Field	Type	Reset	Description
7,5,1	FREEZE OFFSET CORR	R/W	0h	Use this bit and bits 5 and 1 to freeze the offset estimation process of the offset corrector; see the *Using DC Coupling in the ADC32RF42* section. 011 = Apply this setting after powering up the device 111 = Offset corrector is frozen, does not estimate offset anymore, and applies the last computed value. Others = Do not use
6	0	W	0h	Must write 0
5	ALWAYS WRITE 1	R/W	0h	Always set this bit to 1 for the offset correction block to work properly.
4-3	0	W	0h	Must write 0
2	DIS OFFSET CORR	R/W	0h	0 = Offset correction block works and removes $f_{S/8}$, $f_{S/4}$, $3f_{S/8}$, and $f_{S/2}$ spurs 1 = Offset correction block is disabled
1	ALWAYS WRITE 1	R/W	0h	Always set this bit to 1 for the offset correction block to work properly.
0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.7 Digital Gain Page (610005h, M = 1 for Channel A and 610105h, M = 1 for Channel B)

9.5.7.1 Register 0A6h (address = 0A6h), Digital Gain Page

Figure 109. Register 0A6h

7	6	5	4	3	2	1	0
0	0	0	0	DIGITAL GAIN			
W-0h	W-0h	W-0h	W-0h	R/W-0h			

Table 51. Register 0A6h Field Descriptions

Bit	Field	Type	Reset	Description
7-4	0	W	0h	Must write 0
3-0	DIGITAL GAIN	R/W	0h	These bits apply a digital gain to the ADC data (before the DDC) up to 11 dB. 0000 = Default 0001 = 1 dB 1011 = 11 dB Others = Do not use

9.5.8 Main Digital Page Channel A (680000h, M = 1)

9.5.8.1 Register 000h (address = 000h), Main Digital Page Channel A

Figure 110. Register 000h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	DIG CORE RESET GBL
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 52. Register 000h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	DIG CORE RESET GBL	R/W	0h	Pulse this bit (0 →1 →0) to reset the digital core (applies to both channel A and B). All Nyquist zone settings take effect when this bit is pulsed.

Copyright © 2017, Texas Instruments Incorporated

9.5.8.2 Register 0A2h (address = 0A2h), Main Digital Page Channel A

Figure 111. Register 0A2h

7	6	5	4	3	2	1	0
0	0	0	0	NQ ZONE EN	NYQUIST ZONE		
W-0h	W-0h	W-0h	W-0h	R/W-0h	R/W-0h		

Table 53. Register 0A2h Field Descriptions

Bit	Field	Type	Reset	Description
7-4	0	W	0h	Must write 0
3	NQ ZONE EN	R/W	0h	This bit allows for specification of the operating Nyquist zone. 0 = Nyquist zone specification disabled 1 = Nyquist zone specification enabled
2-0	NYQUIST ZONE	R/W	0h	These bits specify the operating Nyquist zone for the analog correction loop. Set the NQ ZONE EN bit before programming these bits. For example, at a 1.5-GSPS chip clock, the first Nyquist zone is from dc to 750 MHz, the second Nyquist zone is from 750 MHz to 1.5 GHz, and so on. 000 = First Nyquist zone (dc – f_S / 2) 001 = Second Nyquist zone (f_S / 2 – f_S) 010 = Third Nyquist zone 011 = Fourth Nyquist zone

9.5.9 Main Digital Page Channel B (680100h, M = 1)

9.5.9.1 Register 0A2h (address = 0A2h), Main Digital Page Channel B

Figure 112. Register 0A2h

7	6	5	4	3	2	1	0
0	0	0	0	NQ ZONE EN	NYQUIST ZONE		
W-0h	W-0h	W-0h	W-0h	R/W-0h	R/W-0h		

Table 54. Register 0A2h Field Descriptions

Bit	Field	Type	Reset	Description
7-4	0	W	0h	Must write 0
3	NQ ZONE EN	R/W	0h	This bit allows for specification of the operating Nyquist zone. 0 = Nyquist zone specification disabled 1 = Nyquist zone specification enabled
2-0	NYQUIST ZONE	R/W	0h	These bits specify the operating Nyquist zone for the analog correction loop. Set the NQ ZONE EN bit before programming these bits. For example, at a 2.6-GSPS chip clock, first Nyquist zone is from dc to 1.3 GHz, the second Nyquist zone is from 1.3 GHz to 2.6 GHz, and so on. 000 = First Nyquist zone (dc – f_S / 2) 001 = Second Nyquist zone (f_S / 2 – f_S) 010 = Third Nyquist zone 011 = Fourth Nyquist zone

Copyright © 2017, Texas Instruments Incorporated

9.5.10 JESD Digital Page (690000h, M = 1)

9.5.10.1 Register 001h (address = 001h), JESD Digital Page

Figure 113. Register 001h

7	6	5	4	3	2	1	0
CTRL K	0	0	TESTMODE EN	0	LANE ALIGN	FRAME ALIGN	TX LINK DIS
R/W-0h	W-0h	W-0h	R/W-0h	W-0h	R/W-0h	R/W-0h	R/W-0h

Table 55. Register 001h Field Descriptions

Bit	Field	Type	Reset	Description
7	CTRL K	R/W	0h	This bit is the enable bit for the number of frames per multiframe. 0 = Default is five frames per multiframe 1 = Frames per multiframe can be set in register 07h
6-5	0	R/W	0h	Must write 0
4	TESTMODE EN		0	This bit generates a long transport layer test pattern mode according to section 5.1.6.3 of the JESD204B specification. 0 = Test mode disabled 1 = Test mode enabled
3	0	W	0h	Must write 0
2	LANE ALIGN	R/W	0h	This bit inserts a lane alignment character (K28.3) for the receiver to align to the lane boundary per section 5.3.3.5 of the JESD204B specification. 0 = Normal operation 1 = Inserts lane alignment characters
1	FRAME ALIGN	R/W	0h	This bit inserts a frame alignment character (K28.7) for the receiver to align to the frame boundary per section 5.3.35 of the JESD204B specification. 0 = Normal operation 1 = Inserts frame alignment characters
0	TX LINK DIS	R/W	0h	This bit disables sending the initial link alignment (ILA) sequence when SYNC is deasserted. 0 = Normal operation 1 = ILA disabled

Copyright © 2017, Texas Instruments Incorporated

9.5.10.2 Register 002h (address = 002h), JESD Digital Page

Figure 114. Register 002h

7	6	5	4	3	2	1	0
SYNC REG	SYNC REG EN	0	0	12BIT MODE		JESD MODE0	
R/W-0h	R/W-0h	W-0h	W-0h	R/W-0h		R/W-0h	

Table 56. Register 002h Field Descriptions

Bit	Field	Type	Reset	Description
7	SYNC REG	R/W	0h	This bit provides SYNC control through the SPI. 0 = Normal operation 1 = ADC output data are replaced with K28.5 characters
6	SYNC REG EN	R/W	0h	This bit is the enable bit for SYNC control through the SPI. 0 = Normal operation 1 = SYNC control through the SPI is enabled (ignores the SYNCB input pins)
5-4	0	W	0h	Must write 0
3-2	12BIT MODE	R/W	0h	This bit enables the 12-bit output mode for more efficient data packing. 00 = Normal operation, 14-bit output 01, 10 = Unused 11 = High-efficient data packing enabled
1-0	JESD MODE0	R/W	0h	These bits select the configuration register to configure the correct LMFS frame assemblies for different decimation settings; see the JESD frame assembly tables in the *JESD204B Frame Assembly* section. 00 = 0 01 = 1 10 = 2 11 = 3

Copyright © 2017, Texas Instruments Incorporated

9.5.10.3 Register 003h (address = 003h), JESD Digital Page

Figure 115. Register 003h

7	6	5	4	3	2	1	0
LINK LAYER TESTMODE			LINK LAY RPAT	LMFC MASK RESET	JESD MODE1	JESD MODE2	RAMP 12BIT
R/W-0h			R/W-0h	R/W-0h	R/W-1h	R/W-0h	R/W-0h

Table 57. Register 003h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	LINK LAYER TESTMODE	R/W	0h	These bits generate a pattern according to section 5.3.3.8.2 of the JESD204B document. 000 = Normal ADC data 001 = D21.5 (high-frequency jitter pattern) 010 = K28.5 (mixed-frequency jitter pattern) 011 = Repeat initial lane alignment (generates a K28.5 character and repeats lane alignment sequences continuously) 100 = 12-octet RPAT jitter pattern
4	LINK LAY RPAT	R/W	0h	This bit changes the running disparity in a modified RPAT pattern test mode (only when link layer test mode = 100). 0 = Normal operation 1 = Changes disparity
3	LMFC MASK RESET	R/W	0h	0 = Normal operation
2	JESD MODE1	R/W	1h	These bits select the configuration register to configure the correct LMFS frame assemblies for different decimation settings; see the JESD frame assembly tables in the *JESD204B Frame Assembly* section
1	JESD MODE2	R/W	0h	These bits select the configuration register to configure the correct LMFS frame assemblies for different decimation settings; see the JESD frame assembly tables in the *JESD204B Frame Assembly* section
0	RAMP 12BIT	R/W	0h	This bit enables the RAMP test pattern for 12-bit mode only (LMFS = 42810). 0 = Normal data output 1 = Digital output is the RAMP pattern

9.5.10.4 Register 004h (address = 004h), JESD Digital Page

Figure 116. Register 004h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	REL ILA SEQ	
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	

Table 58. Register 004h Field Descriptions

Bit	Field	Type	Reset	Description
7-2	0	W	0h	Must write 0
1-0	REL ILA SEQ	R/W	0h	These bits delay the generation of the lane alignment sequence by 0, 1, 2, or 3 multiframes after the code group synchronization. 00 = 0 multiframe delays 01 = 1 multiframe delay 10 = 2 multiframe delays 11 = 3 multiframe delays

Copyright © 2017, Texas Instruments Incorporated

9.5.10.5 Register 006h (address = 006h), JESD Digital Page

Figure 117. Register 006h

7	6	5	4	3	2	1	0
SCRAMBLE EN	0	0	0	0	0	0	0
R/W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h

Table 59. Register 006h Field Descriptions

Bit	Field	Type	Reset	Description
7	SCRAMBLE EN	R/W	0h	This bit is the scramble enable bit in the JESD204B interface. 0 = Scrambling disabled 1 = Scrambling enabled
6-0	0	W	0h	Must write 0

9.5.10.6 Register 007h (address = 007h), JESD Digital Page

Figure 118. Register 007h

7	6	5	4	3	2	1	0
0	0	0	FRAMES PER MULTIFRAME (K)				
W-0h	W-0h	W-0h	R/W-0h				

Table 60. Register 007h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4-0	FRAMES PER MULTIFRAME (K)	R/W	0h	These bits set the number of multiframes. Actual K is the value in hex + 1 (that is, 0Fh is K = 16).

Copyright © 2017, Texas Instruments Incorporated

9.5.10.7 Register 016h (address = 016h), JESD Digital Page

Figure 119. Register 016h

7	6	5	4	3	2	1	0
LANE 0		LANE 1		LANE 2		LANE 03	
R/W-0h		R/W-0h		R/W-0h		R/W-0h	

Table 61. Register 016h Field Descriptions

Bit	Field	Type	Reset	Description
7-6	LANE 0	R/W	0h	For 80x mode: set these bits as 70h. Also set the 80X MODE EN register bit. For 40x mode: set these bits as 70h. For 20x mode: these bits can be used to swap the data on output lanes as shown in Table 62 and Figure 120.
5-4	LANE 1	R/W	0h	
3-2	LANE 2	R/W	0h	
1-0	LANE 3	R/W	0h	

Table 62. Swapping Data on Output Lanes for 20x Serialization

REGISTER BIT LANE 0	OUTPUT LANE0 CARRIES	REGISTER BIT LANE 1	OUTPUT LANE1 CARRIES	REGISTER BIT LANE 2	OUTPUT LANE2 CARRIES	REGISTER BIT LANE 3	OUTPUT LANE3 CARRIES
00	D0	00	D1	00	D2	00	D3
01	D1	01	D2	01	D3	01	D0
10	D2	10	D3	10	D0	10	D1
11	D3	11	D0	11	D1	11	D2

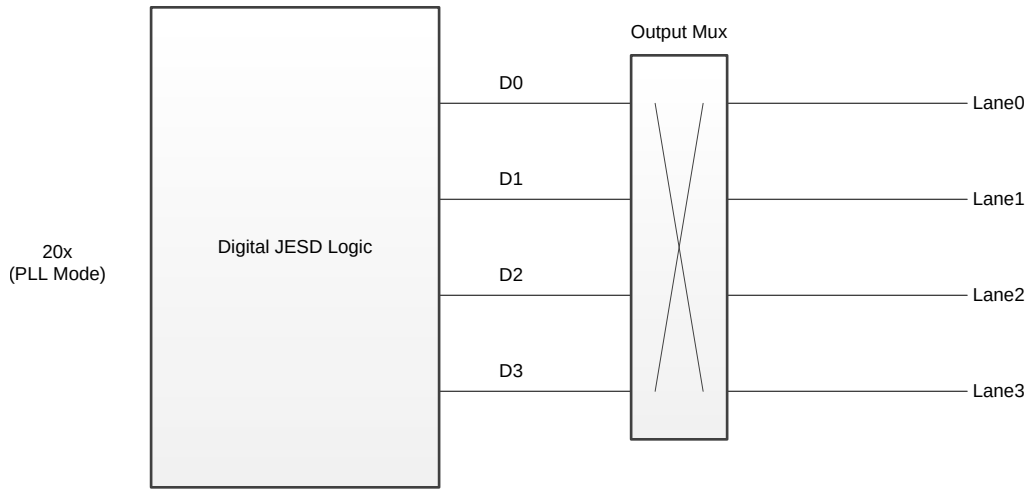


Figure 120. Output Lane Multiplexer

Copyright © 2017, Texas Instruments Incorporated

9.5.10.8 Register 017h (address = 017h), JESD Digital Page

Figure 121. Register 017h

7	6	5	4	3	2	1	0
0	0	0	0	Lane0 POL	Lane1 POL	Lane2 POL	Lane3 POL
W-0h	R/W-0h	R/W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h

Table 63. Register 017h Field Descriptions

Bit	Field	Type	Reset	Description
7	0	W	0h	Must write 0
6-4	0	R/W	0h	Must write 0
3-0	Lane[3:0] POL	W	0h	These bits set the polarity of the individual JESD output lanes. 0 = Polarity as given in the pinout (noninverted) 1 = Inverts polarity (positive, P, or negative, M)

9.5.10.9 Register 032h-035h (address = 032h-035h), JESD Digital Page

Figure 122. Register 032h

7	6	5	4	3	2	1	0
SEL EMP LANE 0						0	0
R/W-0h						W-0h	W-0h

Figure 123. Register 033h

7	6	5	4	3	2	1	0
SEL EMP LANE 1						0	0
R/W-0h						W-0h	W-0h

Figure 124. Register 034h

7	6	5	4	3	2	1	0
SEL EMP LANE 2						0	0
R/W-0h						W-0h	W-0h

Figure 125. Register 035h

7	6	5	4	3	2	1	0
SEL EMP LANE 3						0	0
R/W-0h						W-0h	W-0h

Table 64. Register 032h-035h Field Descriptions

Bit	Field	Type	Reset	Description
7-2	SEL EMP LANE	R/W	0h	These bits select the amount of de-emphasis for the JESD output transmitter. The de-emphasis value in dB is measured as the ratio between the peak value after the signal transition to the settled value of the voltage in one bit period. 0 = 0 dB 1 = –1 dB 3 = –2 dB 7 = –4.1 dB 15 = –6.2 dB 31 = –8.2 dB 63 = –11.5 dB
1-0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.10.10 Register 036h (address = 036h), JESD Digital Page

Figure 126. Register 036h

7	6	5	4	3	2	1	0
80X MODE EN	CMOS SYNCB	0	0	0	0	0	0
R/W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h

Table 65. Register 036h Field Descriptions

Bit	Field	Type	Reset	Description
7	80X MODE EN	R/W	0h	This bit enables the 80x mode. 0 = 80x mode disable 1 = 80x mode enable
6	CMOS SYNCB	R/W	0h	This bit enables single-ended control of SYNCB using the GPIO4 pin (pin 63). The differential SYNCB input is ignored. Set the EN CMOS SYNC register bit to make this bit effective. When programming this bit, keep the CH bit set to 1. 0 = Differential SYNCB input 1 = Single-ended SYNCB input using pin 63
5-0	0	W	0h	Must write 0

9.5.10.11 Register 037h (address = 037h), JESD Digital Page

Figure 127. Register 037h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	PLL MODE	
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	

Table 66. Register 037h Field Descriptions

Bit	Field	Type	Reset	Description
7-2	0	W	0h	Must write 0
1-0	PLL MODE	R/W	0h	These bits select the PLL multiplication factor; see the JESD tables in the *JESD204B Frame Assembly* section for settings. 00 = 20x mode 01 = 16x mode 10 = 40x mode (write register 16h with 70h) 11 = 80x mode (the 40X_80X MODE bit in register 16h must also be set)

Copyright © 2017, Texas Instruments Incorporated

9.5.10.12 Register 03Ch (address = 03Ch), JESD Digital Page

Figure 128. Register 03Ch

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	EN CMOS SYNCB
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 67. Register 03Ch Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
5	EN CMOS SYNCB	R/W	0h	0 = Default 1 = This bit enables the control of the SYNC request from the CMOS SYNCB register bit. When programming this bit, keep the CH bit set to 1.

9.5.10.13 Register 03Eh (address = 03Eh), JESD Digital Page

Figure 129. Register 03Eh

7	6	5	4	3	2	1	0
0	MASK CLKDIV SYSREF	MASK NCO SYSREF	0	0	0	0	0
W-0h	R/W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h	W-0h

Table 68. Register 03Eh Field Descriptions

Bit	Field	Type	Reset	Description
7	0	W	0h	Must write 0
6	MASK CLKDIV SYSREF	R/W	0h	Use this bit to mask the SYSREF going to the input clock divider. 0 = Input clock divider is reset when SYSREF is asserted (that is, when SYSREF transitions from low to high) 1 = Input clock divider ignores SYSREF assertions
5	MASK NCO SYSREF	R/W	0h	Use this bit to mask the SYSREF going to the NCO in the DDC block and LMFC counter of the JESD interface. 0 = NCO phase and LMFC counter are reset when SYSREF is asserted (that is, when SYSREF transitions from low to high) 1 = NCO and LMFC counter ignore SYSREF assertions
4-0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.11 Special Page Channel A

Channel A (6A0100h, M = 1)

9.5.11.1 Register 019h (address = 019h), Special Page Channel A

Figure 130. Register 019h

7	6	5	4	3	2	1	0
0	0	0	ALWAYS WRITE 1		0	0	0
W-0h	W-0h	W-0h	R/W-0h		W-0h	W-0h	W-0h

Table 69. Register 019h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4-3	W-0h	R/W	0h	Always write this bit as 1.
2-0	0	W	0h	Must write 0

9.5.12 Special Page Channel B

Channel B (6A0000h, M = 1)

9.5.12.1 Register 019h (address = 019h), Special Page Channel B

Figure 131. Register 019h

7	6	5	4	3	2	1	0
0	0	0	ALWAYS WRITE 1		0	0	0
W-0h	W-0h	W-0h	R/W-0h		W-0h	W-0h	W-0h

Table 70. Register 019h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4-3	W-0h	R/W	0h	Always write this bit as 1.
2-0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.13 Decimation Filter Page

Direct Addressing, 16-Bit Address, 5000h for Channel A, 5800h for Channel B

9.5.13.1 Register 000h (address = 000h), Decimation Filter Page

Figure 132. Register 000h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	DDC EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 71. Register 000h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	DDC EN	R/W	0h	This bit enables the decimation filter and disables the bypass mode. 0 = Bypass mode (DDC disabled) 1 = Decimation filter enabled

9.5.13.2 Register 001h (address = 001h), Decimation Filter Page

Figure 133. Register 001h

7	6	5	4	3	2	1	0
0	0	0	0	DECIM FACTOR			
W-0h	W-0h	W-0h	W-0h	R/W-0h			

Table 72. Register 001h Field Descriptions

Bit	Field	Type	Reset	Description
7-4	0	W	0h	Must write 0
3-0	DECIM FACTOR	R/W	0h	These bits configure the decimation filter setting. 0010 = Divide-by-4 complex 0101 = Divide-by-6 complex 0111 = Divide-by-8 complex 1000 = Divide-by-9 complex 1001 = Divide-by-10 complex 1010 = Divide-by-12 complex 1100 = Divide-by-16 complex Others = Not used

Copyright © 2017, Texas Instruments Incorporated

9.5.13.3 Register 002h (address = 2h), Decimation Filter Page

Figure 134. Register 002h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	DUAL BAND EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 73. Register 002h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	DUAL BAND EN	R/W	0h	This bit enables the dual-band DDC filter for the corresponding channel. 0 = Single-band DDC 1 = Dual-band DDC

9.5.13.4 Register 005h (address = 005h), Decimation Filter Page

Figure 135. Register 005h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	REAL OUT EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 74. Register 005h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	REAL OUT EN	R/W	0h	This bit converts the complex output to real output at 2x the output rate. 0 = Complex output format 1 = Real output format

Copyright © 2017, Texas Instruments Incorporated

9.5.13.5 Register 006h (address = 006h), Decimation Filter Page

Figure 136. Register 006h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	DDC MUX
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 75. Register 006h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	DDC MUX	R/W	0h	This bit connects the DDC to the alternate channel ADC to enable up to four DDCs with one ADC and completely turn off the other ADC channel. 0 = Normal operation 1 = DDC block takes input from the alternate ADC

9.5.13.6 Register 007h (address = 007h), Decimation Filter Page

Figure 137. Register 007h

7	6	5	4	3	2	1	0
DDC0 NCO1 LSB							
R/W-0h							

Table 76. Register 007h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC0 NCO1 LSB	R/W	0h	These bits are the LSB of the NCO frequency word for NCO1 of DDC0 (band 1). The LSB represents $f_S / (2^{16})$, where f_S is the ADC sampling frequency.

9.5.13.7 Register 008h (address = 008h), Decimation Filter Page

Figure 138. Register 008h

7	6	5	4	3	2	1	0
DDC0 NCO1 MSB							
R/W-0h							

Table 77. Register 008h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC0 NCO1 MSB	R/W	0h	These bits are the MSB of the NCO frequency word for NCO1 of DDC0 (band 1). The LSB represents $f_S / (2^{16})$, where f_S is the ADC sampling frequency.

Copyright © 2017, Texas Instruments Incorporated

9.5.13.8 Register 009h (address = 009h), Decimation Filter Page

Figure 139. Register 009h

7	6	5	4	3	2	1	0
DDC0 NCO2 LSB							
R/W-0h							

Table 78. Register 009h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC0 NCO2 MSB	R/W	0h	These bits are the LSB of the NCO frequency word for NCO2 of DDC0 (band 1). The LSB represents f_S / (2^{16}), where f_S is the ADC sampling frequency.

9.5.13.9 Register 00Ah (address = 00Ah), Decimation Filter Page

Figure 140. Register 00Ah

7	6	5	4	3	2	1	0
DDC0 NCO2 MSB							
R/W-0h							

Table 79. Register 00Ah Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC0 NCO2 MSB	R/W	0h	These bits are the MSB of the NCO frequency word for NCO2 of DDC0 (band 1). The LSB represents f_S / (2^{16}), where f_S is the ADC sampling frequency.

9.5.13.10 Register 00Bh (address = 00Bh), Decimation Filter Page

Figure 141. Register 00Bh

7	6	5	4	3	2	1	0
DDC0 NCO3 LSB							
R/W-0h							

Table 80. Register 00Bh Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC0 NCO3 LSB	R/W	0h	These bits are the LSB of the NCO frequency word for NCO3 of DDC0 (band 1). The LSB represents f_S / (2^{16}), where f_S is the ADC sampling frequency.

Copyright © 2017, Texas Instruments Incorporated

9.5.13.11 Register 00Ch (address = 00Ch), Decimation Filter Page

Figure 142. Register 00Ch

7	6	5	4	3	2	1	0
DDC0 NCO3 MSB							
R/W-0h							

Table 81. Register 00Ch Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC0 NCO3 MSB	R/W	0h	These bits are the MSB of the NCO frequency word for NCO3 of DDC0 (band 1). The LSB represents f_S / (2^{16}), where f_S is the ADC sampling frequency.

9.5.13.12 Register 00Dh (address = 00Dh), Decimation Filter Page

Figure 143. Register 00Dh

7	6	5	4	3	2	1	0
DDC1 NCO4 LSB							
R/W-0h							

Table 82. Register 00Dh Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC1 NCO4 LSB	R/W	0h	These bits are the LSB of the NCO frequency word for NCO4 of DDC1 (band 2, only when dual-band mode is enabled). The LSB represents f_S / (2^{16}), where f_S is the ADC sampling frequency.

Copyright © 2017, Texas Instruments Incorporated

9.5.13.13 Register 00Eh (address = 00Eh), Decimation Filter Page

Figure 144. Register 00Eh

7	6	5	4	3	2	1	0
DDC1 NCO4 MSB							
R/W-0h							

Table 83. Register 00Eh Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DDC1 NCO4 MSB	R/W	0h	These bits are the MSB of the NCO frequency word for NCO4 of DDC1 (band 2, only when dual-band mode is enabled). The LSB represents f_S / (2^{16}), where f_S is the ADC sampling frequency.

9.5.13.14 Register 00Fh (address = 00Fh), Decimation Filter Page

Figure 145. Register 00Fh

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	NCO SEL PIN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 84. Register 00Fh Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	NCO SEL PIN	R/W	0h	This bit enables NCO selection through the GPIO pins. 0 = NCO selection through SPI (see address 0h10) 1 = NCO selection through GPIO pins

9.5.13.15 Register 010h (address = 010h), Decimation Filter Page

Figure 146. Register 010h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	NCO SEL	
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	

Table 85. Register 010h Field Descriptions

Bit	Field	Type	Reset	Description
7-2	0	W	0h	Must write 0
1-0	NCO SEL	R/W	0h	These bits enable NCO selection through register setting. 00 = NCO1 selected for DDC 1 01 = NCO2 selected for DDC 1 10 = NCO3 selected for DDC 1

Copyright © 2017, Texas Instruments Incorporated

9.5.13.16 Register 011h (address = 011h), Decimation Filter Page

Figure 147. Register 011h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	LMFC RESET MODE	
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	

Table 86. Register 011h Field Descriptions

Bit	Field	Type	Reset	Description
7-2	0	W	0h	Must write 0
1-0	LMFC RESET MODE	R/W	0h	These bits reset the configuration for all DDCs and NCOs. 00 = All DDCs and NCOs are reset with every LMFC RESET 01 = Reset with first LMFC RESET after DDC start. Afterwards, reset only when analog clock dividers are resynchronized. 10 = Reset with first LMFC RESET after DDC start. Afterwards, whenever analog clock dividers are resynchronized, use two LMFC resets. 11 = Do not use an LMFC reset at all. Reset the DDCs only when a DDC start is asserted and afterwards continue normal operation. Deterministic latency is not ensured.

9.5.13.17 Register 014h (address = 014h), Decimation Filter Page

Figure 148. Register 014h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	DDC0 6DB GAIN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 87. Register 014h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	DDC0 6DB GAIN	R/W	0h	This bit scales the output of DDC0 by 2 (6 dB) to compensate for real-to-complex conversion and image suppression. This scaling does not apply to the high-bandwidth filter path (divide-by-4 and -6); see register 1Fh. 0 = Normal operation 1 = 6-dB digital gain is added

Copyright © 2017, Texas Instruments Incorporated

9.5.13.18 Register 016h (address = 016h), Decimation Filter Page

Figure 149. Register 016h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	DDC1 6DB GAIN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 88. Register 016h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	DDC1 6DB GAIN	R/W	0h	This bit scales the output of DDC0 by 2 (6 dB) to compensate for real-to-complex conversion and image suppression. This scaling does not apply to the high-bandwidth filter path (divide-by-4 and -6); see register 1Fh. 0 = Normal operation 1 = 6-dB digital gain is added

9.5.13.19 Register 01Eh (address = 01Eh), Decimation Filter Page

Figure 150. Register 01Eh

7	6	5	4	3	2	1	0
0	DDC DET LAT			0	0	0	0
W-0h	R/W-0h			W-0h	W-0h	W-0h	W-0h

Table 89. Register 01Eh Field Descriptions

Bit	Field	Type	Reset	Description
7	0	W	0h	Must write 0
6-4	DDC DET LAT	R/W	0h	These bits ensure deterministic latency depending on the decimation setting used; see Table 90.
3-0	0	W	0h	Must write 0

Table 90. DDC DET LAT Bit Settings

SETTING	COMPLEX DECIMATION SETTING
10h	Divide-by-24, -32 complex
20h	Divide-by-16, -18, -20 complex
40h	Divide-by-by 6, -12 complex
50h	Divide-by-4, -8, -9, -10 complex

Copyright © 2017, Texas Instruments Incorporated

9.5.13.20 Register 01Fh (address = 01Fh), Decimation Filter Page

Figure 151. Register 01Fh

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	WBF 6DB GAIN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 91. Register 01Fh Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	WBF 6DB GAIN	R/W	0h	This bit scales the output of the wide bandwidth DDC filter by 2 (6 dB) to compensate for real-to-complex conversion and image suppression. This setting only applies to the high-bandwidth filter path (divide-by-4 and -6). 0 = Normal operation 1 = 6-dB digital gain is added

9.5.13.21 Register 020h (address = 020h), Decimation Filter Page

Figure 152. Register 20h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	ALWAYS WRITE 1
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 92. Register 020h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	ALWAYS WRITE 1	R/W	0h	Always set this bit to 1

9.5.13.22 Register 033h-036h (address = 033h-036h), Decimation Filter Page

Figure 153. Register 033h

7	6	5	4	3	2	1	0
CUSTOM PATTERN1[7:0]							
R/W-0h							

Figure 154. Register 034h

7	6	5	4	3	2	1	0
CUSTOM PATTERN1[15:8]							
R/W-0h							

Figure 155. Register 035h

7	6	5	4	3	2	1	0
CUSTOM PATTERN2[7:0]							
R/W-0h							

Figure 156. Register 036h

7	6	5	4	3	2	1	0
CUSTOM PATTERN2[15:8]							
R/W-0h							

Copyright © 2017, Texas Instruments Incorporated

Table 93. Register 033h-036h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	CUSTOM PATTERN	R/W	0h	These bits set the custom test pattern in address 33h, 34h, 35h, or 36h.

9.5.13.23 Register 037h (address = 037h), Decimation Filter Page

Figure 157. Register 037h

7	6	5	4	3	2	1	0
0	0	0	0	TEST PATTERN SEL			
W-0h	W-0h	W-0h	W-0h	R/W-0h			

Table 94. Register 037h Field Descriptions

Bit	Field	Type	Reset	Description
7-3	0	W	0h	Must write 0
3-0	TEST PATTERN SEL	R/W	0h	These bits select the test pattern output on the channel. 0000 = Normal operation using ADC output data 0001 = Outputs all 0s 0010 = Outputs all 1s 0011 = Outputs toggle pattern: output data are an alternating sequence of 10101010101010 and 01010101010101 0100 = Output digital ramp: output data increment by one LSB every clock cycle from code 0 to 16384 0110 = Single pattern: output data are custom pattern 1 (75h and 76h) 0111 = Double pattern: output data alternate between custom pattern 1 and custom pattern 2 1000 = Deskew pattern: output data are AAAAh 1001 = SYNC pattern: output data are FFFFh

Copyright © 2017, Texas Instruments Incorporated

9.5.13.24 Register 038h (address = 038h), Decimation Filter Page

Figure 158. Register 038h

7	6	5	4	3	2	1	0
TEST PATTERN DDC2 Q-DATA				TEST PATTERN DDC2 I-DATA			
R/W-0h				R/W-0h			

Table 95. Register 038h Field Descriptions

Bit	Field	Type	Reset	Description
7-4	TEST PATTERN DDC2 Q-DATA	R/W	0h	These bits select the test patten for the Q stream of the DDC2. 0000 = Normal operation using ADC output data 0001 = Outputs all 0s 0010 = Outputs all 1s 0011 = Outputs toggle pattern: output data are an alternating sequence of 10101010101010 and 01010101010101 0100 = Output digital ramp: output data increment by one LSB every clock cycle from code 0 to 65535 0110 = Single pattern: output data are a custom pattern 1 (75h and 76h) 0111 Double pattern: output data alternate between custom pattern 1 and custom pattern 2 1000 = Deskew pattern: output data are AAAAh 1001 = SYNC pattern: output data are FFFFh
3-0	TEST PATTERN DDC2 I-DATA	R/W	0h	These bits select the test patten for the I stream of the DDC2. 0000 = Normal operation using ADC output data 0001 = Outputs all 0s 0010 = Outputs all 1s 0011 = Outputs toggle pattern: output data are an alternating sequence of 10101010101010 and 01010101010101 0100 = Output digital ramp: output data increment by one LSB every clock cycle from code 0 to 65535 0110 = Single pattern: output data are a custom pattern 1 (75h and 76h) 0111 Double pattern: output data alternate between custom pattern 1 and custom pattern 2 1000 = Deskew pattern: output data are AAAAh 1001 = SYNC pattern: output data are FFFFh

9.5.13.25 Register 039h (address = 039h), Decimation Filter Page

Figure 159. Register 039h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	USE COMMON TEST PATTERN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 96. Register 039h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	USE COMMON TEST PATTERN	R/W	0h	0 = Each data stream sends test patterns programmed by bits[3:0] of register 37h. 1 = Test patterns are individually programmed for the I and Q stream of each DDC using the TEST PATTERN DDCx y-DATA register bits (where x = 1 or 2 and y = I or Q).

Copyright © 2017, Texas Instruments Incorporated

9.5.13.26 Register 03Ah (address = 03Ah), Decimation Filter Page

Figure 160. Register 03Ah

7	6	5	4	3	2	1	0
0	0	0	0	0	0	TEST PAT RES	TP RES EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h	R/W-0h

Table 97. Register 03Ah Field Descriptions

Bit	Field	Type	Reset	Description
7-2	0	W	0h	Must write 0
1	TEST PAT RES	R/W	0h	Pulsing this bit resets the test pattern. The test pattern reset must be enabled first (bit D0). 0 = Normal operation 1 = Reset the test pattern
0	TP RES EN	R/W	0h	This bit enables the test pattern reset. 0 = Reset disabled 1 = Reset enabled

9.5.14 Power Detector Page

9.5.14.1 Register 000h (address = 000h), Power Detector Page

Figure 161. Register 000h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	PKDET EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 98. Register 000h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	PKDET EN	R/W	0h	This bit enables the peak power and crossing detector. 0 = Power detector disabled 1 = Power detector enabled

Copyright © 2017, Texas Instruments Incorporated

9.5.14.2 Register 001h-002h (address = 001h-002h), Power Detector Page

Figure 162. Register 001h

7	6	5	4	3	2	1	0
BLKPKDET [7:0]							
R/W-0h							

Figure 163. Register 002h

7	6	5	4	3	2	1	0
BLKPKDET [15:8]							
R/W-0h							

Table 99. Register 001h-002h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	BLKPKDET	R/W	0h	This register specifies the block length in terms of number of samples (S`) used for peak power computation. Each sample S` is a peak of 8 actual ADC samples. This parameter is a 17-bit value directly in linear scale. In decimation mode, the block length must be a multiple of a divide-by-4 or -6 complex: length = 5 × decimation factor. The divide-by-8 to -32 complex: length = 10 × decimation factor.

Copyright © 2017, Texas Instruments Incorporated

9.5.14.3 Register 003h (address = 003h), Power Detector Page

Figure 164. Register 003h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	BLKPKDET[16]
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 100. Register 003h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	BLKPKDET[16]	R/W	0h	This register specifies the block length in terms of number of samples (S`) used for peak power computation. Each sample S` is a peak of 8 actual ADC samples. This parameter is a 17-bit value directly in linear scale. In decimation mode, the block length must be a multiple of a divide-by-4 or -6 complex: length = 5 × decimation factor. The divide-by-8 to -32 complex: length = 10 × decimation factor.

9.5.14.4 Register 007h-00Ah (address = 007h-00Ah), Power Detector Page

Figure 165. Register 007h

7	6	5	4	3	2	1	0
BLKTHHH							
R/W-0h							

Figure 166. Register 008h

7	6	5	4	3	2	1	0
BLKTHHL							
R/W-0h							

Figure 167. Register 009h

7	6	5	4	3	2	1	0
BLKTHLH							
R/W-0h							

Figure 168. Register 00Ah

7	6	5	4	3	2	1	0
BLKTHLL							
R/W-0h							

Table 101. Register 007h-00Ah Field Descriptions

Bit	Field	Type	Reset	Description
7-0	BLKTHHH BLKTHHL BLKTHLH BLKTHLL	R/W	0h	These registers set the four different thresholds for the hysteresis function threshold values from 0 to 256 (2TH), where 256 is equivalent to the peak amplitude. Example: BLKTHHH is set to –2 dBFS from peak: $10^{(-2 / 20)} \times 256$ = 203, then set 5407h, 5C07h = CBh.

Copyright © 2017, Texas Instruments Incorporated

9.5.14.5 Register 00Bh-00Ch (address = 00Bh-00Ch), Power Detector Page

Figure 169. Register 00Bh

7	6	5	4	3	2	1	0
DWELL[7:0]							
R/W-0h							

Figure 170. Register 00Ch

7	6	5	4	3	2	1	0
DWELL[15:8]							
R/W-0h							

Table 102. Register 00Bh-00Ch Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DWELL	R/W	0h	DWELL time counter. When the computed block peak crosses the upper thresholds BLKTHHH or BLKTHLH, the peak detector output flags are set. In order to be reset, the computed block peak must remain continuously lower than the lower threshold (BLKTHHL or BLKTHLL) for the period specified by the DWELL value. This threshold is 16 bits, is specified in terms of f_S / 8 clock cycles, and must be set to 0 for the crossing detector. Example: if f_S = 3 GSPS, f_S / 8 = 375 MHz, and DWELL = 0100h then the DWELL time = 2^9 / 375 MHz = 1.36 µs.

9.5.14.6 Register 00Dh (address = 00Dh), Power Detector Page

Figure 171. Register 00Dh

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	FILT0LPSEL
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 103. Register 00Dh Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	FILT0LPSEL	R/W	0h	This bit selects either the block detector output or 2-bit output as the input to the IIR filter. 0 = Use the output of the high comparators (HH and HL) as the input of the IIR filter 1 = Combine the output of the high (HH and HL) and low (LH and LL) comparators to generate a 3-level input to the IIR filter (–1, 0, 1)

Copyright © 2017, Texas Instruments Incorporated

9.5.14.7 Register 00Eh (address = 00Eh), Power Detector Page

Figure 172. Register 00Eh

7	6	5	4	3	2	1	0
0	0	0	0	TIMECONST			
W-0h	W-0h	W-0h	W-0h	R/W-0h			

Table 104. Register 00Eh Field Descriptions

Bit	Field	Type	Reset	Description
7-4	0	W	0h	Must write 0
3-0	TIMECONST	R/W	0h	These bits set the crossing detector time period for N = 0 to 15 as $2^N \times f_S / 8$ clock cycles. The maximum time period is 32768 × $f_S / 8$ clock cycles (approximately 100 µs at 2.6 GSPS).

9.5.14.8 Register 00Fh, 010h-012h, and 016h-019h (address = 00Fh, 010h-012h, and 016h-019h), Power Detector Page

Figure 173. Register 00Fh

7	6	5	4	3	2	1	0
FIL0THH[7:0]							
R/W-0h							

Figure 174. Register 010h

7	6	5	4	3	2	1	0
FIL0THH[15:8]							
R/W-0h							

Figure 175. Register 011h

7	6	5	4	3	2	1	0
FIL0THL[7:0]							
R/W-0h							

Figure 176. Register 012h

7	6	5	4	3	2	1	0
FIL0THL[15:8]							
R/W-0h							

Figure 177. Register 016h

7	6	5	4	3	2	1	0
FIL1THH[7:0]							
R/W-0h							

Figure 178. Register 017h

7	6	5	4	3	2	1	0
FIL1THH[15:8]							
R/W-0h							

Copyright © 2017, Texas Instruments Incorporated

Figure 179. Register 018h

7	6	5	4	3	2	1	0
FIL1THL[7:0]							
R/W-0h							

Figure 180. Register 019h

7	6	5	4	3	2	1	0
FIL1THL[15:8]							
R/W-0h							

Table 105. Register 00Fh, 010h, 011h, 012h, 016h, 017h, 018h, and 019h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	FIL0THH FIL0THL FIL1THH FIL1THL	R/W	0h	Comparison thresholds for the crossing detector counter. This threshold is 16 bits in 2.14 signed notation. A value of 1 (4000h) corresponds to 100% crossings, a value of 0.125 (0800h) corresponds to 12.5% crossings.

9.5.14.9 Register 013h-01Ah (address = 013h-01Ah), Power Detector Page

Figure 181. Register 013h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	IIR0 2BIT EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Figure 182. Register 01Ah

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	IIR1 2BIT EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 106. Register 013h and 01Ah Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	IIR0 2BIT EN IIR1 2BIT EN	R/W	0h	This bit enables 2-bit output format of the IIR0 and IIR1 output comparators. 0 = Selects 1-bit output format 1 = Selects 2-bit output format

Copyright © 2017, Texas Instruments Incorporated

9.5.14.10 Register 01Dh-01Eh (address = 01Dh-01Eh), Power Detector Page

Figure 183. Register 01Dh

7	6	5	4	3	2	1	0
DWELLIIR[7:0]							
R/W-0h							

Figure 184. Register 01Eh

7	6	5	4	3	2	1	0
DWELLIIR[15:8]							
R/W-0h							

Table 107. Register 01Dh-01Eh Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DWELLIIR	R/W	0h	DWELL time counter for the IIR output comparators. When the IIR filter output crosses the upper thresholds FIL0THH or FIL1THH, the IIR peak detector output flags are set. In order to be reset, the output of the IIR filter must remain continuously lower than the lower threshold (FIL0THL or FIL1THL) for the period specified by the DWELLIIR value. This threshold is 16 bits and is specified in terms of f_S / 8 clock cycles. Example: if f_S = 2.6 GSPS, f_S / 8 = 325 MHz, and DWELLIIR = 0100h, then the DWELL time = 2^9 / 325 MHz = 1.57 µs.

9.5.14.11 Register 020h (address = 020h), Power Detector Page

Figure 185. Register 020h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	RMSDET EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 108. Register 020h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	RMSDET EN	R/W	0h	This bit enables the RMS power detector. 0 = Power detector disabled 1 = Power detector enabled

Copyright © 2017, Texas Instruments Incorporated

9.5.14.12 Register 021h (address = 021h), Power Detector Page

Figure 186. Register 021h

7	6	5	4	3	2	1	0
0	0	0	PWRDETACCU				
W-0h	W-0h	W-0h	R/W-0h				

Table 109. Register 021h Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4-0	PWRDETACCU	R/W	0h	These bits program the block length to be used for RMS power computation. The block length is defined in terms of f_S / 8 clocks and can be programmed as 2M, where M = 0 to 16.

9.5.14.13 Register 022h-025h (address = 022h-025h), Power Detector Page

Figure 187. Register 022h

7	6	5	4	3	2	1	0
PWRDETH[7:0]							
R/W-0h							

Figure 188. Register 023h

7	6	5	4	3	2	1	0
PWRDETH[15:8]							
R/W-0h							

Figure 189. Register 024h

7	6	5	4	3	2	1	0
PWRDETL[7:0]							
R/W-0h							

Figure 190. Register 025h

7	6	5	4	3	2	1	0
PWRDETL[15:8]							
R/W-0h							

Table 110. Register 022h-025h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	PWRDETH[15:0] PWRDETL[15:0]	R/W	0h	The computed average power is compared against these high and low thresholds. One LSB of the thresholds represents 1 / 2^{16}. Example: if PWRDETH is set to –14 dBFS from peak, $(10^{(-14 / 20)})^2 \times 2^{16} = 2609$, then set 5422h, 5423h, 5C22h, 5C23h = 0A31h.

Copyright © 2017, Texas Instruments Incorporated

9.5.14.14 Register 027h (address = 027h), Power Detector Page

Figure 191. Register 027h

7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	RMS 2BIT EN
W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	W-0h	R/W-0h

Table 111. Register 027h Field Descriptions

Bit	Field	Type	Reset	Description
7-1	0	W	0h	Must write 0
0	RMS 2BIT EN	R/W	0h	This bit enables 2-bit output format on the RMS output comparators. 0 = Selects 1-bit output format 1 = Selects 2-bit output format

9.5.14.15 Register 02Bh (address = 02Bh), Power Detector Page

Figure 192. Register 02Bh

7	6	5	4	3	2	1	0
0	0	0	RESET AGC	0	0	0	0
W-0h	W-0h	W-0h	R/W-0h	W-0h	W-0h	W-0h	W-0h

Table 112. Register 02Bh Field Descriptions

Bit	Field	Type	Reset	Description
7-5	0	W	0h	Must write 0
4	RESET AGC	R/W	0h	After configuration, the AGC module must be reset and then brought out of reset to start operation. 0 = Clear AGC reset 1 = Set AGC reset Example: set 542Bh to 10h and then to 00h.
3-0	0	W	0h	Must write 0

Copyright © 2017, Texas Instruments Incorporated

9.5.14.16 Register 037h (address = 037h), Power Detector Page

Figure 193. Register 037h

7	6	5	4	3	2	1	0
0	0	0	0	IODIR GPIO4	IODIR GPIO3	IODIR GPIO2	IODIR GPIO1
W-0h	W-0h	W-0h	W-0h	R/W-0h	R/W-0h	R/W-0h	R/W-0h

Table 113. Register 037h Field Descriptions

Bit	Field	Type	Reset	Description
7-4	0	W	0h	Must write 0
3-0	IODIRGPIO[4:1]	R/W	0h	These bits select the output direction for the GPIO[4:1] pins. 0 = Input (for the NCO control) 1 = Output (for the AGC alarm function)

9.5.14.17 Register 038h (address = 038h), Power Detector Page

Figure 194. Register 038h

7	6	5	4	3	2	1	0
0	0	INSEL1		0	0	INSEL0	
W-0h	W-0h	R/W-0h		R/W-0h	R/W-0h	R/W-0h	

Table 114. Register 038h Field Descriptions

Bit	Field	Type	Reset	Description
7-6	0	W	0h	Must write 0
5-4	INSEL1	R/W	0h	These bits select which GPIO pin is used for the INSEL1 bit. 00 = GPIO4 01 = GPIO1 10 = GPIO3 11 = GPIO2 See the *NCO Switching* section for details.
3-2	0	W	0h	Must write 0
1-0	INSEL0	R/W	0h	These bits select which GPIO pin is used for the INSEL0 bit. 00 = GPIO4 01 = GPIO1 10 = GPIO3 11 = GPIO2 See the *NCO Switching* section for details.

Copyright © 2017, Texas Instruments Incorporated

9.5.14.18 Power Detector Page (Direct Addressing, 16-Bit Address, 5400h)

9.5.14.18.1 Register 032h-035h (address = 032h-035h), Power Detector Page

Figure 195. Register 032h

7	6	5	4	3	2	1	0
OUTSEL GPIO1							
R/W-0h							

Figure 196. Register 033h

7	6	5	4	3	2	1	0
OUTSEL GPIO2							
R/W-0h							

Figure 197. Register 034h

7	6	5	4	3	2	1	0
OUTSEL GPIO3							
R/W-0h							

Figure 198. Register 035h

7	6	5	4	3	2	1	0
OUTSEL GPIO4							
R/W-0h							

Table 115. Register 032h-035h Field Descriptions

Bit	Field	Type	Reset	Description
7-0	OUTSEL GPIOx	R/W	0h	These bits set the function or signal for each GPIO pin. 0 = IIR PK DET0[0] of channel A 1 = IIR PK DET0[1] of channel A (2-bit mode) 2 = IIR PK DET1[0] of channel A 3 = IIR PK DET1[1] of channel A (2-bit mode) 4 = BLKPKDETH of channel A 5 = BLKPKDETL of channel A 6 = PWR Det[0] of channel A 7 = PWR Det[1] of channel A (2-bit mode) 8 = FOVR of channel A 9-17 = Repeat outputs 0-8 but for channel B instead

Copyright © 2017, Texas Instruments Incorporated

10 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

10.1 Application Information

10.1.1 Start-Up Sequence

The steps in Table 116 are recommended as the power-up sequence when the ADC32RF42 is in bypass mode with a 12-bit output (LMFS = 42810).

Table 116. Initialization Sequence

STEP	DESCRIPTION	PAGE, REGISTER ADDRESS AND DATA	COMMENT
1	Supply all supply voltages. There is no required power-supply sequence for the 1.15 V, 1.2 V, and 1.9 V supplies, and can be supplied in any order.	—	—
2	Provide the SYSREF signal.	—	—
3	Pulse a hardware reset (low-to-high-to-low) on pin 48.	—	—
4	Write the register addresses described in the *PowerUpConfig* file.	See the files located in SBAA226	The *Power-up config* file contains analog trim registers that are required for best performance of the ADC. Write these registers every time after power up.
5	Write the register addresses mentioned in the ILConfigNyqX_ChA file, where x is the Nyquist zone.	See the files located in SBAA226	Based on the signal band of interest, provide the Nyquist zone information to the device.
6	Write the register addresses mentioned in the ILConfigNyqX_ChB file, where x is the Nyquist zone.	See the files located in SBAA226	This step optimizes device' performance by reducing interleaving mismatch errors.
6.1	Wait for 50 ms for the device to estimate the interleaving errors.	—	—
7	Depending upon the Nyquist band of operation, choose and write the registers from the appropriate file, *NLConfigNyqX_ChA*, where x is the Nyquist zone.	See the files located in SBAA226	Third-order nonlinearity of the device is optimized by this step for channel A.
7.1	Depending upon the Nyquist band of operation, choose and write the registers from the appropriate file, *NLConfigNyqX_ChB*, where x is the Nyquist zone.	See the files located in SBAA226	Third-order nonlinearity of the device is optimized by this step for channel B.
8	Configure the JESD interface and DDC block by writing the registers mentioned in the *DDC Config* file.	See the files located in SBAA226	Determine the DDC and JESD interface LMFS options. Program these options in this step.

Copyright © 2017, Texas Instruments Incorporated

10.1.2 Hardware Reset

Figure 199 and Table 117 show timing information for the hardware reset.

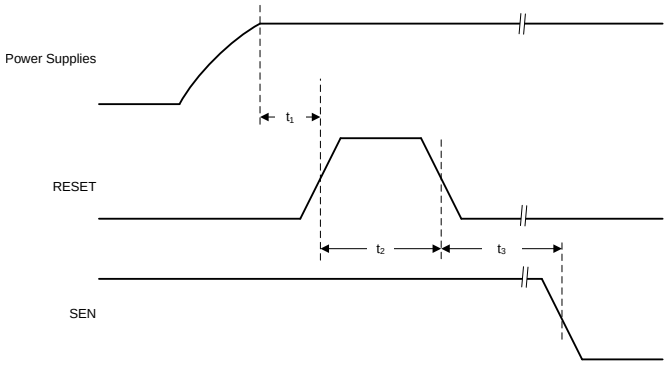


Figure 199. Hardware Reset Timing Diagram

Table 117. Hardware Reset Timing Information

		MIN	TYP	MAX	UNIT
t_1	Power-on delay from power-up to active high RESET pulse	1			ms
t_2	Reset pulse duration: active high RESET pulse duration	1			µs
t_3	Register write delay from RESET disable to SEN active	100			ns

Copyright © 2017, Texas Instruments Incorporated

10.1.3 SNR and Clock Jitter

The signal-to-noise ratio (SNR) of the ADC is limited by three different factors, as shown in Equation 5: quantization noise, thermal noise, and jitter. The quantization noise is typically not noticeable in pipeline converters and is 84 dB for a 14-bit ADC. The thermal noise limits the SNR at low input frequencies and the clock jitter sets the SNR for higher input frequencies.

$$SNRADC\left[dBc\right] = -20\log\sqrt{\left(10^{-\frac{SNR_{Quantization\ Noise}}{20}}\right)^2 + \left(10^{-\frac{SNR_{Thermal\ Noise}}{20}}\right)^2 + \left(10^{-\frac{SNR_{Jitter}}{20}}\right)^2} \quad (5)$$

Equation 6 calculates the SNR limitation resulting from sample clock jitte:

$$SNR_{Jitter}\left[dBc\right] = -20\log\left(2\pi \times f_{IN} \times t_{Jitter}\right) \quad (6)$$

The total clock jitter (T_{Jitter}) has two components: the internal aperture jitter (90 f_S) is set by the noise of the clock input buffer and the external clock jitter. Use Equation 7 to calculate T_{Jitter}:

$$t_{Jitter} = \sqrt{\left(t_{Jitter,\ Ext_Clock_Input}\right)^2 + \left(t_{Aperture_ADC}\right)^2} \quad (7)$$

External clock jitter can be minimized by using high-quality clock sources and jitter cleaners as well as band-pass filters at the clock input. A faster clock slew rate also improves the ADC aperture jitter.

The ADC32RF42 has a thermal noise of approximately 63 dBFS and an internal aperture jitter of 90 f_S. Figure 200 shows an SNR plot with various amounts of external jitter for different input frequencies.

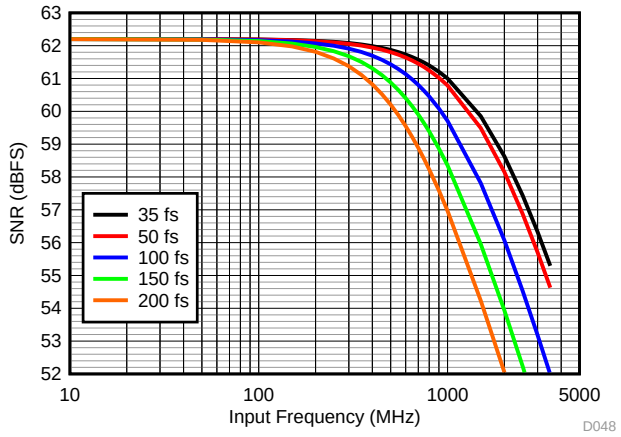


Figure 200. ADC SNR vs Input Frequency and External Clock Jitter

Copyright © 2017, Texas Instruments Incorporated

10.1.3.1 External Clock Phase Noise Consideration

Figure 201 shows how external clock jitter can be calculated by integrating the phase noise of the clock source out to approximately two times of the ADC sampling rate ($2 \times f_S$). In order to maximize the ADC SNR, an external band-pass filter is recommended to be used on the clock input. This filter reduces the jitter contribution from the broadband clock phase noise floor by effectively reducing the integration bandwidth to the pass band of the band-pass filter. This method is suitable when estimating the overall ADC SNR resulting from clock jitter at a certain input frequency.

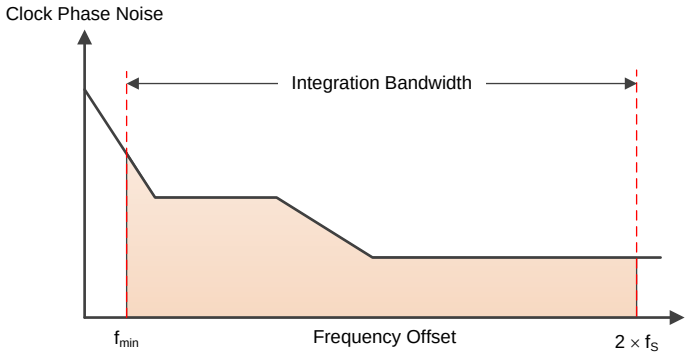


Figure 201. Integration Bandwidth for Extracting Jitter from Clock Phase Noise

However, as shown in Figure 202, when estimating the affect of a nearby blocker (such as a strong in-band interferer to the sensitivity), the phase noise information can be used directly to estimate the noise budget contribution at a certain offset frequency.

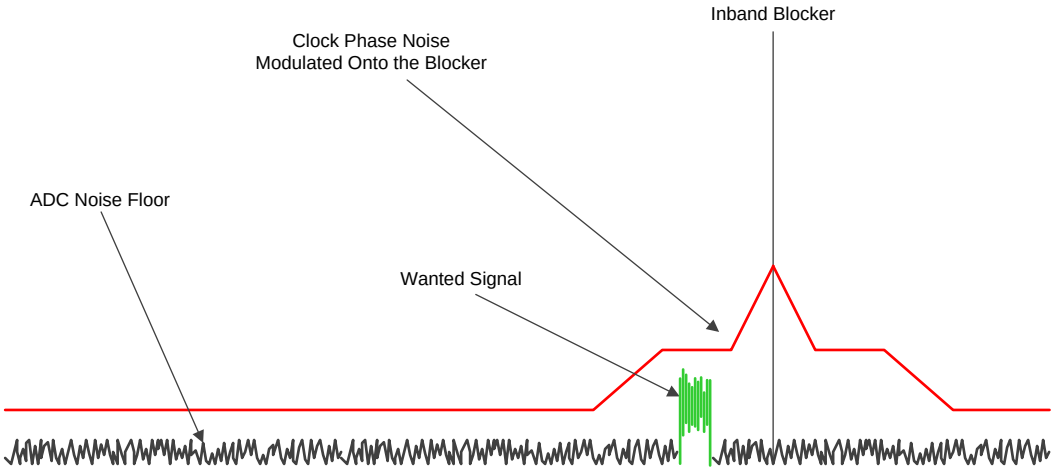


Figure 202. Small Wanted Signal in Presence of Interferer

At the sampling instant, the phase noise profile of the clock source convolves with the input signal (for example, the small wanted signal and the strong interferer merge together). If the power of the clock phase noise in the signal band of interest is too large, the wanted signal cannot not be recovered.

The resulting equivalent phase noise at the ADC input is also dependent on the sampling rate of the ADC and frequency of the input signal. Equation 8 describes how the ADC sampling rate scales the clock phase noise.

$$ADC_{NSD}\left(dBc / Hz\right) = PN_{CLK}\left(dBc / Hz\right) - 20 \times \log\left(\frac{f_S}{f_{IN}}\right) \quad (8)$$

Using this information, the noise contribution resulting from the phase noise profile of the ADC sampling clock can be calculated.

Copyright © 2017, Texas Instruments Incorporated

10.1.4 Power Consumption in Different Modes

The ADC32RF42 consumes approximately 4.01 W of power when both channels are active with a 12-bit, 1.5-GSPS output and a DDC option is not used (bypass mode). When different DDC options are used, the power consumption on the DVDD supply changes by a small amount but remains unaffected on other supplies. In the applications requiring just one channel to be active, channel A must be chosen as the active channel and channel B can be powered down. Power consumption reduces to approximately 2.66 W in single-channel operation with a 12-bit, 1.5-GSPS output (bypass mode).

Table 118 shows power consumption in different DDC modes for dual-channel and single-channel operation.

Table 118. Power Consumption in Different DDC Modes

DECIMATION OPTION	ACTIVE CHANNEL	ACTIVE DDC	AVDD1P9 (mA)	AVDD1P2 (mA)	DVDD1P2 (mA)	TOTAL POWER (mW)
Bypass mode	Channel A, B	NA	1150	604	1000	4029.6
Divide-by-4	Channel A, B	Single	1150	604	1148	4199.8
Divide-by-8	Channel A, B	Dual	1142	602	1236	4283.5
Divide-by-8	Channel A, B	Single	1142	601	1025	4039.7
Divide-by-16	Channel A, B	Dual	1142	601	1000	4010.95
Divide-by-16	Channel A, B	Single	1142	599	984	3990.25
Bypass mode	Channel A	NA	631	588	680	2657.1
Divide-by-4	Channel A	Single	630	570	738	2701.2
Divide-by-8	Channel A	Dual	627	568	806	2771.4
Divide-by-8	Channel A	Single	627	561	690	2629.95
Divide-by-16	Channel A	Dual	627	568	770	2730
Divide-by-16	Channel A	Single	627	561	669	2605.8

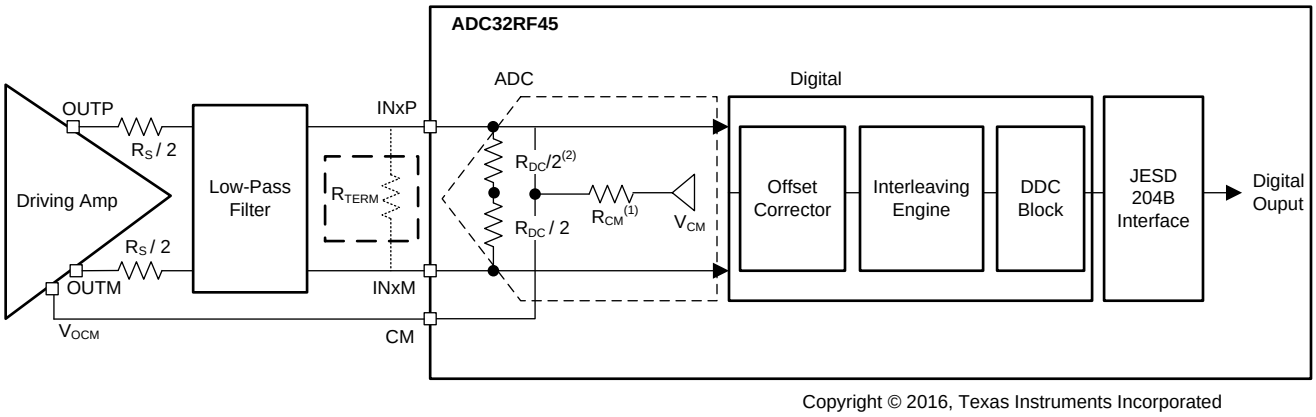
Copyright © 2017, Texas Instruments Incorporated

10.1.5 Using DC Coupling in the ADC32RF42

The ADC32RF42 can be used in dc-coupling applications. However, the following points must be considered when designing the system:

1. Ensure that the correct common-mode voltage is used at the ADC analog inputs.

   The analog inputs are internally self-biased to V_{CM} through approximately a 33-Ω resistor. The internal biasing resistors also function as a termination resistor. However, if a different termination is required as shown in Figure 203, the external resistor R_{TERM} can be differentially placed between the analog inputs. The amplifier V_{OCM} pin is recommended to be driven from the CM pin of the ADC to help the amplifier output common-mode voltage track the required common-mode voltage of the ADC.



Copyright © 2016, Texas Instruments Incorporated

Set the INCR CM IMPEDANCE bit to increase the RCM from 0 Ω to > 5000 Ω.

R_{DC} is approximately 65 Ω.

Figure 203. The ADC32RF42 in a DC-Coupling Application

2. Ensure that the correct SPI settings are written to the ADC.

   As shown in Figure 204, the ADC32RF42 has a digital block that estimates and corrects the offset mismatch among four interleaving ADC cores for a given channel.

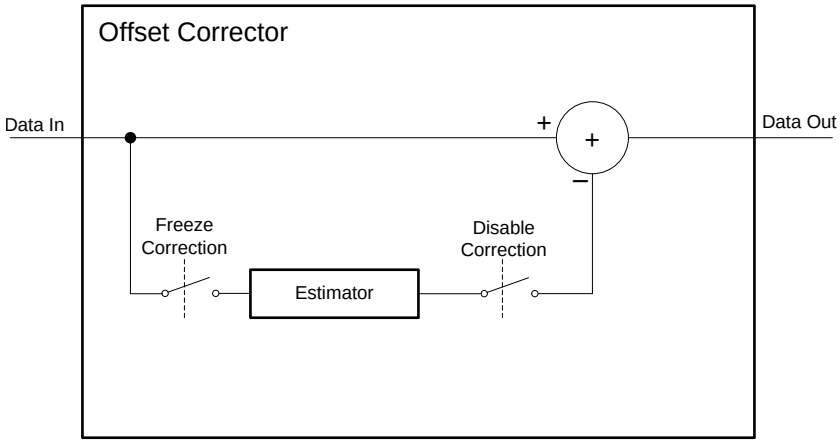


Figure 204. Offset Corrector in the ADC32RF42

The offset corrector block nullifies dc, f_S / 8, f_S / 4, 3 f_S / 8, and f_S / 2. The resulting spectrum becomes free from static spurs at these frequencies. The corrector continuously processes the data coming from the interleaving ADC cores and cannot distinguish if the tone at these frequencies is part of signal or if the tone originated from a mismatch among the interleaving ADC cores. Thus, in applications where the signal is present at these frequencies, the offset corrector block can be bypassed.

10.1.5.1 Bypassing the Offset Corrector Block

When the offset corrector is bypassed, offset mismatch among interleaving ADC cores appears in the ADC output spectrum. To correct the effects of mismatch, place the ADC in an idle channel state (no signal at the ADC inputs) and the corrector must be allowed to run for some time to estimate the mismatch, then the corrector is frozen so that the last estimated value is held. Table 119 provides the required register writes.

Table 119. Freezing and Bypassing the Offset Corrector Block

STEP	REGISTER WRITE	COMMENT
STEPS FOR FREEZING THE CORRECTOR BLOCK		
1	—	Signal source is turned off. The device detects an idle channel at its input.
2	—	Wait for at least 0.4 ms for the corrector to estimate the internal offset
3	Address 4001h, value 00h	Select Offset Corr Page Channel A
	Address 4002h, value 00h	
	Address 4003h, value 00h	
	Address 4004h, value 61h	
	Address 6068h, value C2h	Freeze the corrector for channel A
	Address 4003h, value 01h	Select Offset Corr Page Channel B
	Address 6068h, value C2h	Freeze the corrector for channel B
4	—	Signal source can now be turned on
STEPS FOR BYPASSING THE CORRECTOR BLOCK		
1	Address 4001h, value 00h	—
	Address 4002h, value 00h	
	Address 4003h, value 00h	
	Address 4004h, value 61h	Select Offset Corr Page Channel A
	Address 6068h, value 46h	Disable the corrector for channel A
	Address 4003h, value 01h	Select Offset Corr Page Channel B
	Address 6068h, value 46h	Disable the corrector for channel B

10.1.5.1.1 Effect of Temperature

Figure 205 and Figure 206 show the behavior of nf_S / 8 tones with respect to temperature when the offset corrector block is frozen or disabled.

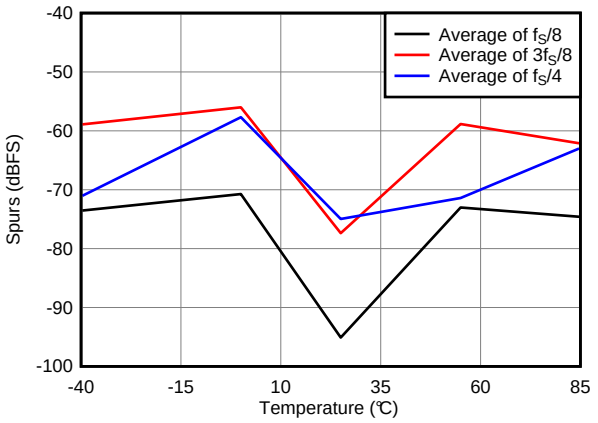


Figure 205. Offset Corrector Block Frozen at Room Temperature

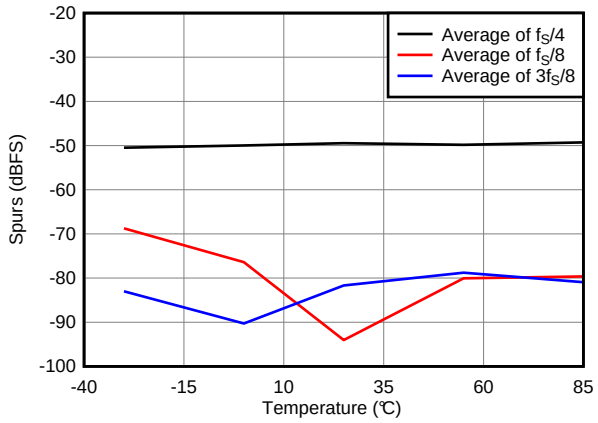


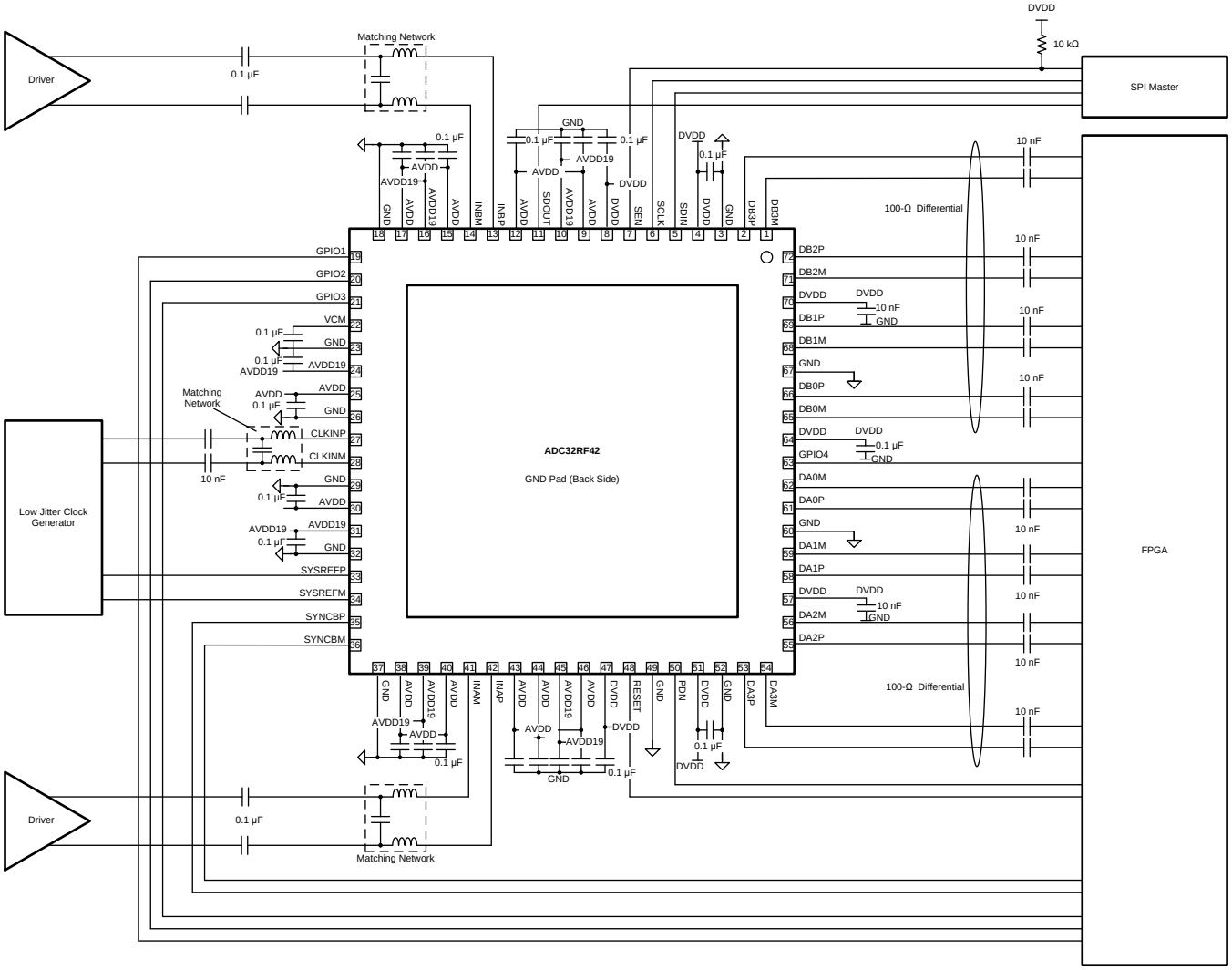
Figure 206. Offset Corrector Block Disabled

Copyright © 2017, Texas Instruments Incorporated

10.2 Typical Application

The ADC32RF42 is designed for wideband receiver applications demanding high dynamic range over a large input frequency range. Figure 207 shows a typical schematic for an ac-coupled receiver.

Decoupling capacitors with low ESL are recommended to be placed as close as possible at the pins indicated in Figure 207. Additional capacitors can be placed on the remaining power pins.



Copyright © 2017, Texas Instruments Incorporated

Figure 207. Typical Application Implementation Diagram

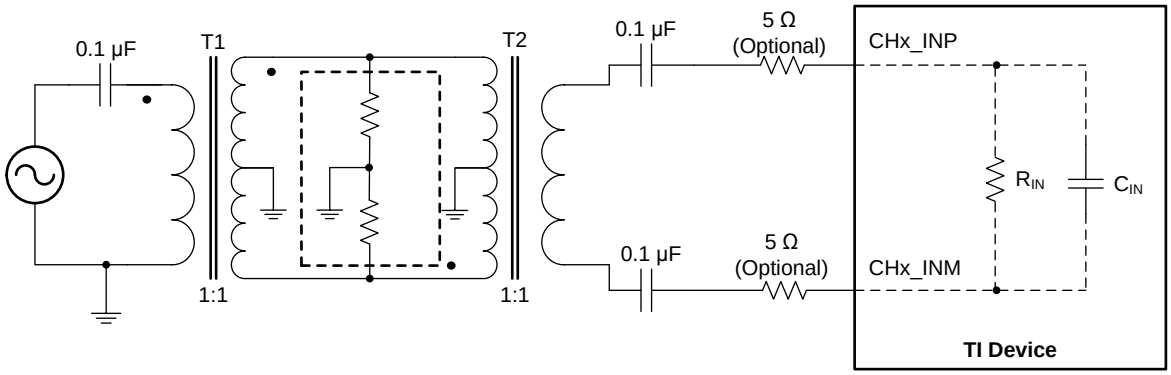
Typical Application (continued)

10.2.1 Design Requirements

10.2.1.1 Transformer-Coupled Circuits

Typical applications involving transformer-coupled circuits are discussed in this section. To ensure good amplitude and phase balance at the analog inputs, transformers (such as TC1-1-13 and TC1-1-43) can be used from the dc to 1000-MHz range and from the 1000-MHz to 4-GHz range of input frequencies, respectively. When designing the driving circuits, the ADC input impedance (or $S_{DD}11$) must be considered.

By using the simple drive circuit of Figure 208, uniform performance can be obtained over a wide frequency range. The buffers present at the analog inputs of the device help isolate the external drive source from the switching currents of the sampling circuit.



Copyright © 2016, Texas Instruments Incorporated

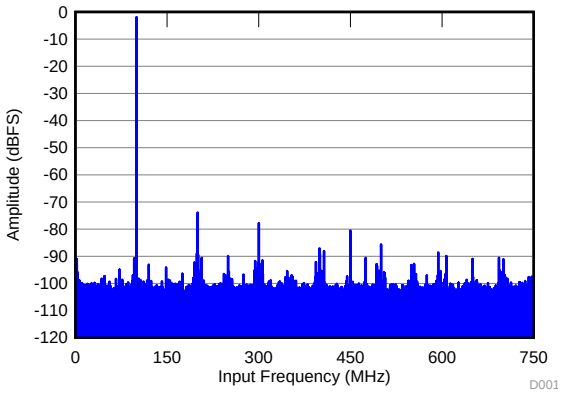
Figure 208. Input Drive Circuit

10.2.2 Detailed Design Procedure

For optimum performance, the analog inputs must be driven differentially. This architecture improves common-mode noise immunity and even-order harmonic rejection. As shown in Figure 208, a small resistor (5 Ω to 10 Ω) in series with each input pin is recommended to damp out ringing caused by package parasitics.

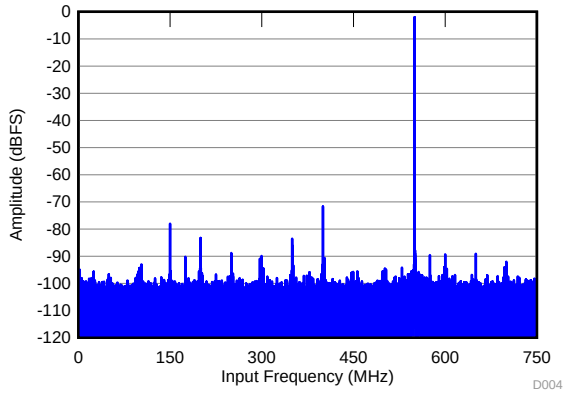
10.2.3 Application Curves

Figure 209 and Figure 210 show the typical performance at 100 MHz and 1850 MHz, respectively.



SFDR = 73 dBc, SNR = 62.4 dBFS,
SINAD = 62 dBFS, THD = 71 dBc,
HD2 = –75 dBFS, HD3 = –78 dBFS,
SFDR (non HD2, HD3) = 85 dBc, IL spur = 81 dBFS

Figure 209. FFT for 100-MHz Input Frequency



SFDR = 70 dBc, SNR = 60.8 dBFS,
SINAD = 60 dBFS, THD = 69 dBc,
HD2 = –72 dBFS, HD3 = –78 dBFS,
SFDR (non HD2, HD3) = 81 dBc, IL spur = 82 dBFS

Figure 210. FFT for 950-MHz Input Frequency

Copyright © 2017, Texas Instruments Incorporated

11 Power Supply Recommendations

Figure 211 shows that the DVDD power supply (1.15 V) must be stable before ramping up the AVDD19 supply (1.9 V). The AVDD supply (1.15 V) can come up in any order during the power sequence. The power supplies can ramp up at any rate and there is no hard requirement for the time delay between DVDD (1.15 V) ramping up to AVDD (1.9 V) ramping up (which can be in orders of microseconds but is recommended to be a few milliseconds).

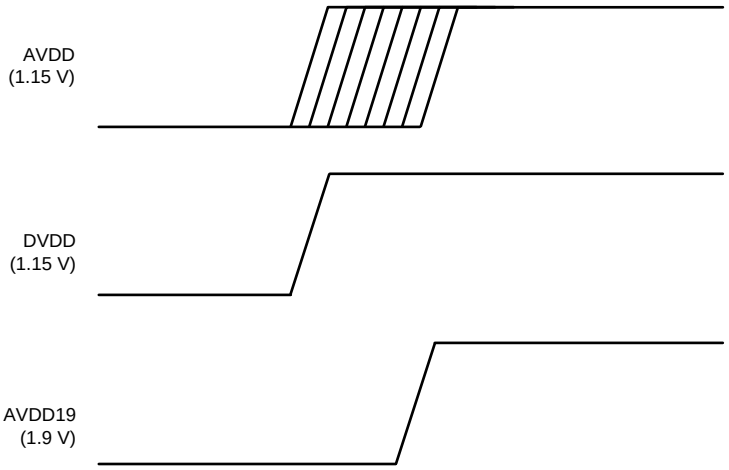


Figure 211. Power Sequencing for the ADC32RF8x Family of Devices

12 Layout

12.1 Layout Guidelines

The device evaluation module (EVM) layout can be used as a reference layout to obtain the best performance. A layout diagram of the EVM top layer is provided in Figure 212. The *ADC32RF45/RF80 EVM Quick Startup Guide* provides a complete layout of the EVM. Some important points to remember during board layout are:

- Analog inputs are located on opposite sides of the device pinout to ensure minimum crosstalk on the package level. To minimize crosstalk onboard, the analog inputs must exit the pinout in opposite directions, as shown in the reference layout of Figure 212 as much as possible.
- In the device pinout, the sampling clock is located on a side perpendicular to the analog inputs in order to minimize coupling. This configuration is also maintained on the reference layout of Figure 212 as much as possible.
- Keep digital outputs away from the analog inputs. When these digital outputs exit the pinout, the digital output traces must not be kept parallel to the analog input traces because this configuration can result in coupling from the digital outputs to the analog inputs and degrade performance. All digital output traces to the receiver [such as field-programmable gate arrays (FPGAs) or application-specific integrated circuits (ASICs)] must be matched in length to avoid skew among outputs.
- At each power-supply pin (AVDD, DVDD, or AVDD19), keep a 0.1-µF decoupling capacitor close to the device. A separate decoupling capacitor group consisting of a parallel combination of 10-µF, 1-µF, and 0.1-µF capacitors can be kept close to the supply source.

Copyright © 2017, Texas Instruments Incorporated

12.2 Layout Example

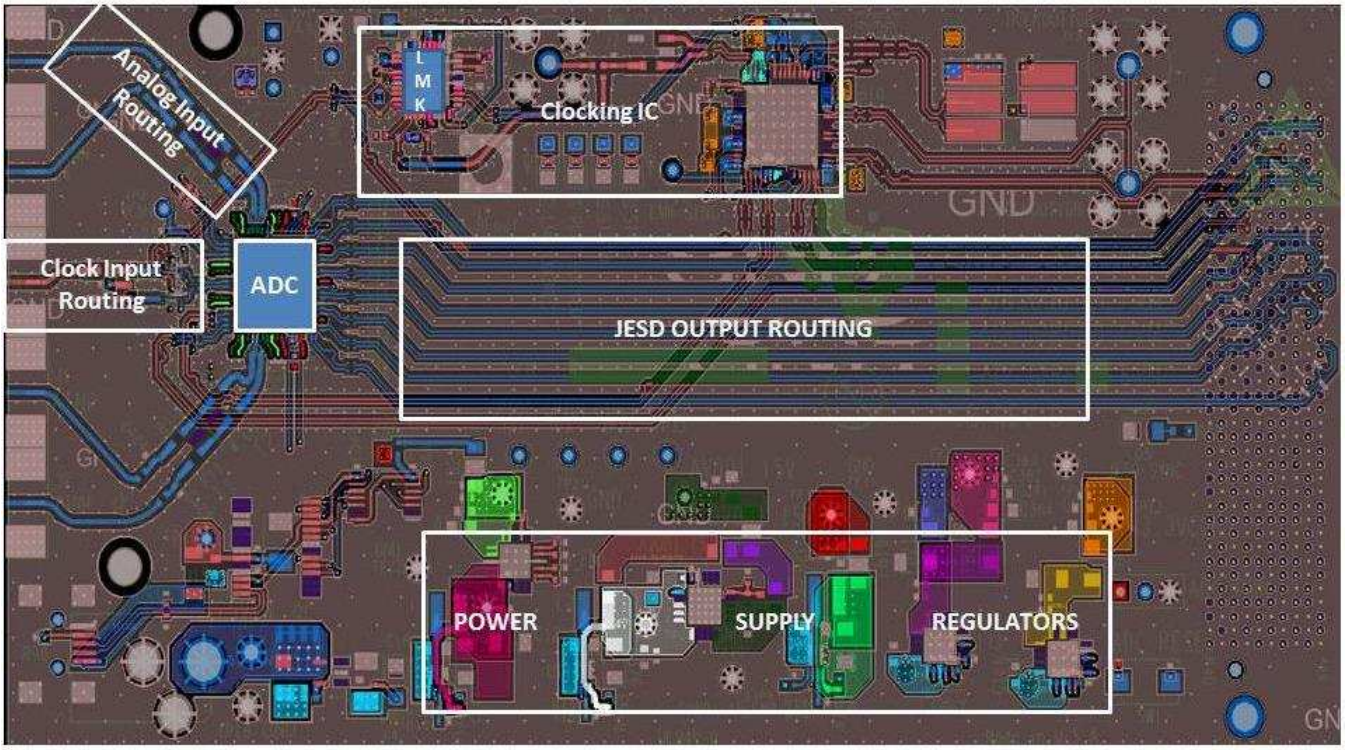


Figure 212. ADC32RF42EVM Layout

Copyright © 2017, Texas Instruments Incorporated

13 デバイスおよびドキュメントのサポート

13.1 ドキュメントのサポート

13.1.1 関連資料

関連資料については、以下を参照してください：

- 『ADC32RF45/RF80 EVMクイック・スタートアップ・ガイド』
- 『ADC32RF45用の構成ファイル』

13.2 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、ti.comのデバイス製品フォルダを開いてください。右上の隅にある「*通知を受け取る*」をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取れます。変更の詳細については、修正されたドキュメントに含まれている改訂履歴をご覧ください。

13.3 コミュニティ・リソース

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™オンライン・コミュニティ ***TIのE2E（Engineer-to-Engineer）コミュニティ。*** **エンジニア間の共同作業を促進するために開設されたものです。**e2e.ti.com**では、他のエンジニアに質問し、知識を共有し、アイディアを検討して、問題解決に役立てることができます。**

設計サポート ***TIの設計サポート*** **役に立つ**E2E**フォーラムや、設計サポート・ツールをすばやく見つけることができます。技術サポート用の連絡先情報も参照できます。**

13.4 商標

E2E is a trademark of Texas Instruments.
All other trademarks are the property of their respective owners.

13.5 静電気放電に関する注意事項



すべての集積回路は、適切なESD保護方法を用いて、取扱いと保存を行うようにして下さい。

静電気放電はわずかな性能の低下から完全なデバイスの故障に至るまで、様々な損傷を与えます。高精度の集積回路は、損傷に対して敏感であり、極めてわずかなパラメータの変化により、デバイスに規定された仕様に適合しなくなる場合があります。

13.6 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

14 メカニカル、パッケージ、および注文情報

以降のページには、メカニカル、パッケージ、および注文に関する情報が記載されています。この情報は、そのデバイスについて利用可能な最新のデータです。このデータは予告なく変更されることがあり、ドキュメントが改訂される場合もあります。本データシートのブラウザ版を使用されている場合は、画面左側の説明をご覧ください。

Copyright © 2017, Texas Instruments Incorporated

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
ADC32RF42IRMP	Active	Production	VQFN (RMP) | 72	168 | JEDEC TRAY (5+1)	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 85	AZ32RF42
ADC32RF42IRMP.A	Active	Production	VQFN (RMP) | 72	168 | JEDEC TRAY (5+1)	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 85	AZ32RF42
ADC32RF42IRMPG4	Active	Production	VQFN (RMP) | 72	168 | JEDEC TRAY (5+1)	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 85	AZ32RF42
ADC32RF42IRMPG4.A	Active	Production	VQFN (RMP) | 72	168 | JEDEC TRAY (5+1)	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 85	AZ32RF42
ADC32RF42IRMPT	Active	Production	VQFN (RMP) | 72	250 | SMALL T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 85	AZ32RF42
ADC32RF42IRMPT.A	Active	Production	VQFN (RMP) | 72	250 | SMALL T&R	Yes	NIPDAU	Level-3-260C-168 HR	-40 to 85	AZ32RF42

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative

and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

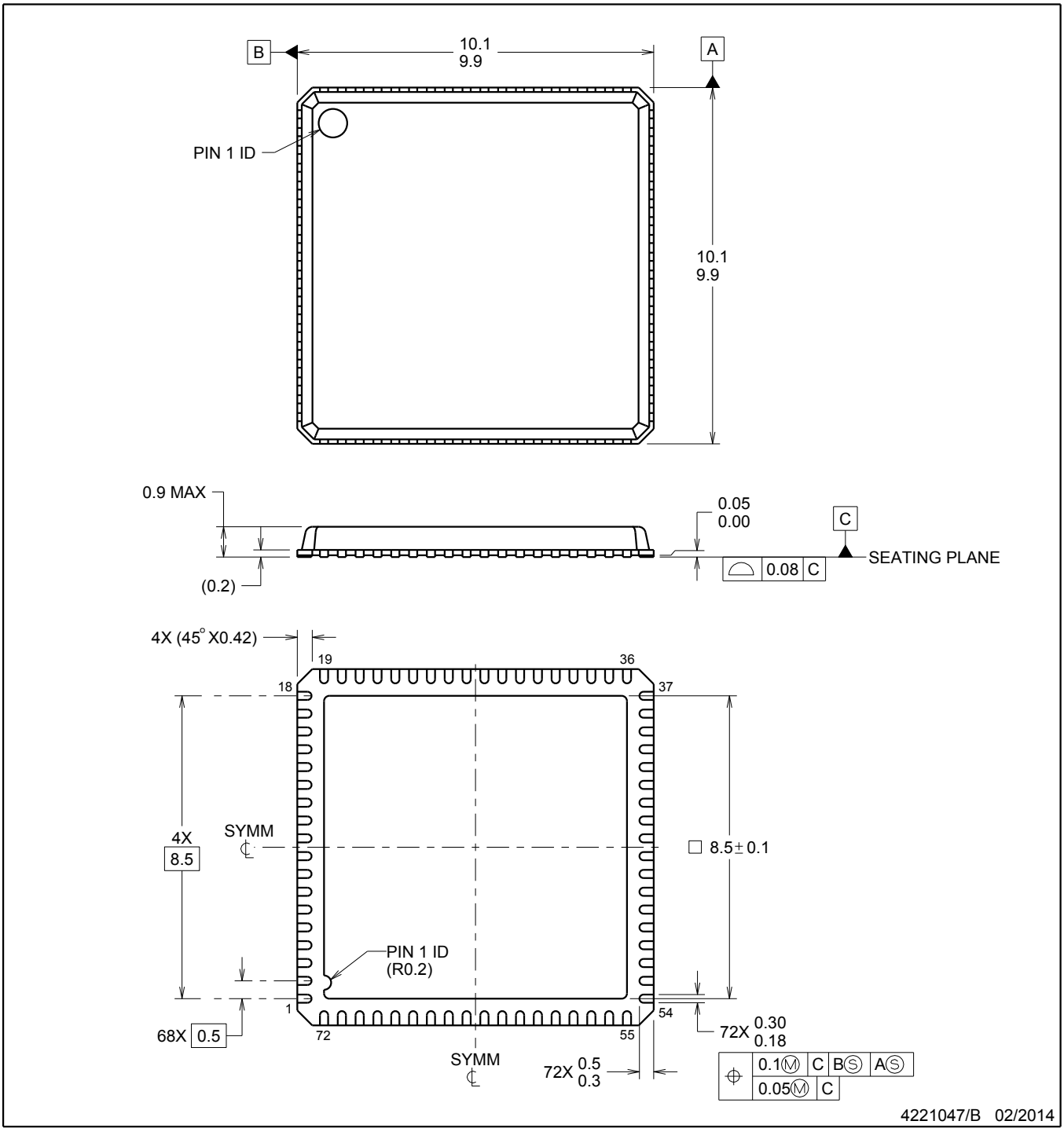
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE OUTLINE

RMP0072A

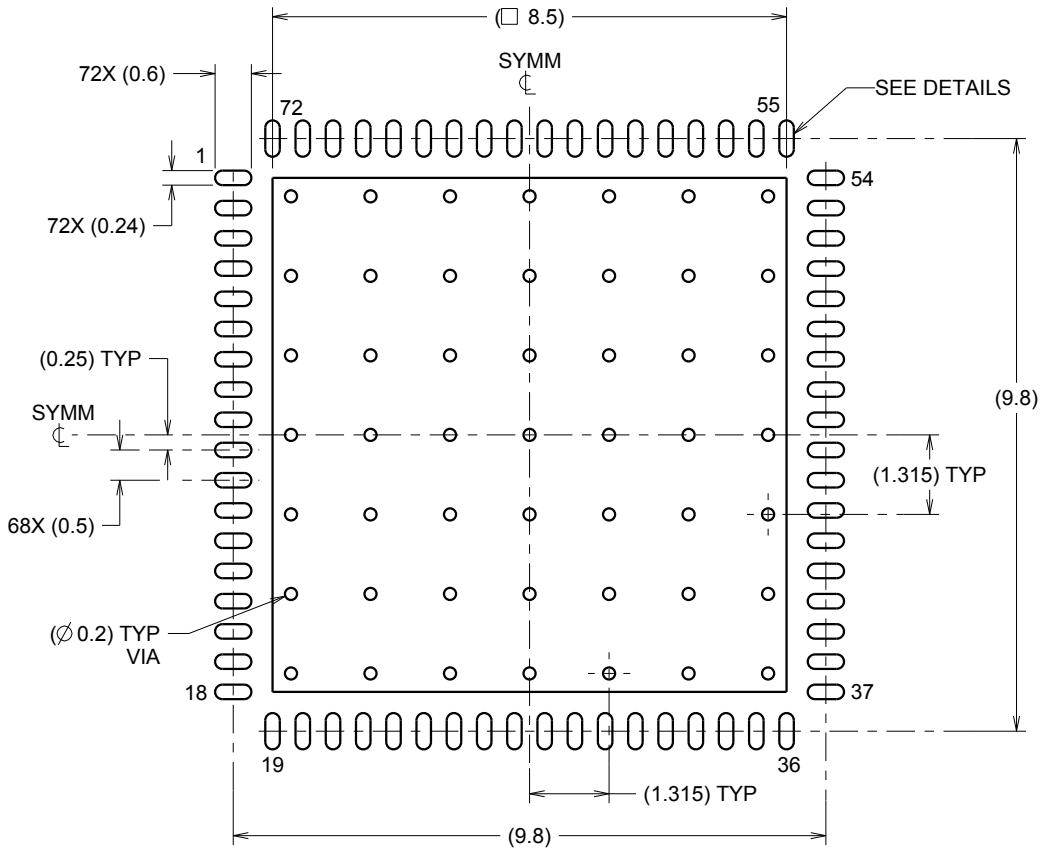
VQFN - 0.9 mm max height

VQFN

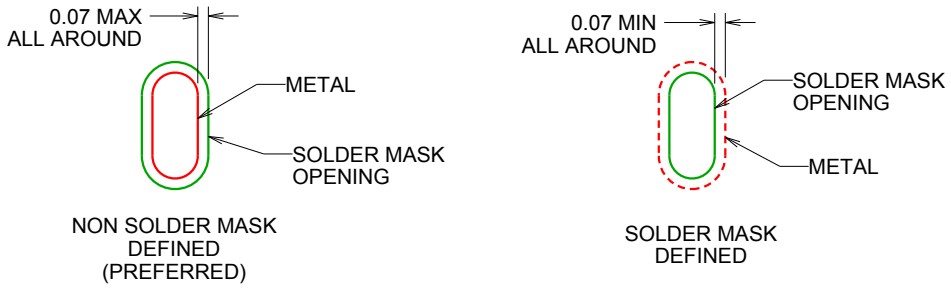


NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



LAND PATTERN EXAMPLE
SCALE:8X

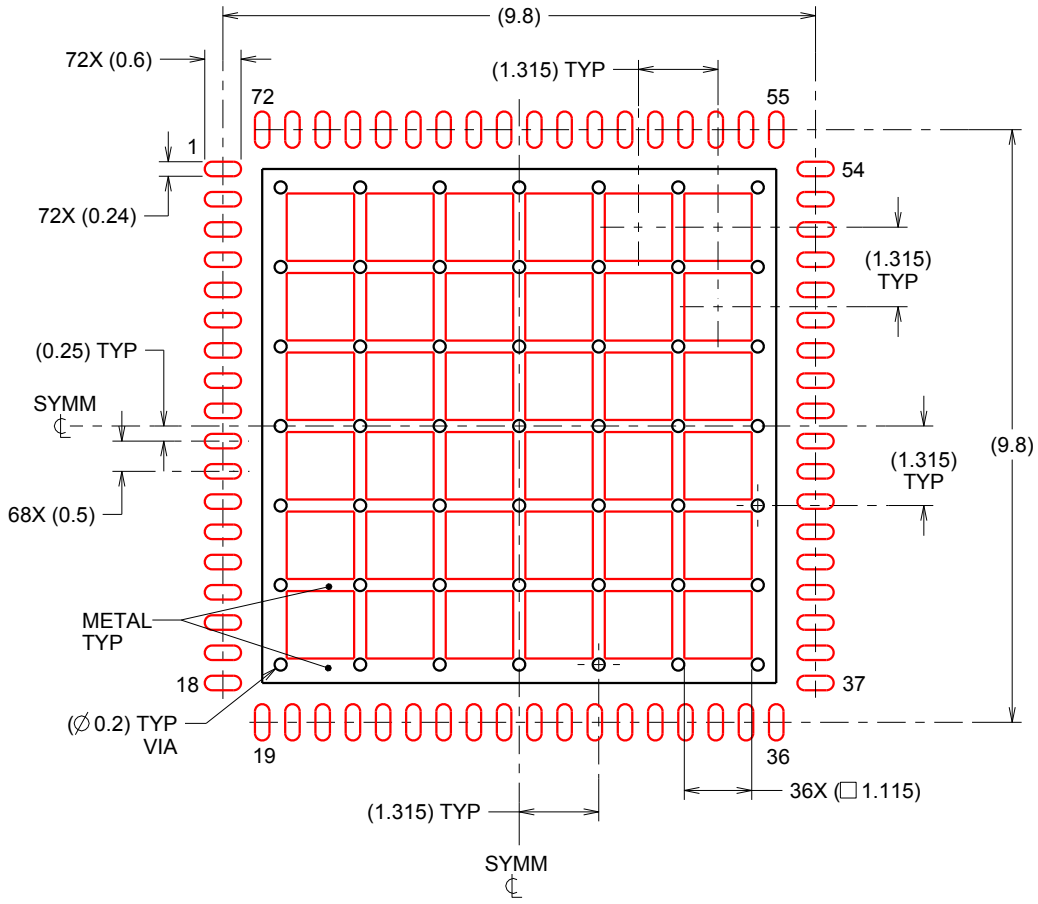


SOLDER MASK DETAILS

4221047/B 02/2014

NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see QFN/SON PCB application report in literature No. SLUA271 (www.ti.com/lit/slua271).



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL

EXPOSED PAD
62% PRINTED SOLDER COVERAGE BY AREA
SCALE:8X

4221047/B 02/2014

NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

重要なお知らせと免責事項

TI は、技術データと信頼性データ (データシートを含みます)、設計リソース (リファレンス デザインを含みます)、アプリケーションや設計に関する各種アドバイス、Web ツール、安全性情報、その他のリソースを、欠陥が存在する可能性のある「現状のまま」提供しており、商品性および特定目的に対する適合性の黙示保証、第三者の知的財産権の非侵害保証を含むいかなる保証も、明示的または黙示的にかかわらず拒否します。

これらのリソースは、TI 製品を使用する設計の経験を積んだ開発者への提供を意図したものです。(1) お客様のアプリケーションに適した TI 製品の選定、(2) お客様のアプリケーションの設計、検証、試験、(3) お客様のアプリケーションに該当する各種規格や、その他のあらゆる安全性、セキュリティ、規制、または他の要件への確実な適合に関する責任を、お客様のみが単独で負うものとします。

上記の各種リソースは、予告なく変更される可能性があります。これらのリソースは、リソースで説明されている TI 製品を使用するアプリケーションの開発の目的でのみ、TI はその使用をお客様に許諾します。これらのリソースに関して、他の目的で複製することや掲載することは禁止されています。TI や第三者の知的財産権のライセンスが付与されている訳ではありません。お客様は、これらのリソースを自身で使用した結果発生するあらゆる申し立て、損害、費用、損失、責任について、TI およびその代理人を完全に補償するものとし、TI は一切の責任を拒否します。

TI の製品は、TI の販売条件 、 TI の総合的な品質ガイドライン 、 ti.com または TI 製品などに関連して提供される他の適用条件に従い提供されます。TI がこれらのリソースを提供することは、適用される TI の保証または他の保証の放棄の拡大や変更を意味するものではありません。 TI がカスタム、またはカスタマー仕様として明示的に指定していない限り、TI の製品は標準的なカタログに掲載される汎用機器です。

お客様がいかなる追加条項または代替条項を提案する場合も、TI はそれらに異議を唱え、拒否します。

Copyright © 2025, Texas Instruments Incorporated

最終更新日：2025 年 10 月